

Two-dimensional materials and applications

# 4. Properties of 2D Semiconductors

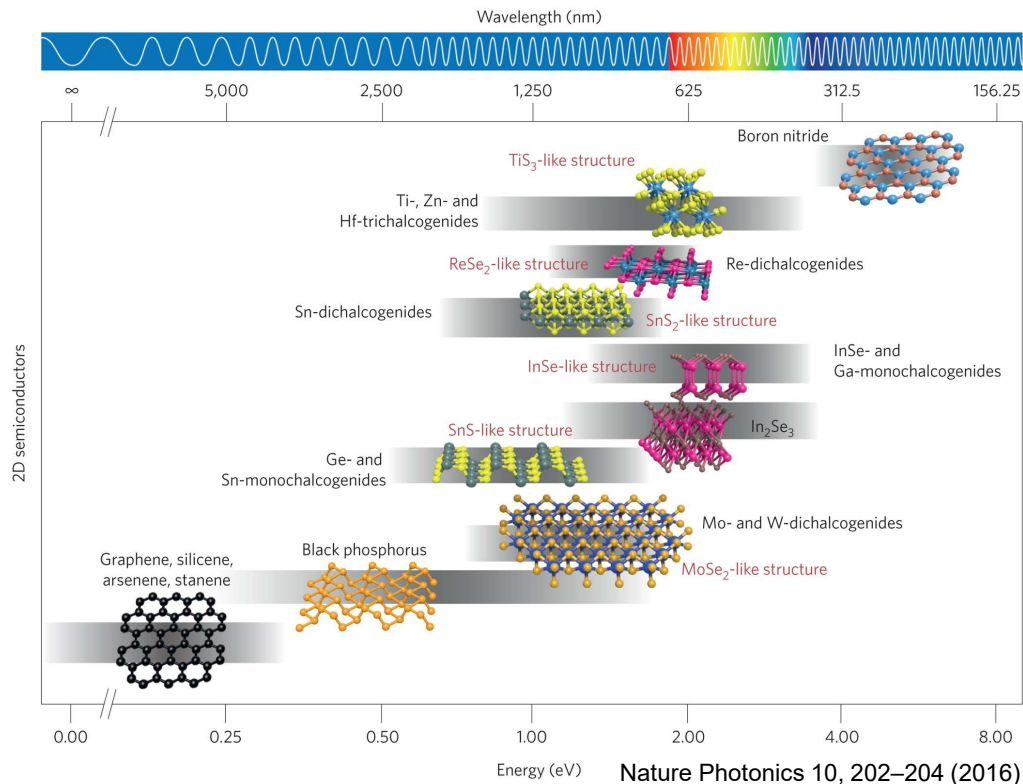
## Part 1



서울대학교  
SEOUL NATIONAL UNIVERSITY

# Family of 2D Semiconductors

Graphene family	Graphene	hBN 'white graphene'	BCN	Fluorographene	Graphene oxide
2D chalcogenides	MoS <sub>2</sub> , WS <sub>2</sub> , MoSe <sub>2</sub> , WSe <sub>2</sub>	Semiconducting dichalcogenides: MoTe <sub>2</sub> , WTe <sub>2</sub> , ZrS <sub>2</sub> , ZrSe <sub>2</sub> and so on		Metallic dichalcogenides: NbSe <sub>2</sub> , NbS <sub>2</sub> , TaS <sub>2</sub> , TiS <sub>2</sub> , NiSe <sub>2</sub> and so on	
				Layered semiconductors: GaSe, GaTe, InSe, Bi <sub>2</sub> Se <sub>3</sub> and so on	
2D oxides	Micas, BSCCO	MoO <sub>3</sub> , WO <sub>3</sub>	Perovskite-type: LaNb <sub>2</sub> O <sub>7</sub> , (Ca,Sr) <sub>2</sub> Nb <sub>3</sub> O <sub>10</sub> , Bi <sub>4</sub> Ti <sub>3</sub> O <sub>12</sub> , Ca <sub>2</sub> Ta <sub>2</sub> TiO <sub>10</sub> and so on		Hydroxides: Ni(OH) <sub>2</sub> , Eu(OH) <sub>2</sub> and so on
	Layered Cu oxides	TiO <sub>2</sub> , MnO <sub>2</sub> , V <sub>2</sub> O <sub>5</sub> , TaO <sub>3</sub> , RuO <sub>2</sub> and so on			Others

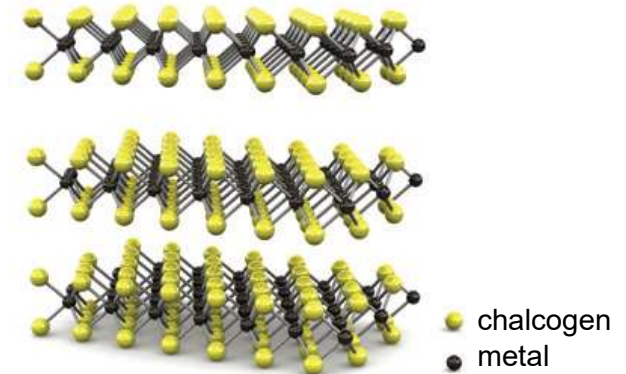
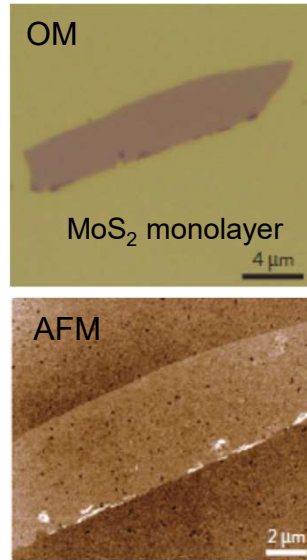


Nature Photonics 10, 202–204 (2016)

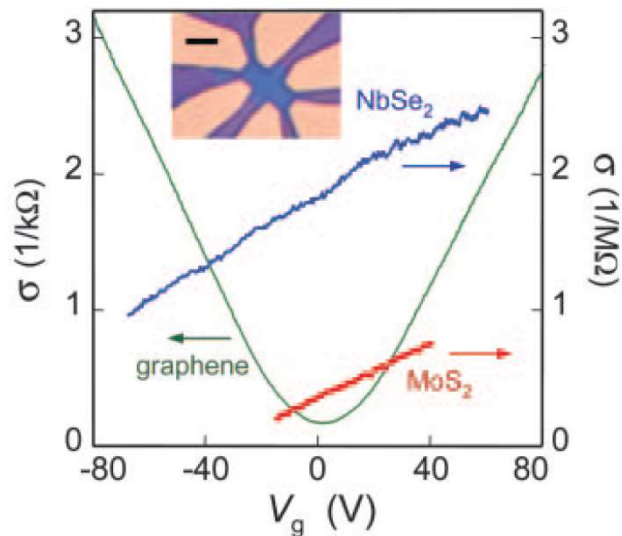
- Bandgap : 0.8 ~ 2.5eV
- Layered structure : monolayer, few-layer, bulk
- High mobility
- Transparency
- Flexibility
- Optical response
- Extra degree of freedom
- Broken symmetry

# History of 2D Semiconductors

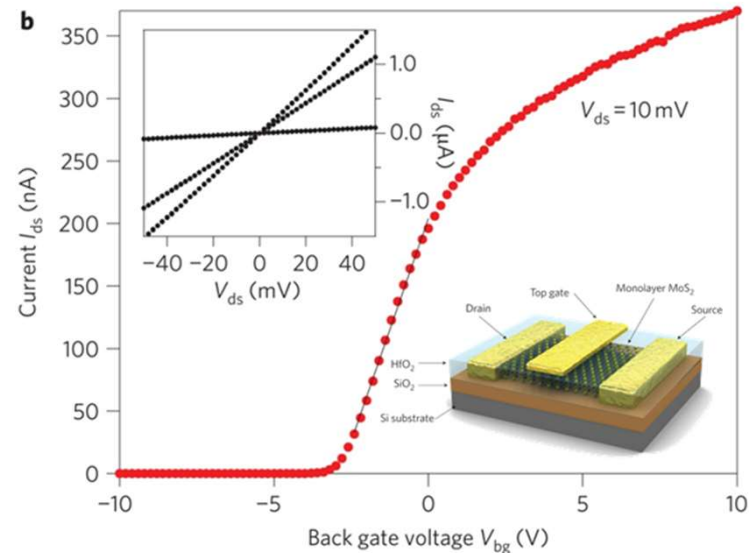
Molybdenum Disulfide ( $\text{MoS}_2$ )



Two-dimensional atomic crystals



*K. S. Novoselov et al. PNAS (2005)*



*A. Kis et al. Nature Nanotechnol. (2011)*

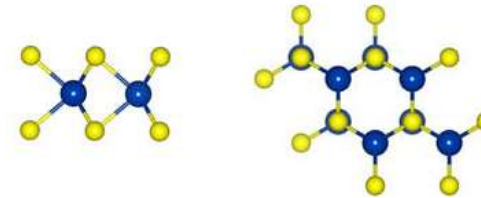
# Transition Metal Chalcogenides (TMDs)

1																	18							
H																	He							
Li																	Ne							
Na																	Ar							
K																	Kr							
Rb																	Xe							
Cs																	Rn							
Fr																								
	2											10	11	12					13	14	15	16	17	
		3	4	5	6	7	8	9	10	11	12													
		Sc	Ti	V	Cr	Mn	Fe	Co	Ni	Cu	Zn					Al	Si	P	S	Cl	Ar			
		Y	Zr	Nb	Mo	Tc	Ru	Rh	Pd	Ag	Cd					Ga	Ge	As	Se	Br	Kr			
		Lu	Hf	Ta	W	Re	Os	Ir	Pt	Au	Hg					In	Sn	Sb	Te	I	Xe			
		Lr	Rf	Db	Sg	Bh	Hs	Mt	Ds	Rg	Cn					Tl	Pb	Bi	Po	At	Rn			
																Uut	Fl	Uup	Lv	Uus	Uuo			
		La	Ce	Pr	Nd	Pm	Sm	Eu	Gd	Tb	Dy	Ho	Er	Tm	Yb									
		Ac	Th	Pa	U	Np	Pu	Am	Cm	Bk	Cf	Es	Fm	Md	No									

Layered structure of the form X-M-X.

Chalcogen atoms: hexagonal plane

Metal atoms: a plane between two chalcogen planes



1. Good lubricant property
2. Catalyst for optoelectronics and photovoltaics

A. Kuc et al. Book: Chemical Modeling (2014)

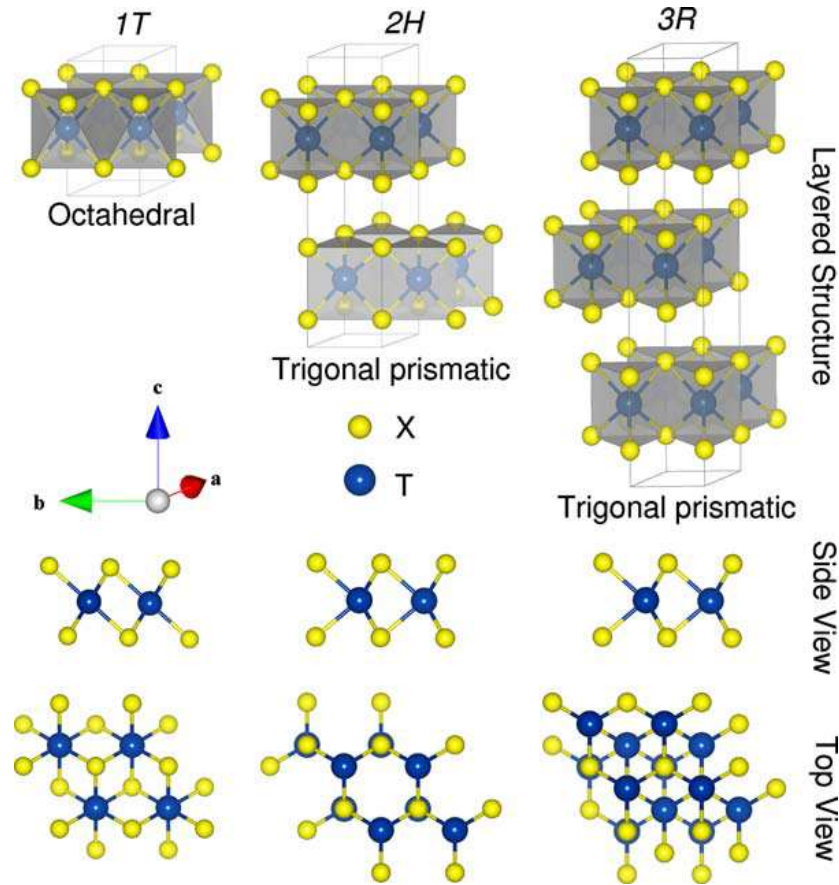
Table 1 | Summary of TMDC materials and properties.

		-S <sub>2</sub>		-Se <sub>2</sub>		-Te <sub>2</sub>	
	Electronic characteristics	References	Electronic characteristics	References	Electronic characteristics	References	
Nb	Metal; superconducting; CDW	138 (E)	Metal; superconducting; CDW	138,164 (E)	Metal	83 (T)	
Ta	Metal; superconducting; CDW	138,164 (E)	Metal; superconducting; CDW	138,164 (E)	Metal	83 (T)	
Mo	Semiconducting 1L: 1.8 eV Bulk: 1.2 eV	31 (E) 88 (E)	Semiconducting 1L: 1.5 eV Bulk: 1.1 eV	82 (T) 88 (E)	Semiconducting 1L: 1.1 eV Bulk: 1.0 eV	82 (T) 165 (E)	
W	Semiconducting 1L: 2.1 eV 1L: 1.9 eV Bulk: 1.4 eV	25 (T) 82 (T) 88 (E)	Semiconducting 1L: 1.7 eV Bulk: 1.2 eV	83 (T) 88 (E)	Semiconducting 1L: 1.1 eV	83 (T)	

The electronic characteristic of each material is listed as metallic, superconducting, semiconducting or charge density wave (CDW). For the semiconducting materials, the bandgap energies for monolayer (1L) and bulk forms are listed. The cited references are indicated as experimental (E) or theoretical (T) results.

H. Q. Wang et al. Nature Nano (2012)

# Crystal Structure of Transition Metal Chalcogenides



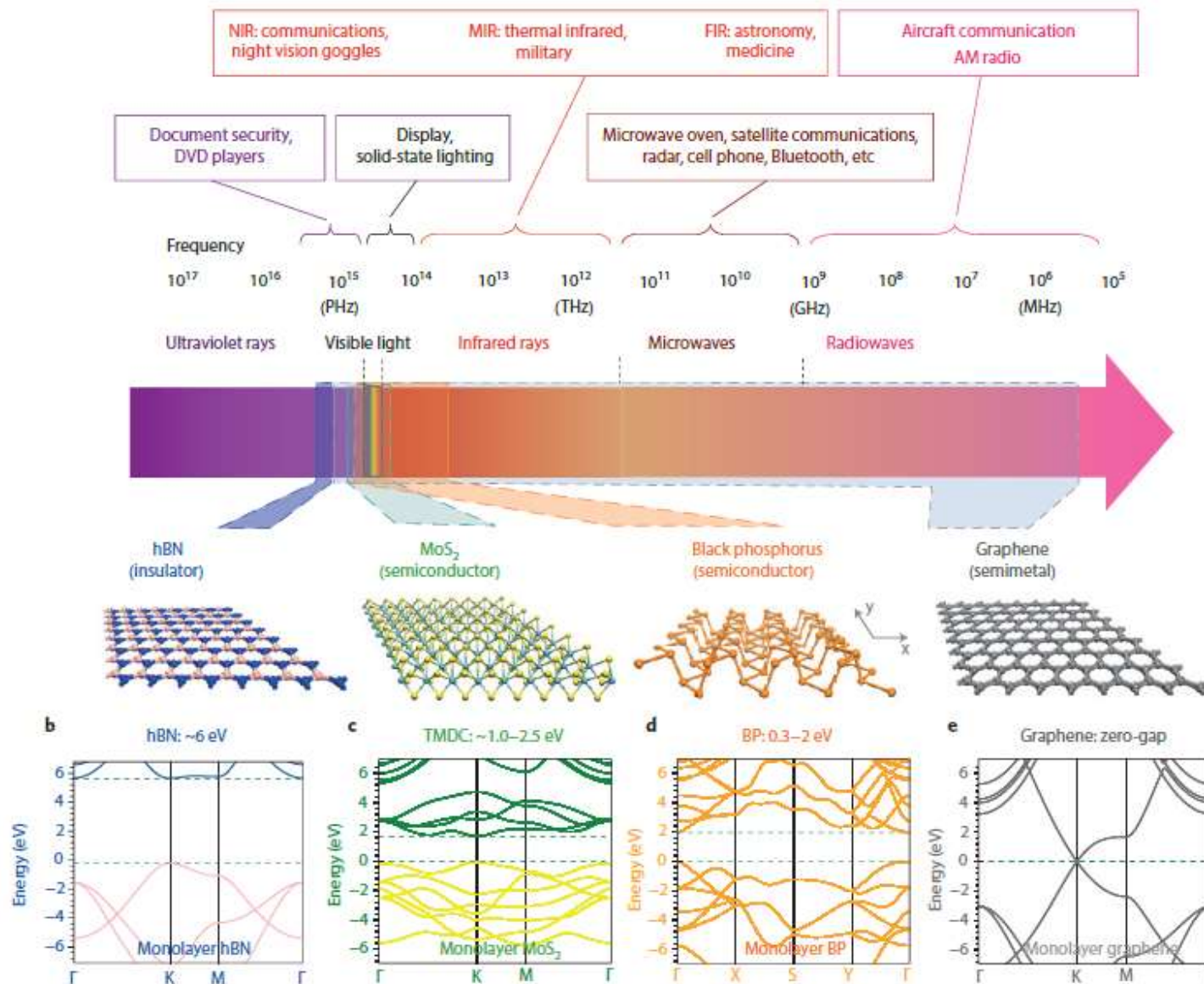
A. Kuc et al. Book: Chemical Modeling (2014)

## Monolayer TMDs

- 1) Broken inversion symmetry  
2H :  $P6_3/mmcD_{6h}^4$  (Bulk)  $\rightarrow$  1H :  $P\bar{6}m2D_{3h}^1$  (ML)
- 2) Quantum confinement
- 3) Direct bandgap for ML @ K and K'
- 4) Valley degree of freedom
- 5) Strong spin-orbit coupling
- 6) Large exciton binding energy (0.5-1eV)
- 7) Trion
- 8) Self-passivation
- 9) Strong interaction with light

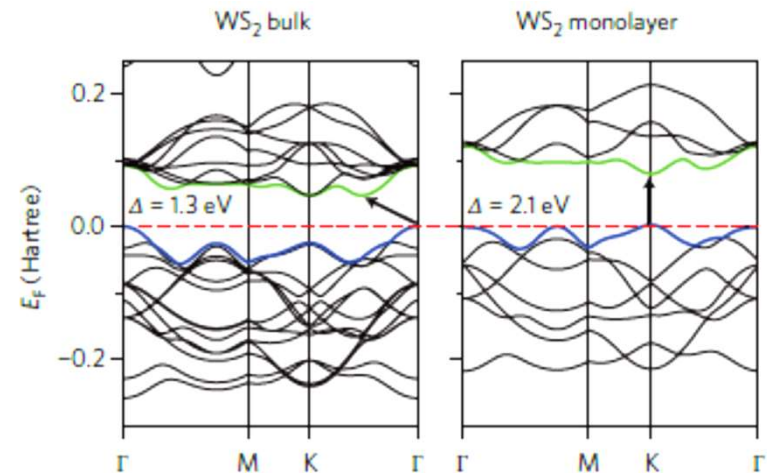
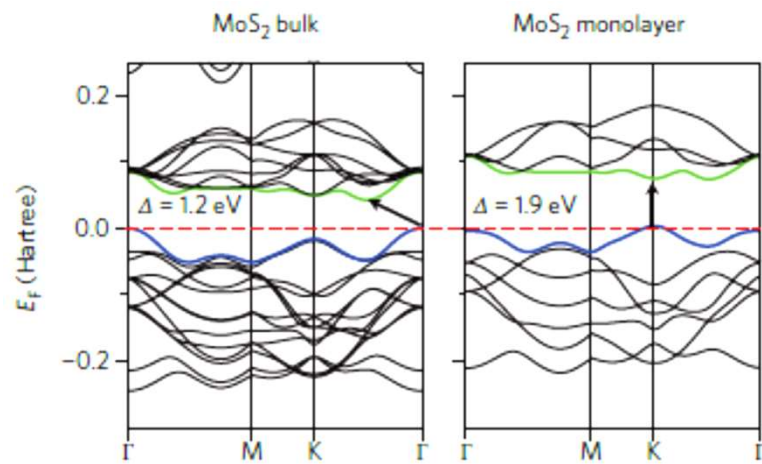
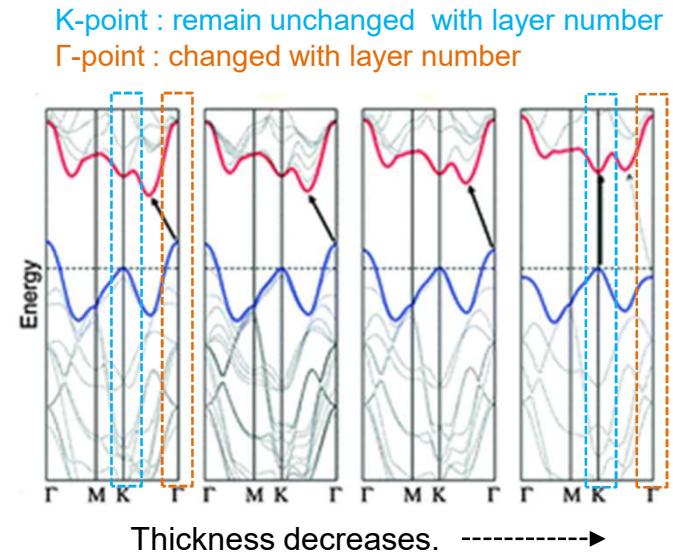
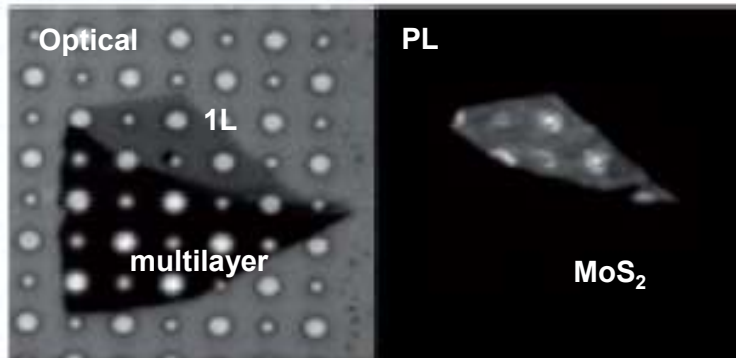
F. Xia et al. Nature Photonics (2014)

# 2D Material Spectra



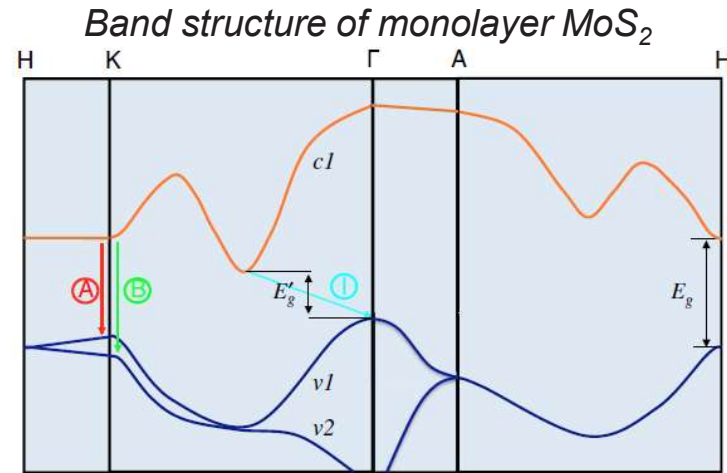
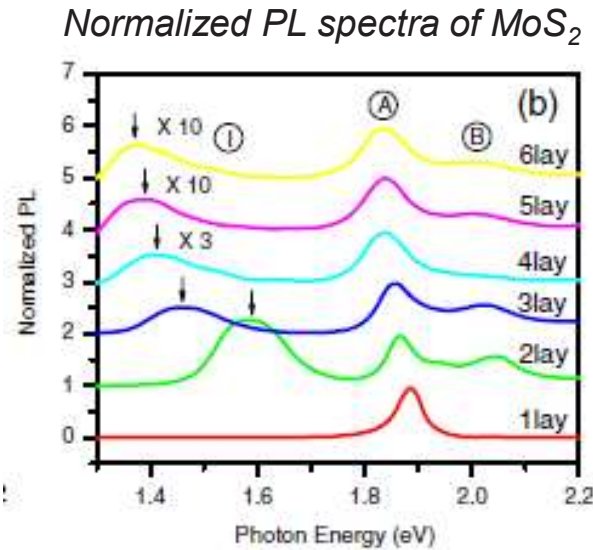
# Electronic Structure of TMDs

Band gap changes with layer number due to quantum confinement & hybridization of d-orbital of metal atom and  $p_z$  orbital of chalcogen atom.

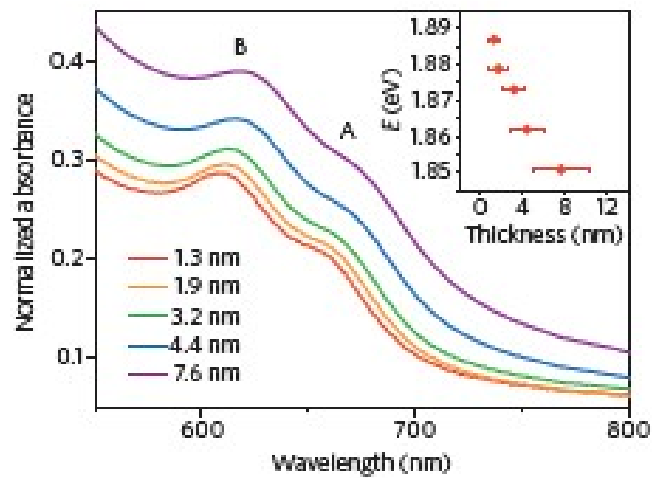


As thickness decreases, bandgap increases and band structure transforms from indirect to direct.

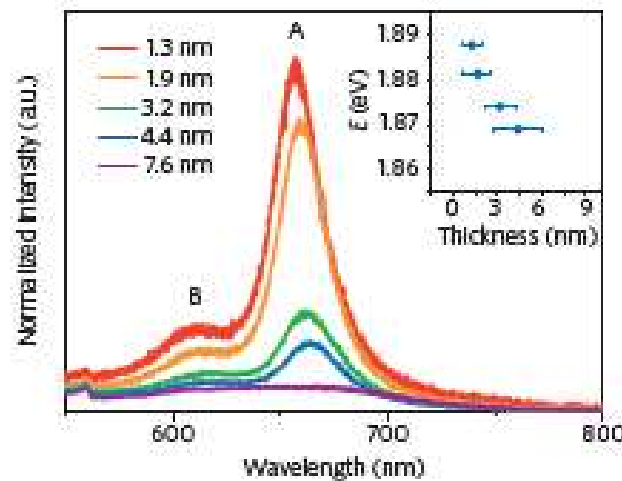
# Electronic Structure of TMDs



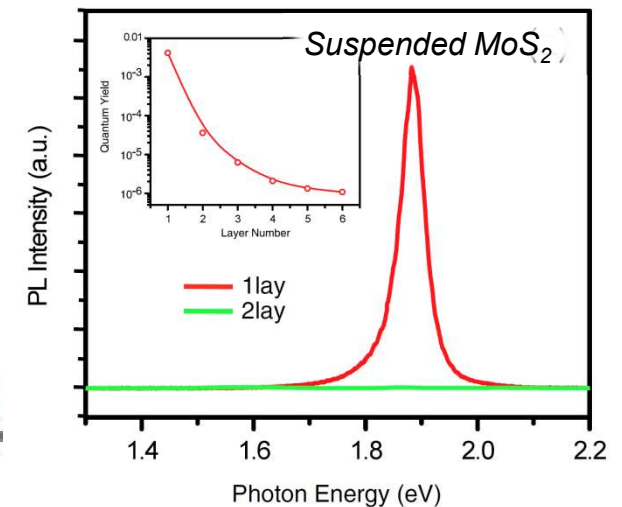
Absorption spectra



PL spectra



Effect of substrate on PL

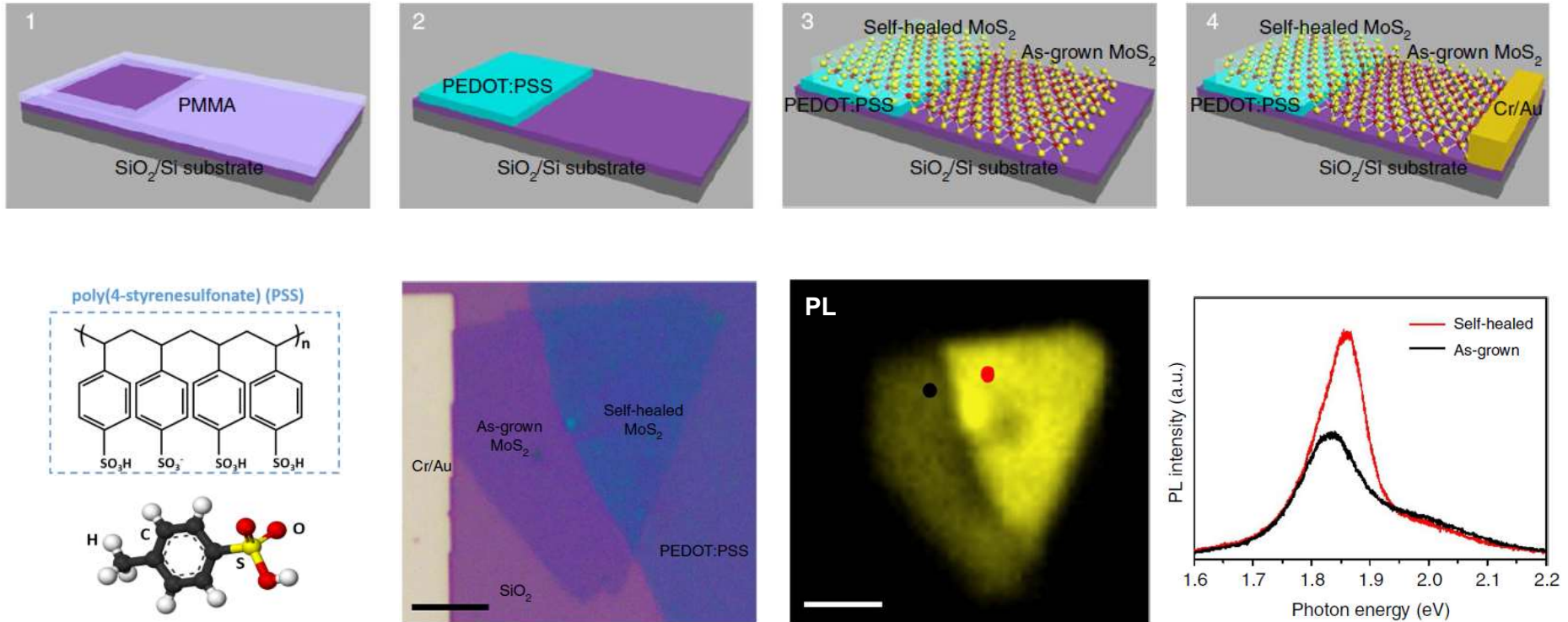


Optical properties of MoS<sub>2</sub> depends on the thickness and substrate.



# Quantum yield enhancement

S-vacancies healing by PSS

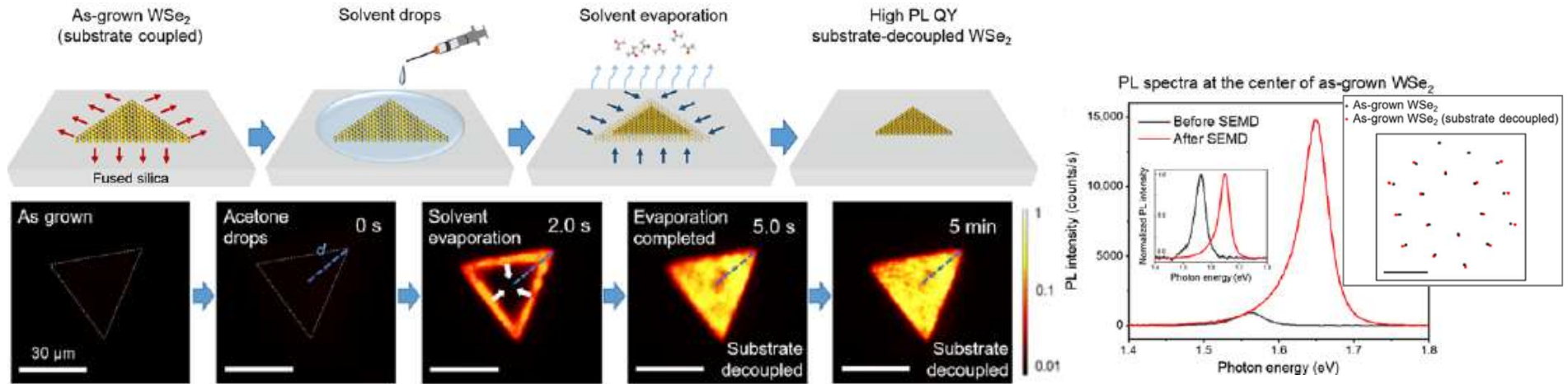


S-vacancies are self-healed by poly(4-styrenesulfonate) (PSS).

By this, not only the PL spectrum intensity of the self-healed one is drastically enhanced, but also the peak energy is obviously blue shifted.

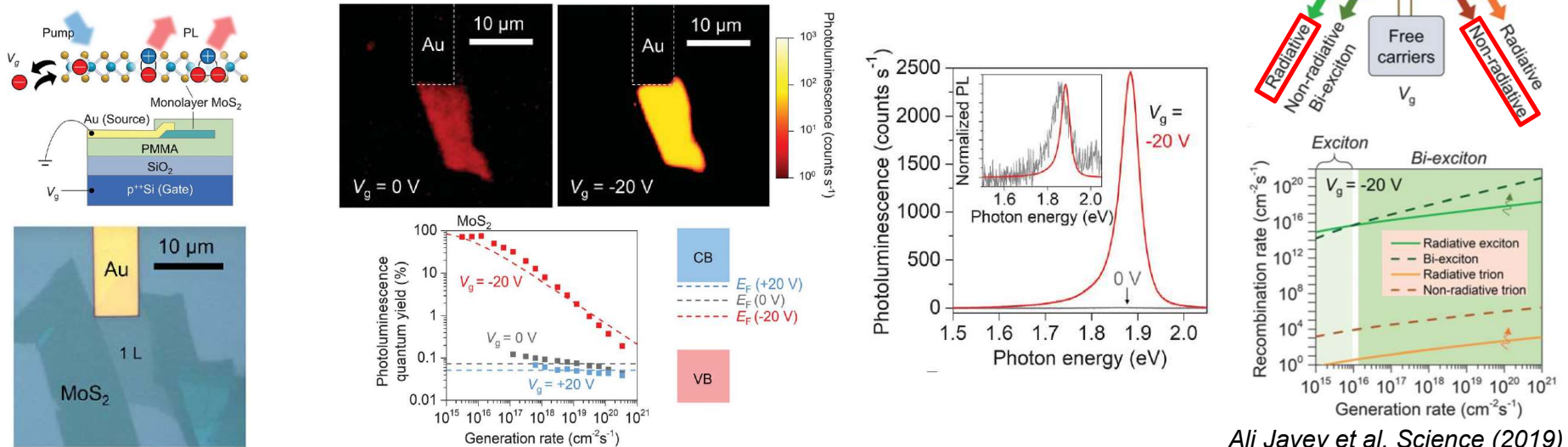
# Quantum yield enhancement

By solvent evaporation-mediated decoupling (SEMD) process



Kim et al., *Sci. Adv.* 5, eaau4728 (2019)

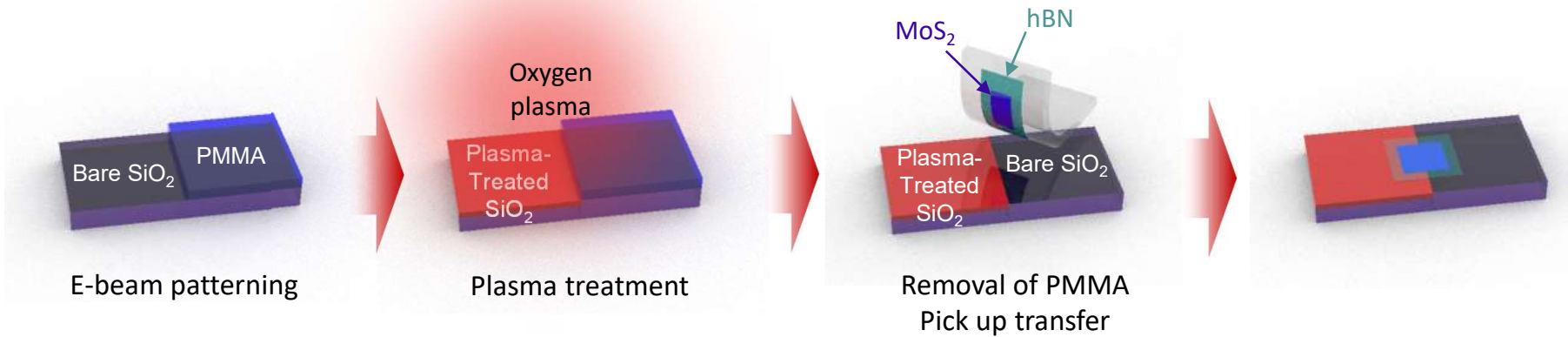
By electrostatic doping



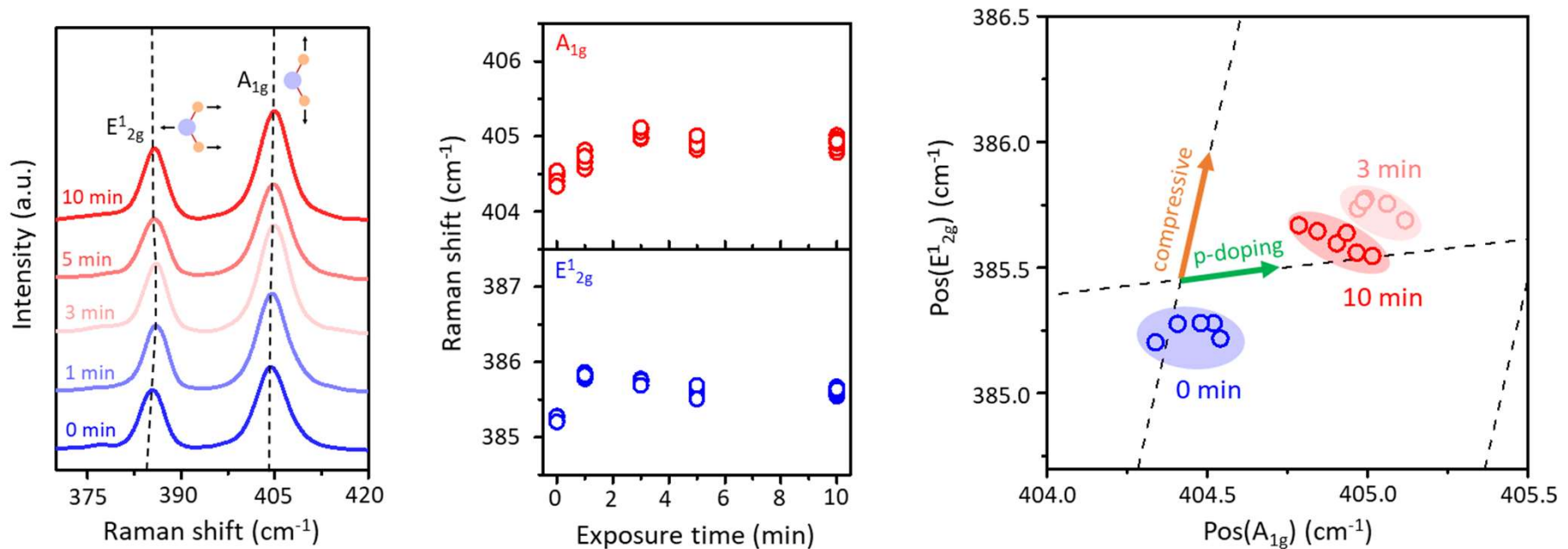
Ali Javey et al. *Science* (2019)

# Effect of Substrate on PL

## Doping by functionalized substrate

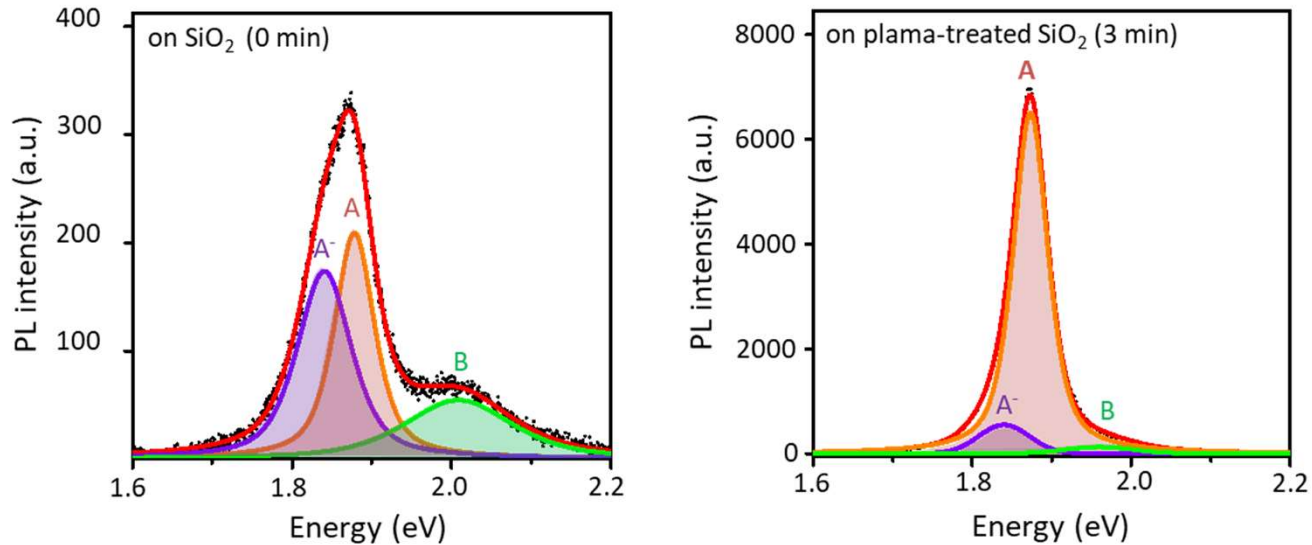


✓ It is well known that the plasma-treated SiO<sub>2</sub> substrate becomes hydrophilic owing to the formation of hydroxyl (-OH) functional groups on the surface.

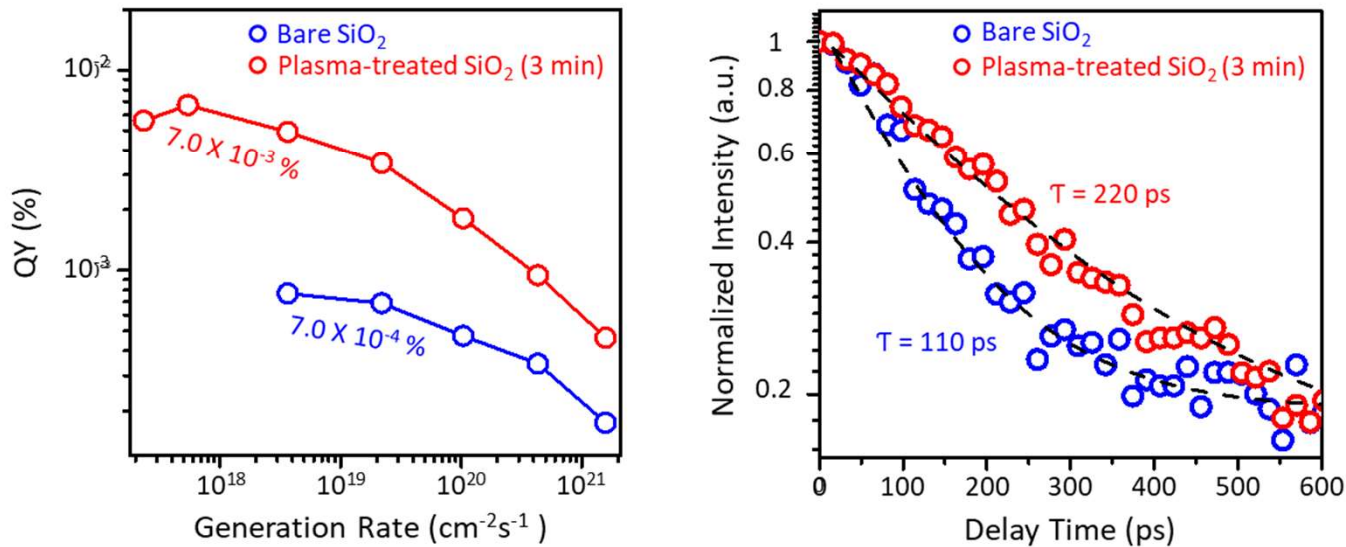


# Effect of Substrate on PL

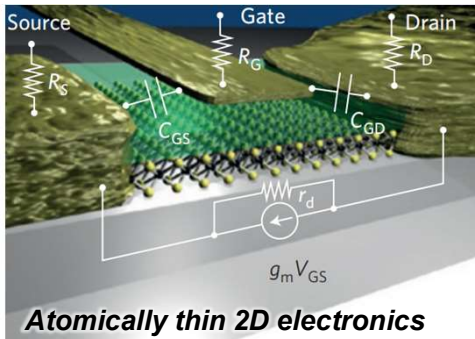
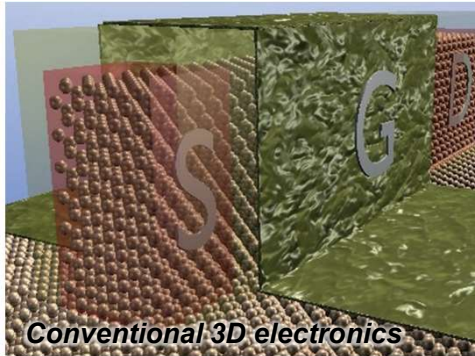
## Exciton-dominant PL of MoS<sub>2</sub> on plasma-treated substrate



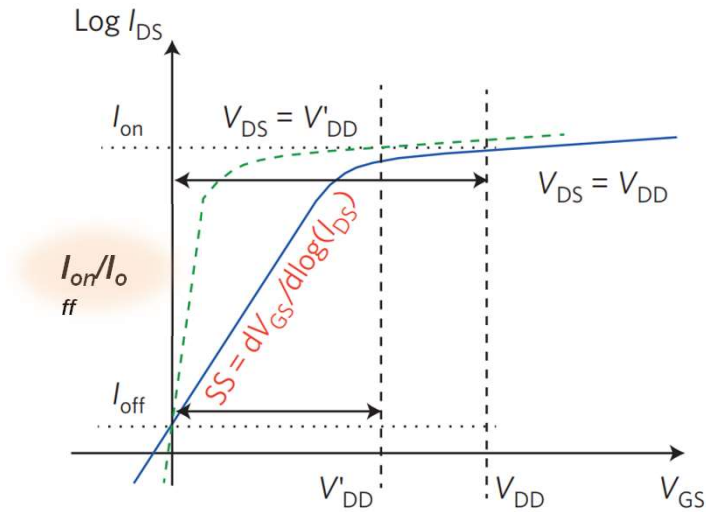
## Suppression of non-radiative recombination by trion



# Electronics Based on Two-dimensional Materials



G. Fiori et al. Nat. Nanotechnol. (2014)



- Two terminal device: open-circuited or short-circuited at  $V_{GS} > V_T$  (threshold voltage)
- Minimizing  $I_{off}$  = low standby power consumption
- Maximizing  $I_{on}$  = high switching speed
- $I_{on}/I_{off}$  ratio needs to be larger than  $10^4$ .
- Intrinsic limit for subthreshold swing (SS) at room T = 60 mV/dec (large  $I_{on}/I_{off}$  ratio at small supply voltage)
- For high-performance applications, large switching speed at the cost of high power dissipation
- For low-power applications, low power consumption (a key requirement in portable electronics)

## Challenges for conventional electronics

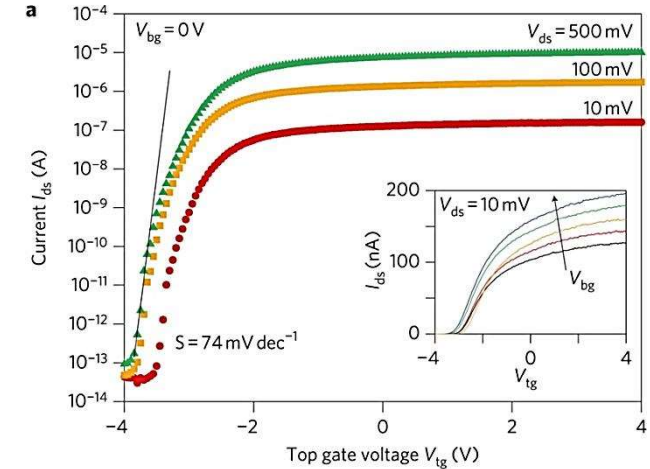
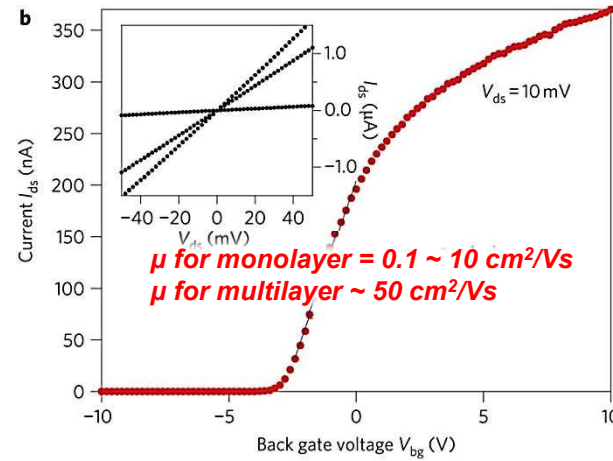
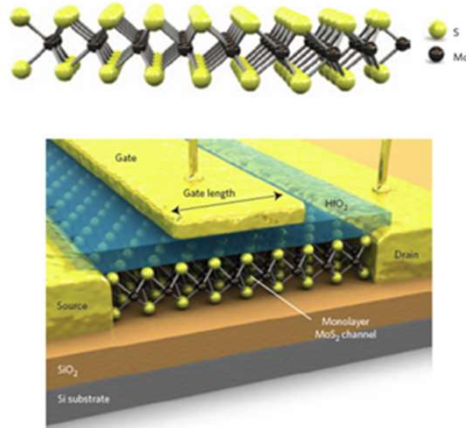
- Extreme scaling down with electrostatic control of the channel
- Thin gate oxides which leads to increased leakage

## Main opportunities for 2D electronics

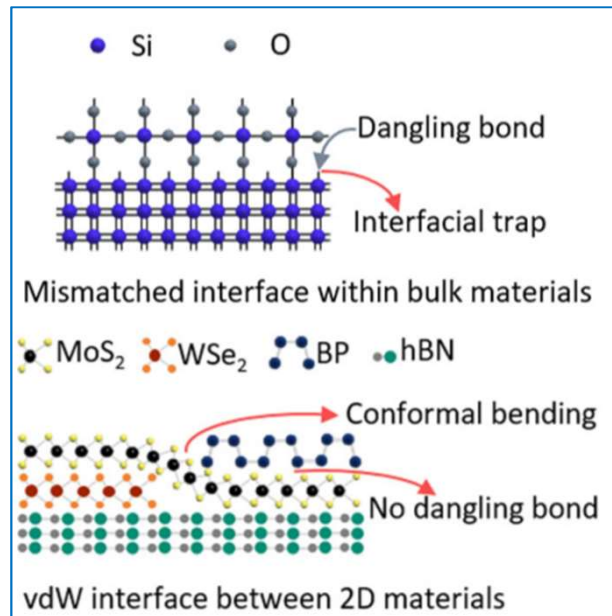
- Ultimately thin channel transistor
- Perfect gate control over the channel barrier
- Reduced short-channel effect

# Electronic Transport of TMDs

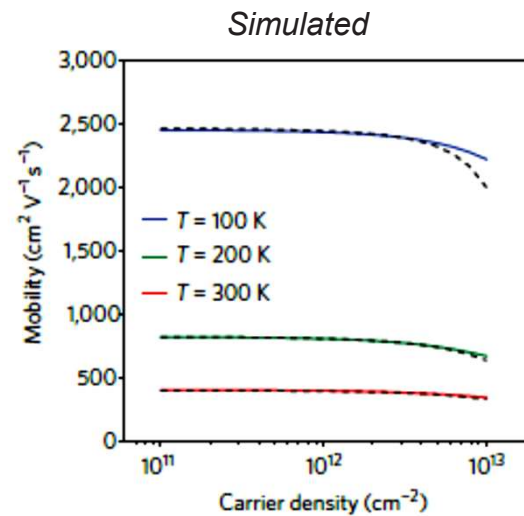
## Molybdenum Disulfide (MoS<sub>2</sub>)



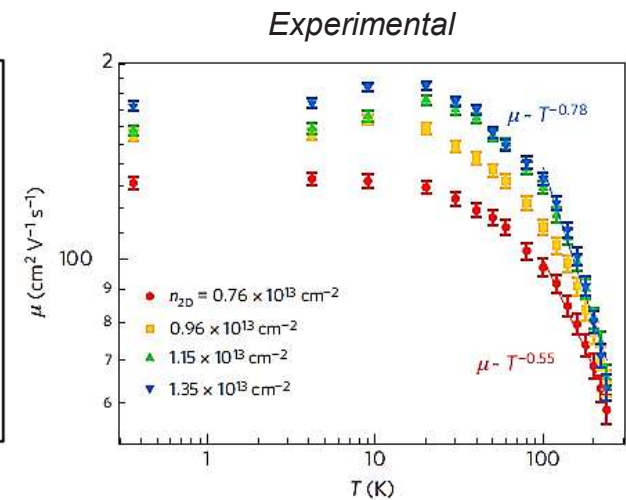
B. Radisavljevic et al. Nature Nano (2011)



npj 2D Mater. Appl. 51 (2022)

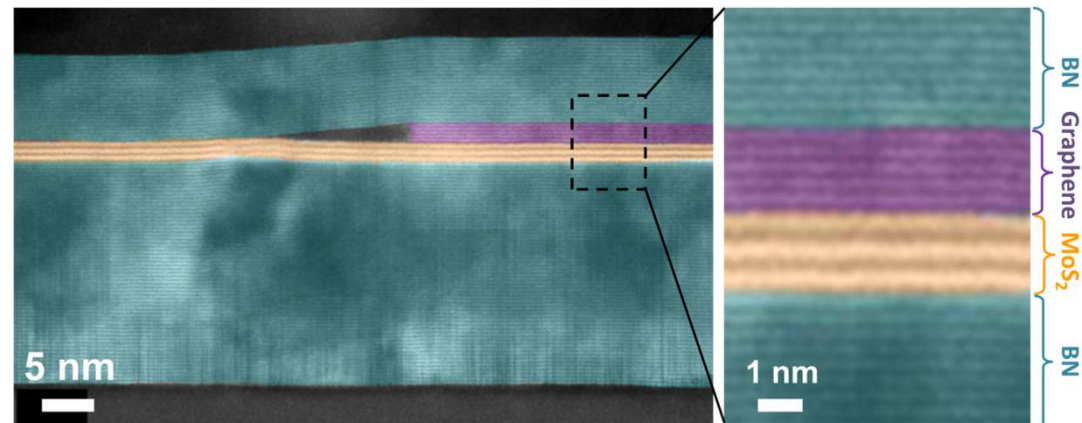
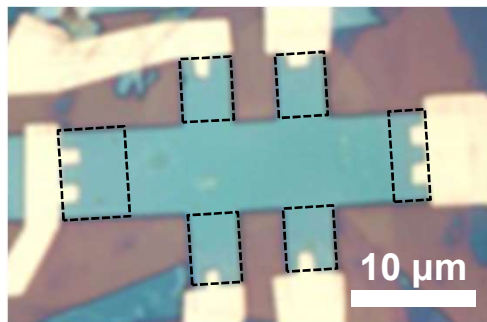
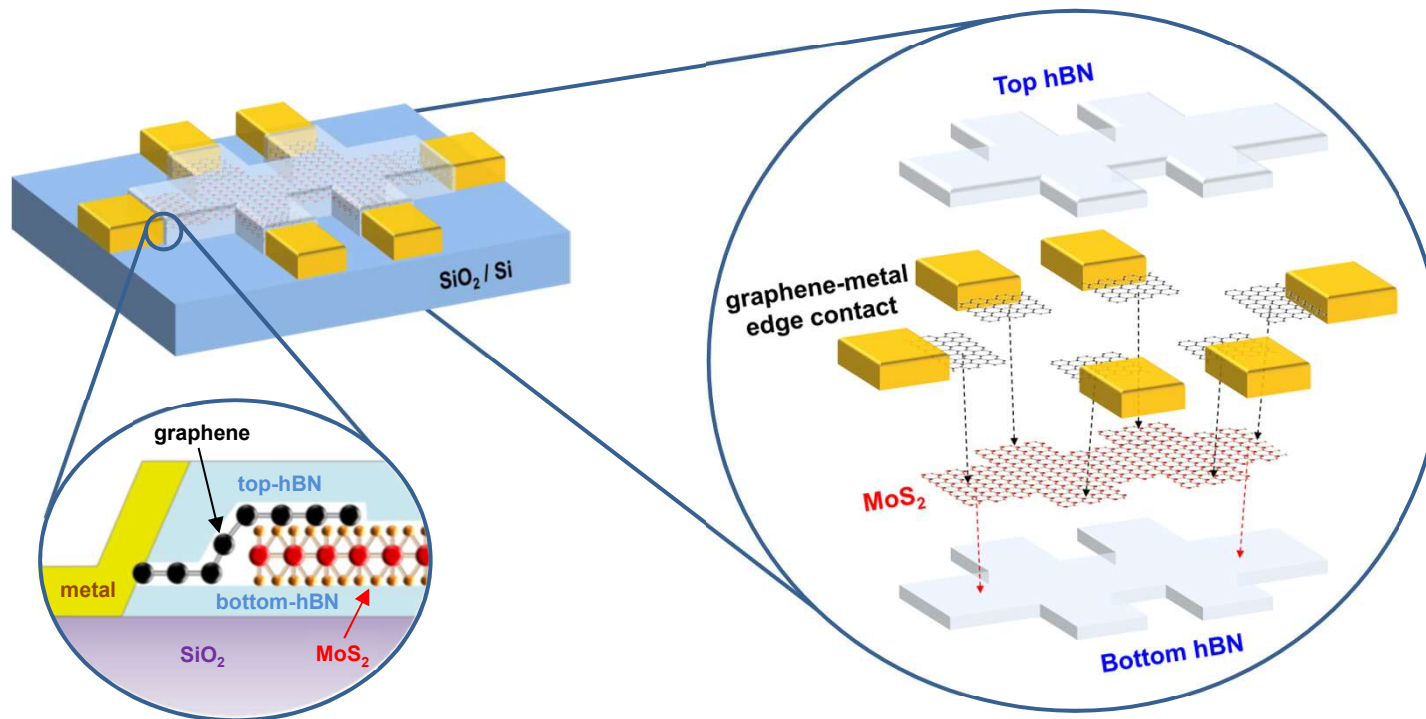


Q. H. Wang et al. Nature Nano (2012)

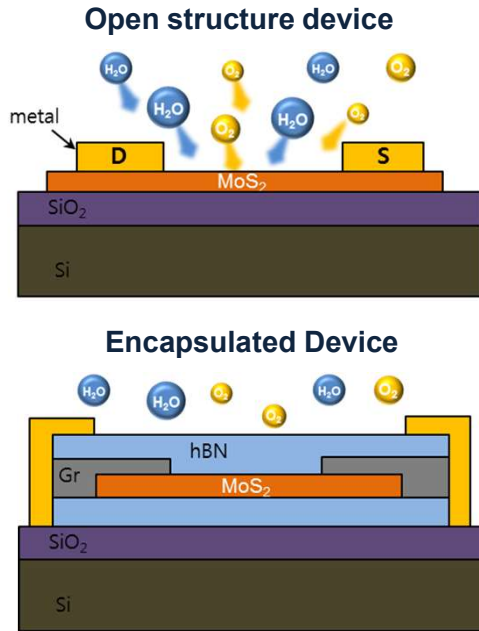


B. Radisavljevic et al. Nature Mater. (2014)

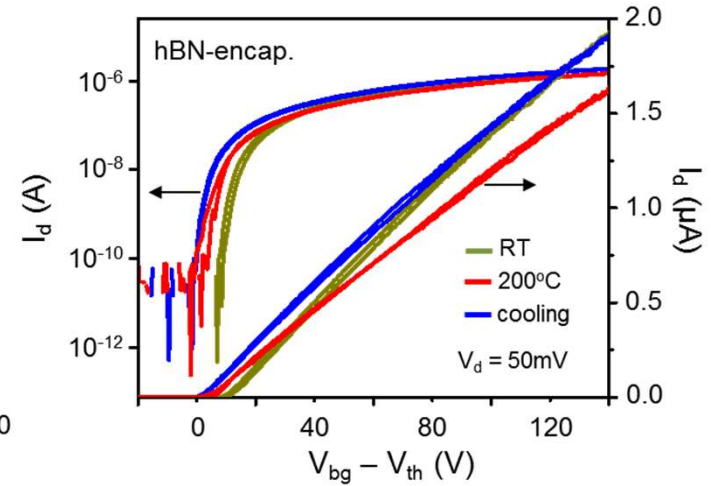
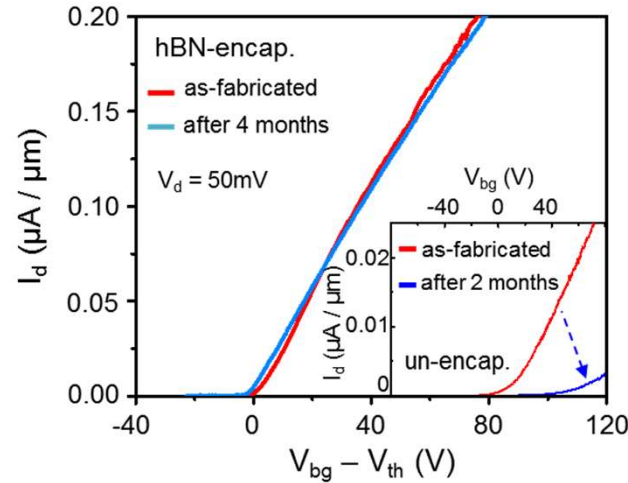
# Electronic Transport of TMDs



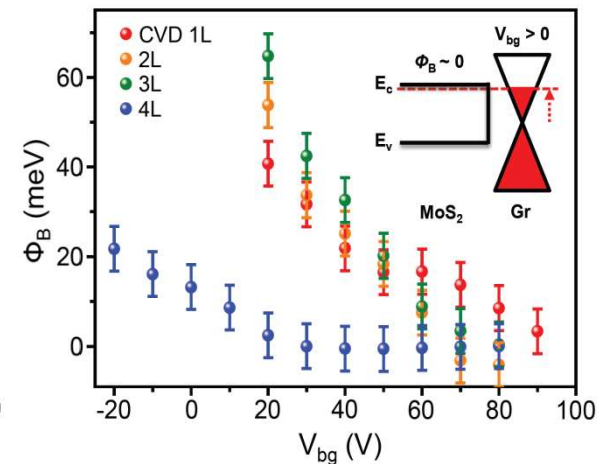
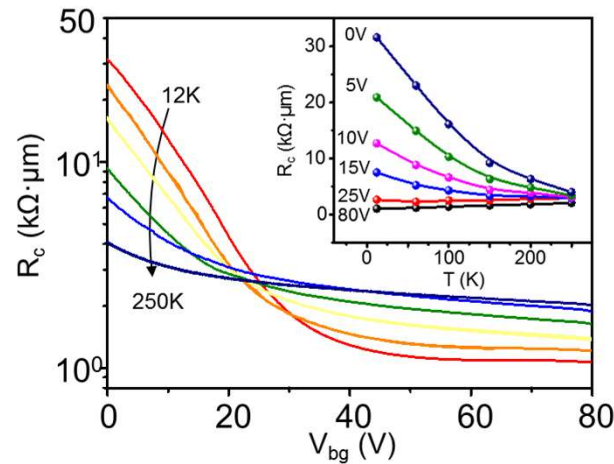
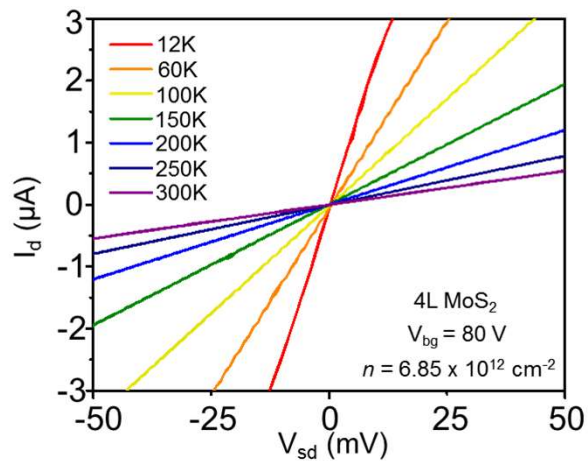
# Electronic Transport of TMDs



## Perfect protection from environment



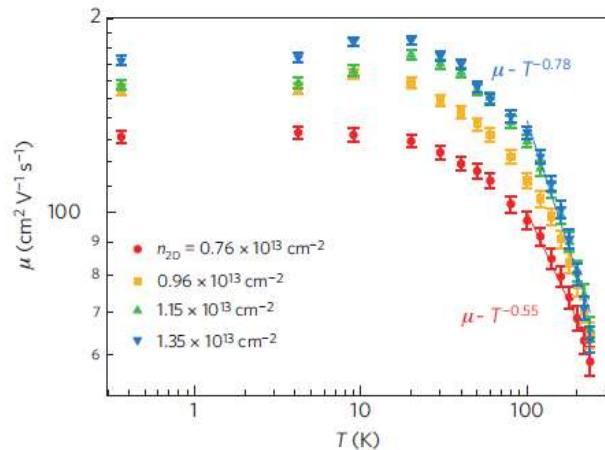
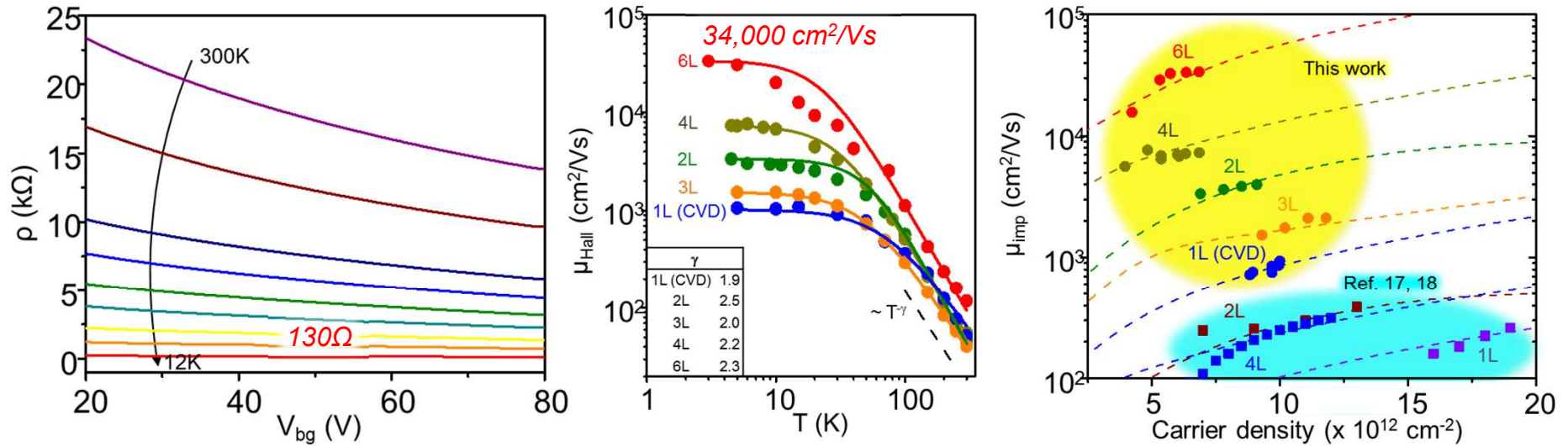
## Gate-tunable graphene electrodes





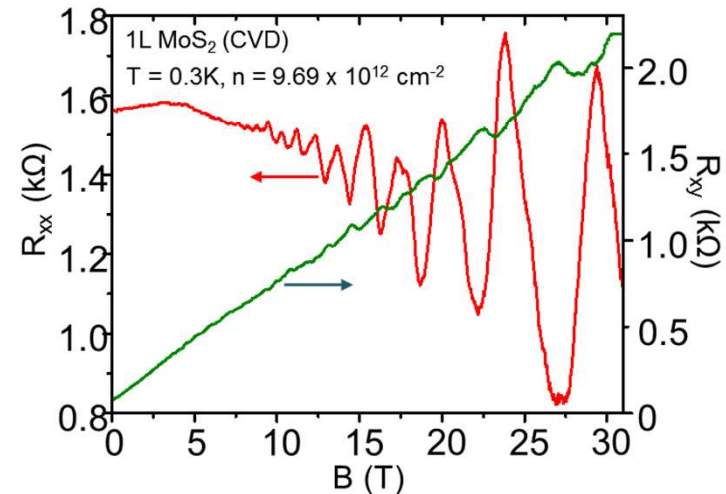
# Electronic Transport of TMDs

## Ultrahigh mobility in MoS<sub>2</sub>



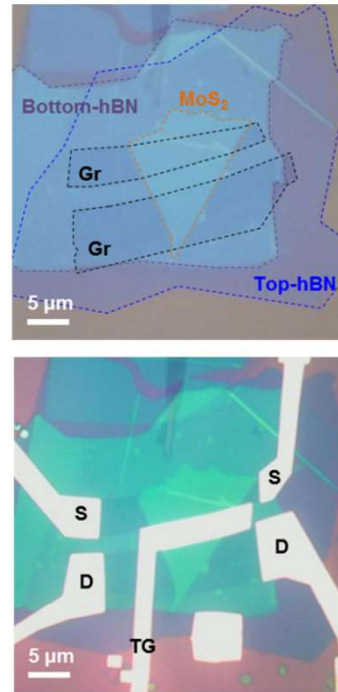
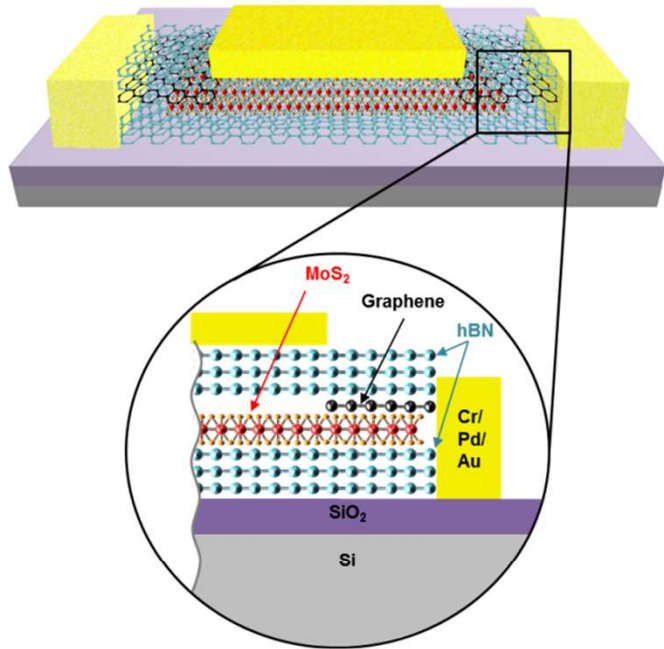
B. Radisavjevic et al. Nature Mater. (2014)

## SdH Oscillations & QHE in MoS<sub>2</sub>

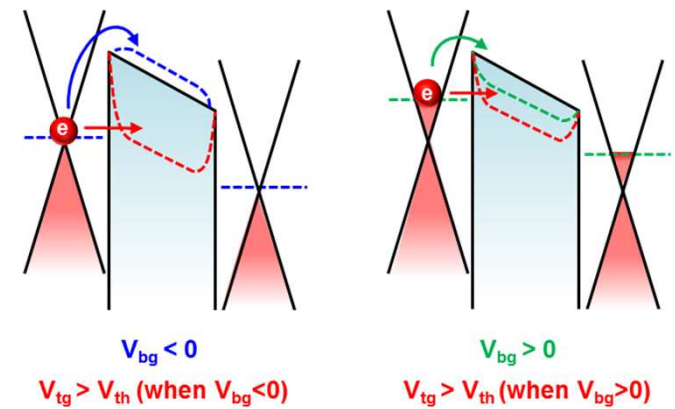
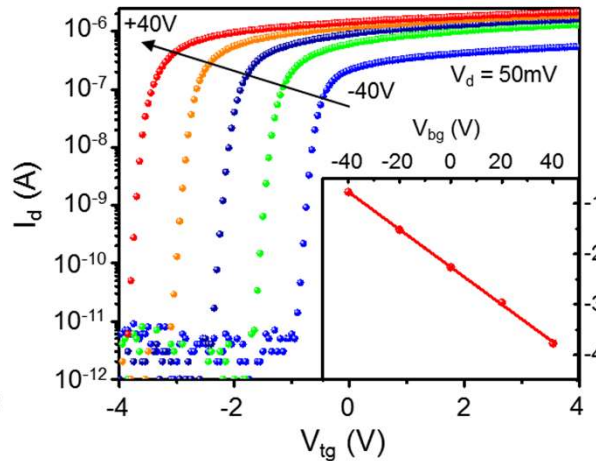
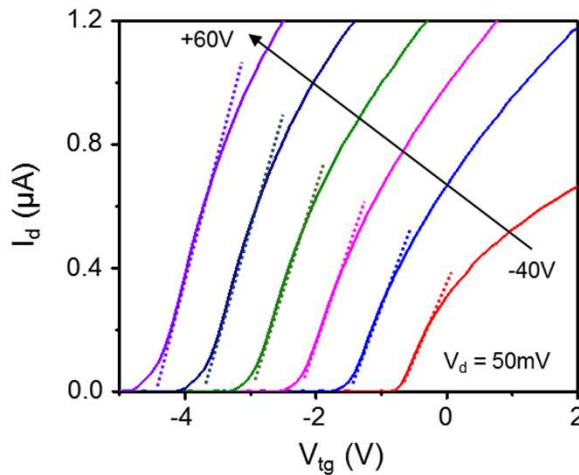


X. Cui et al. Nature Nanotechnol. (2015)

# Electronic Transport of TMDs



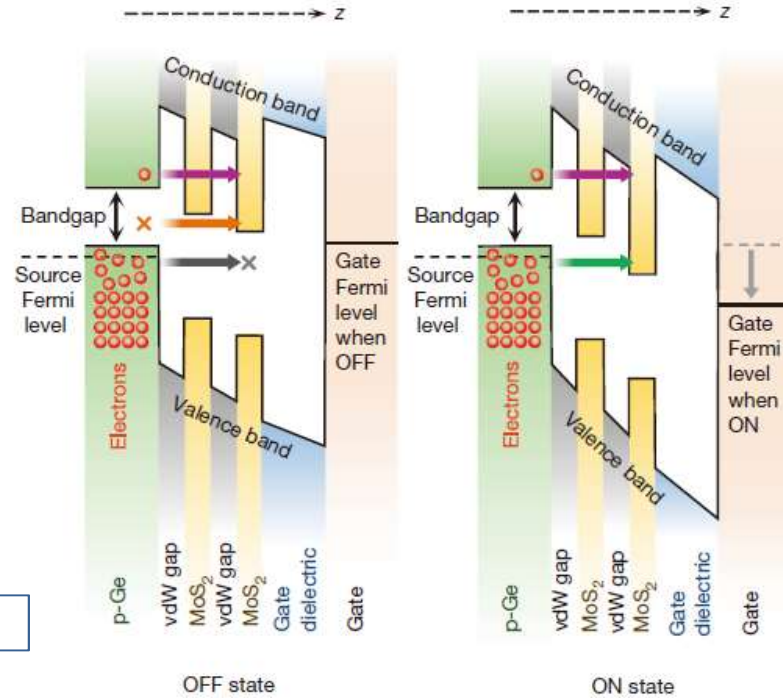
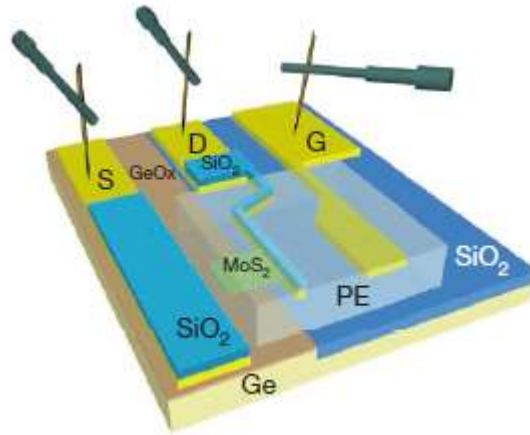
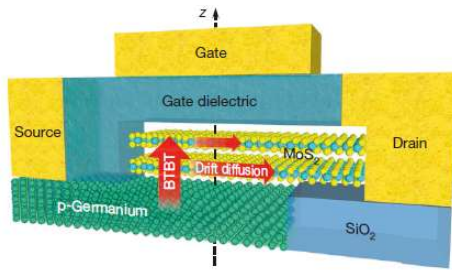
MoS <sub>2</sub> Thickness	2T Mobility (cm <sup>2</sup> /Vs)	Fabrication Method
1L	94 (bottom-gate)	Pick-up
CVD 1L	19 (bottom-gate)	PDMS
2L	120	Pick-up
3L	69 (bottom-gate) 46 (top-gate)	Pick-up
3L	33 (bottom-gate) 37 (top-gate)	Pick-up
5L	52 (top-gate)	Pick-up
6L	96 (bottom-gate)	PDMS
45nm	151 (bottom-gate)	PDMS



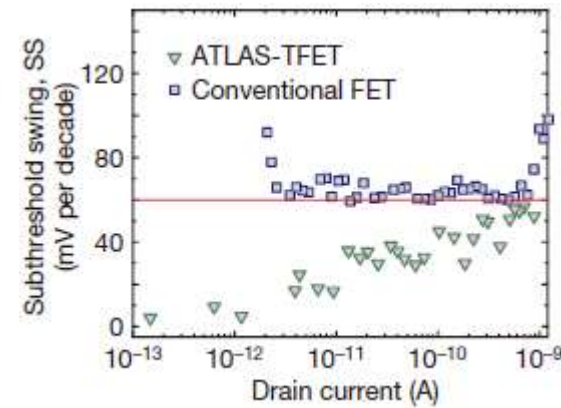
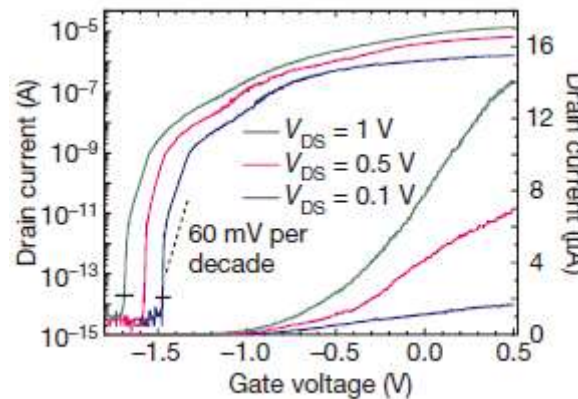
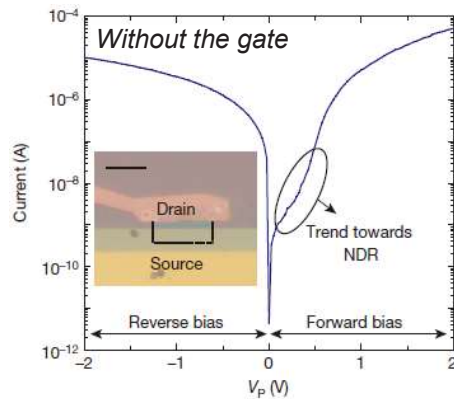
- Tunable contact barrier (contact resistance)
- Tunable threshold voltage

# Electronic Transport of TMDs

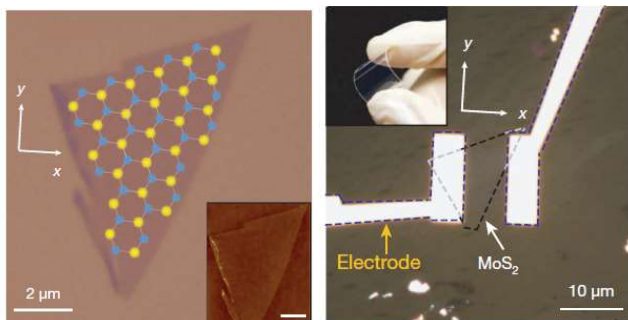
Subthermionic tunnel field-effect transistor



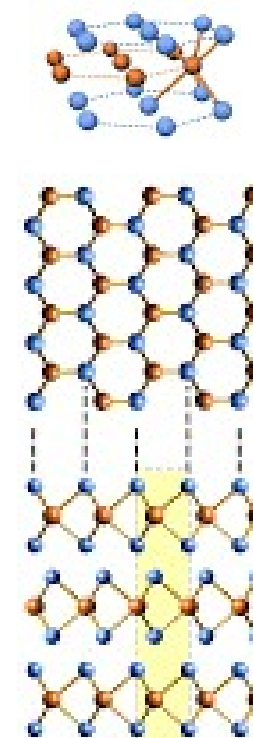
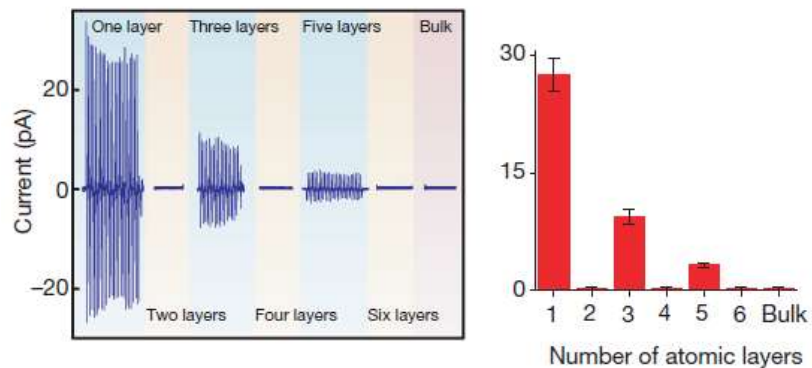
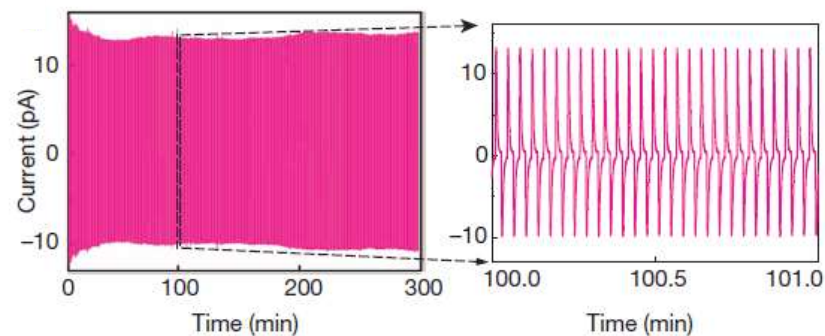
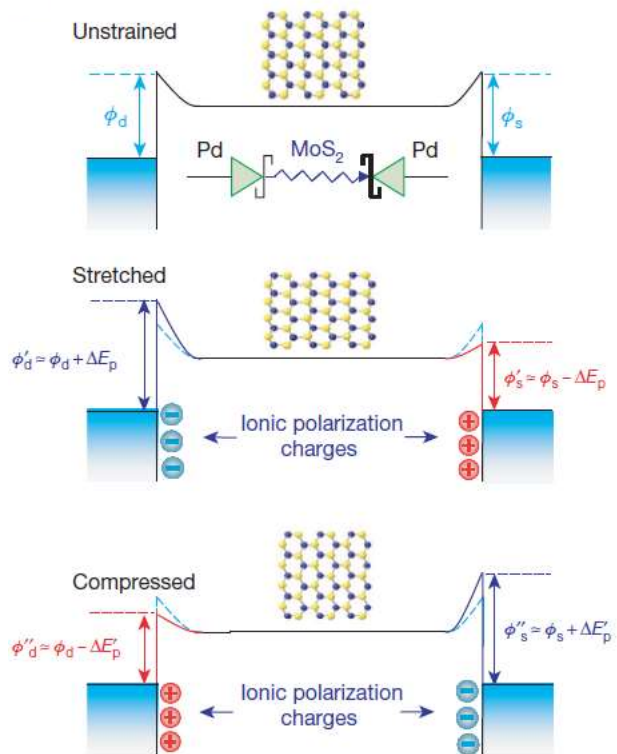
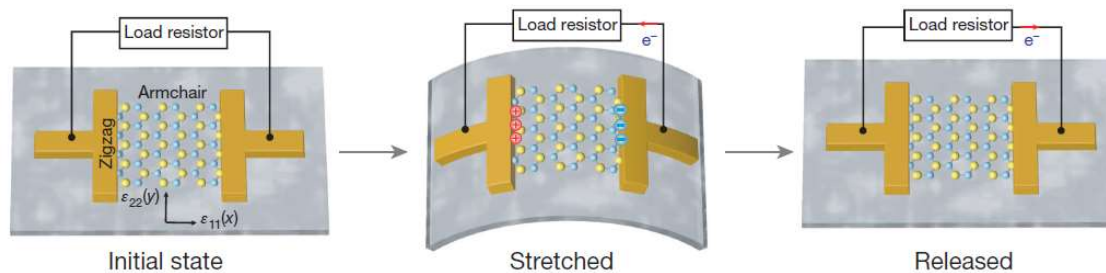
Tunnel current  $\propto$  (Density of carriers  $\times$  Empty states  $\times$  tunnel probability)



# Piezoelectricity of MoS<sub>2</sub>



Directionality of piezoelectricity



Dependence of layer number on piezoelectricity due to inversion symmetry breaking.

# Spins, Valleys and Excitons in TMDs

## Spin-orbit coupling

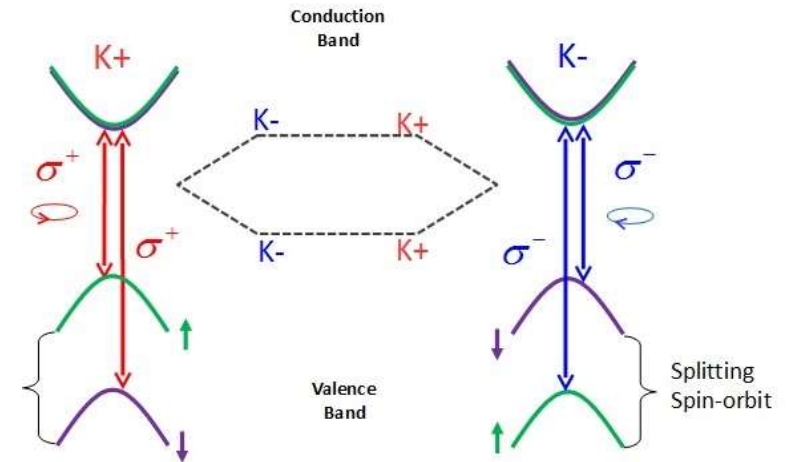
: TMDs have a strong spin-orbit coupling, which introduces a strong energy splitting between spin up and down states. The spin splitting in conduction band and valence band is in the meV range and several hundred meV, respectively.

## Valley degree of freedom

: Confined carriers at different moment and same energy of local maximum/minimum on the valence/conduction band

## Valley dependent optical selection rules

: A right circular polarized photon ( $\sigma^+$ ) initialize a carrier in the  $K^+$  valley and a left circular polarized photon ( $\sigma^-$ ) initialize a carrier in the  $K^-$  valley.



## Valleytronics

: The internal degree of freedom of valley is used to store, manipulate and read out bits of information using the multiple extrema of the band structure, so that the information of 0s and 1s would be stored as different discrete values of the crystal momentum.

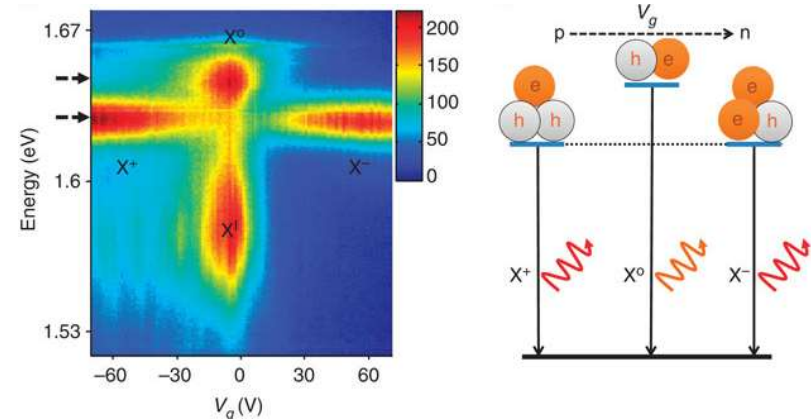
## Large binding energy of exciton

: In atomically thin 2D systems, there exist a strong confinement of electrons and holes in the layer plane, which dramatically enhances the Coulomb interaction between the electron and hole in TMD monolayers, leading to a large binding energy in the hundreds of meV range.

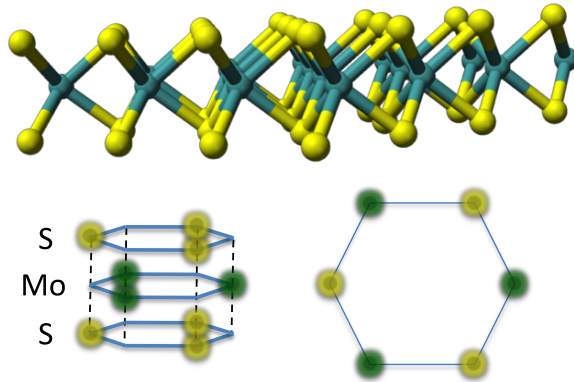
## Trion

: Negatively charged trion consists of two electrons and one hole and a positively charged trion consists of two holes and one electron.

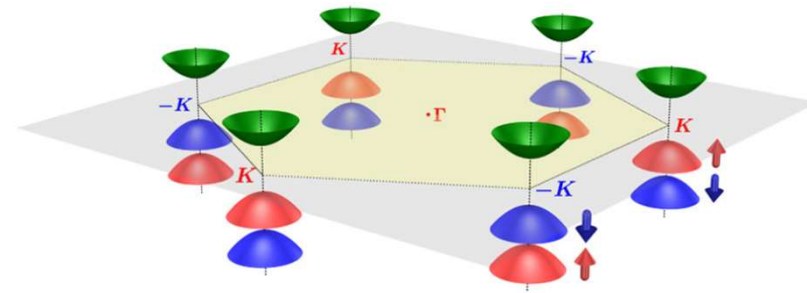
Electrically tunable trion density



# Valleys in TMDs

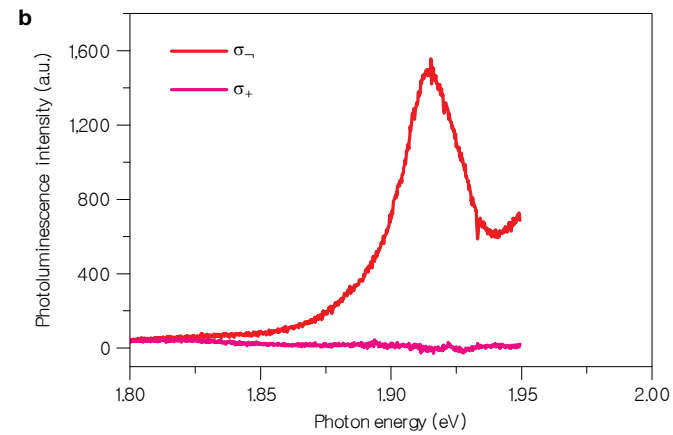
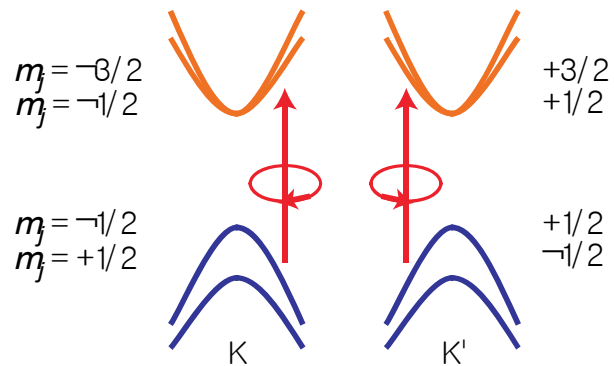


*K. F. Mak et al. Nature Nanotechnology (2013)*



*D. Xie et al. PRL (2012)*

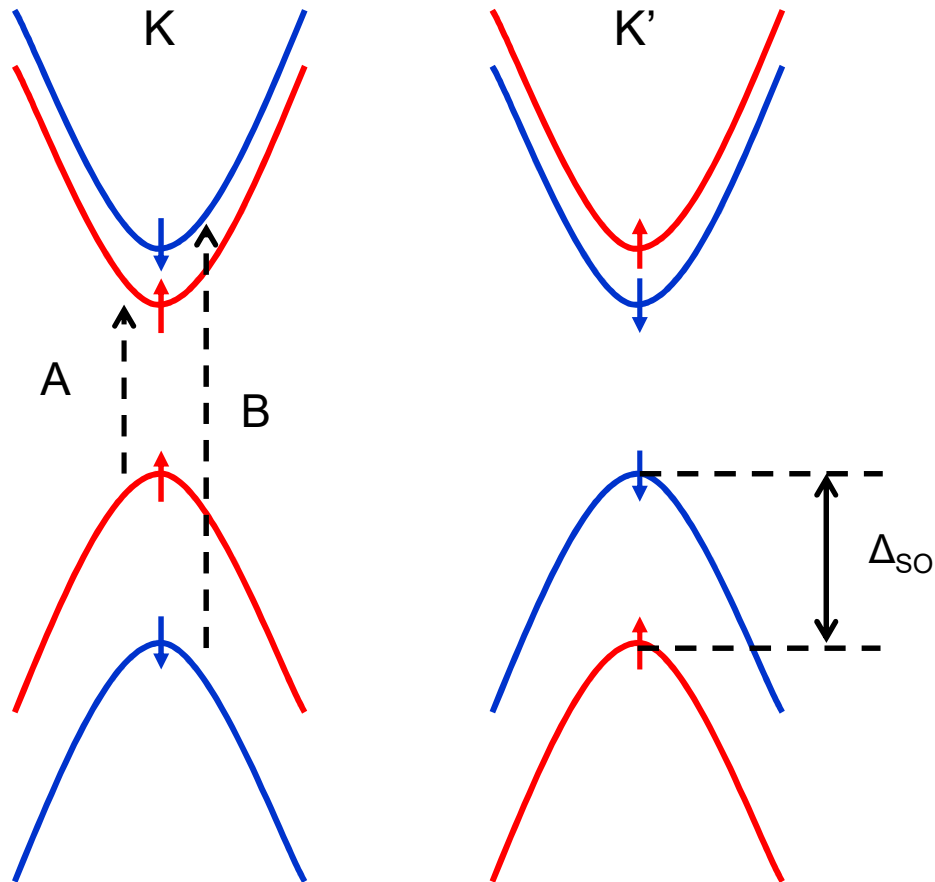
Honeycomb lattice with broken inversion symmetry induces the valley degree of freedom.



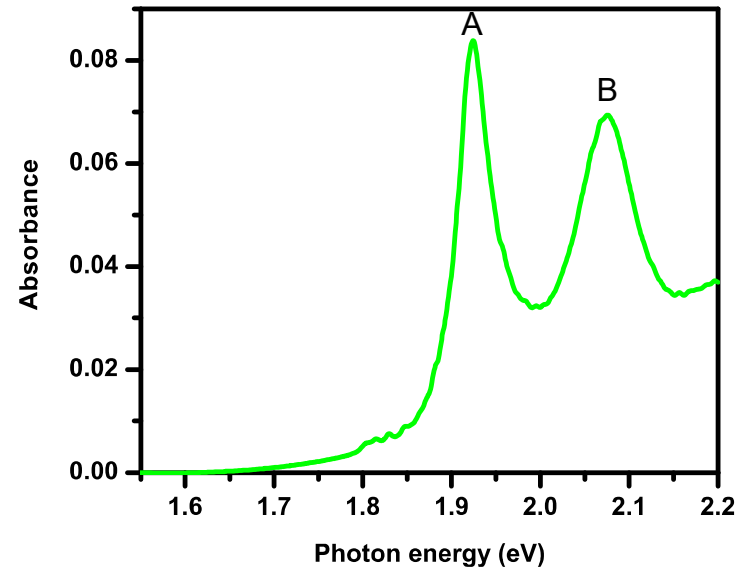
Valley dependent optical selection rule - accessed by circularly polarized light

# Valleys in TMDs

*Spin splitting by the strong spin-orbit coupling*

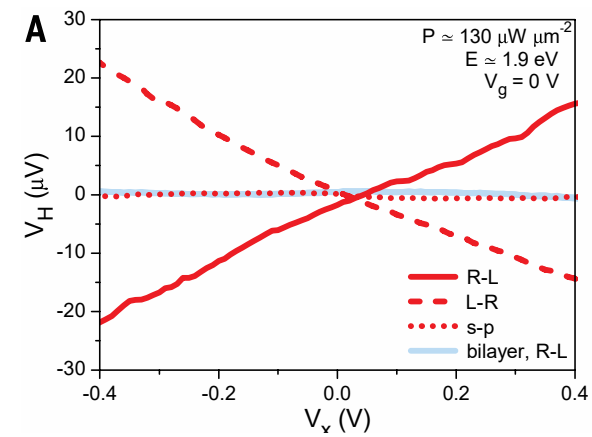
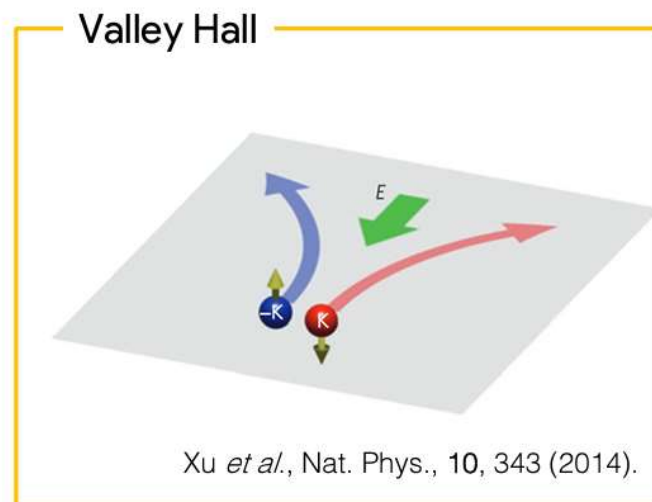
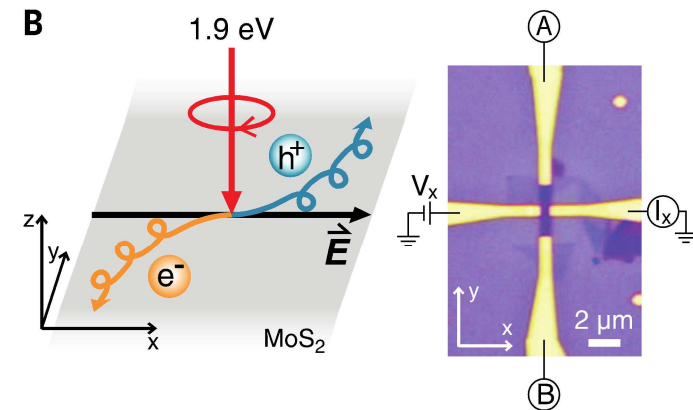
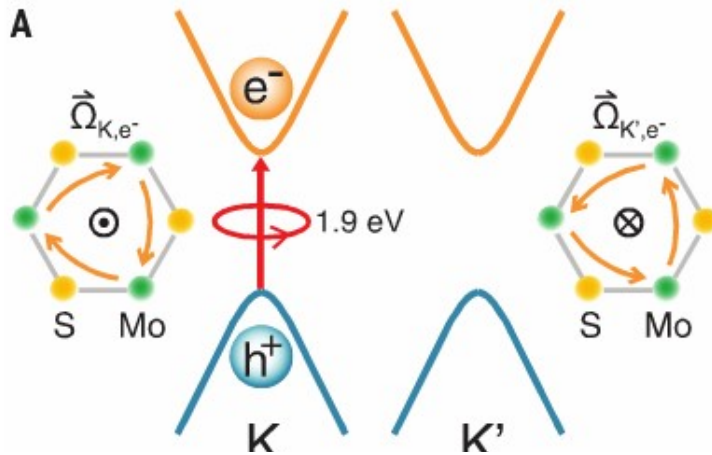


*Optical absorption spectra*



# Valley Hall Effect in Monolayer TMDC

Valley polarization by circularly polarized light  
:observation of Hall voltage by optical pumping

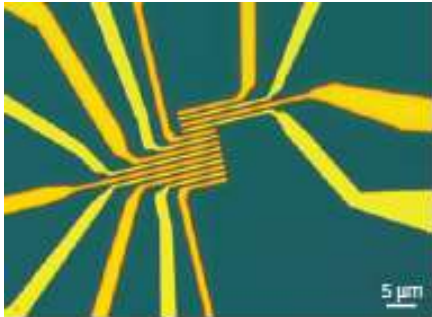


K. F. Mak *et al.*, Science (2014)

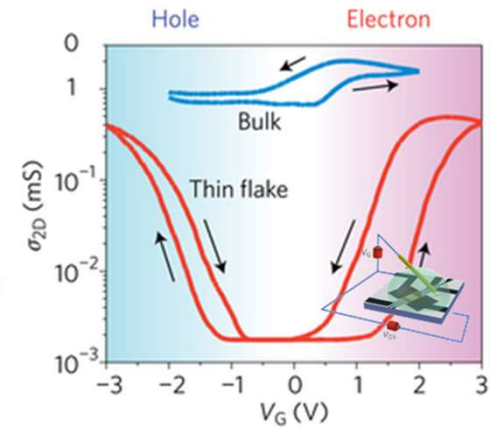
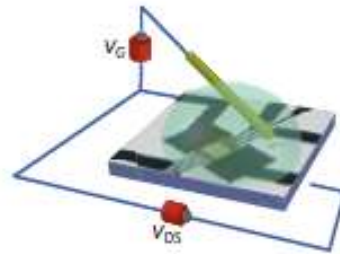


# Charge Carriers in TMDs

Ionic gel-gated MoS<sub>2</sub>

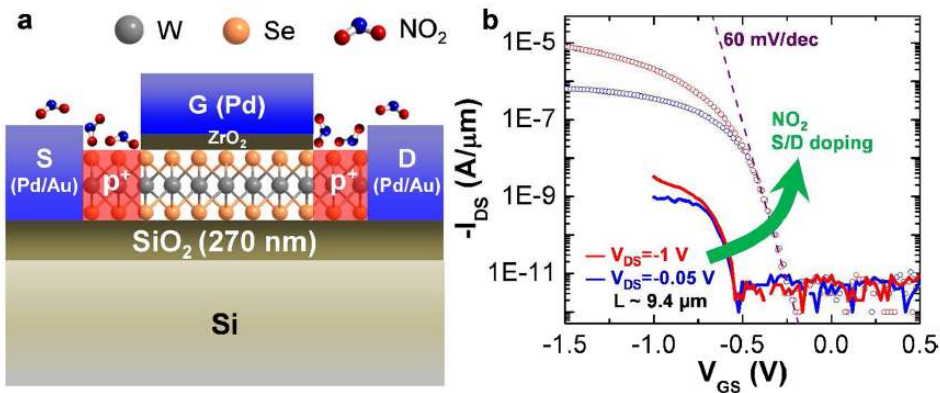


Y. Zhang et al. Nano Lett. (2012)



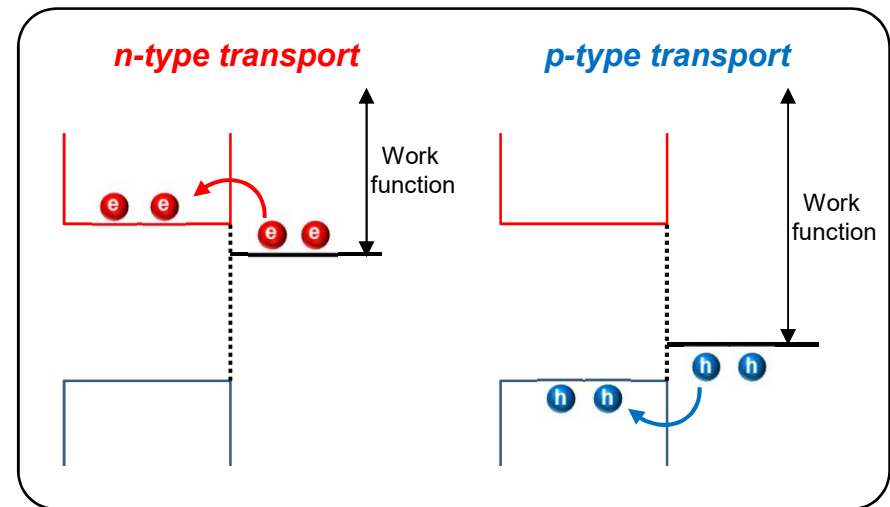
Ambipolar behavior

Tungsten Diselenide (WSe<sub>2</sub>)



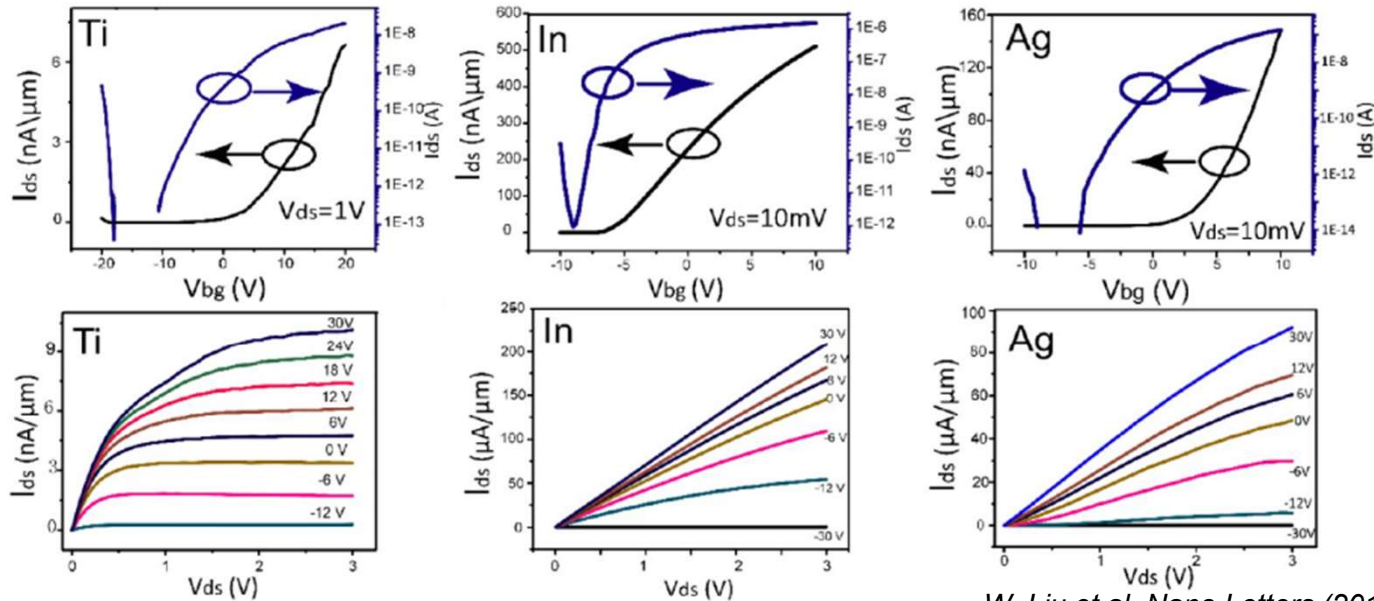
500cm<sup>2</sup>/Vs, ambipolar, 10<sup>4</sup> on/off ratio

H. Fang et al. Nano Lett. (2012)



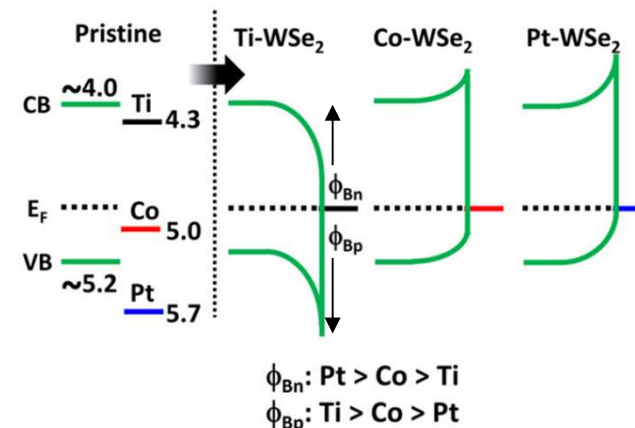
# Carrier Type Control in TMDs: WF of Metal

Transfer curve of  $WSe_2$  transistor with various metal contacts



W. Liu et al. Nano Letters (2013)

Band diagram for  $WSe_2$  FETs



I. Lee et al. Nanotechnology (2015)

Carrier type control with various metal contacts

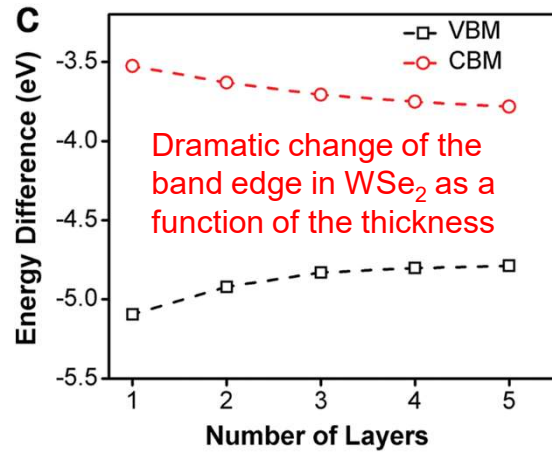
- Band bending occurs through the alignment of the Fermi level of a metal electrode
- Carrier type controlled with different work function of various metals

High WF of Pd on  $WSe_2$  → p-type  $WSe_2$

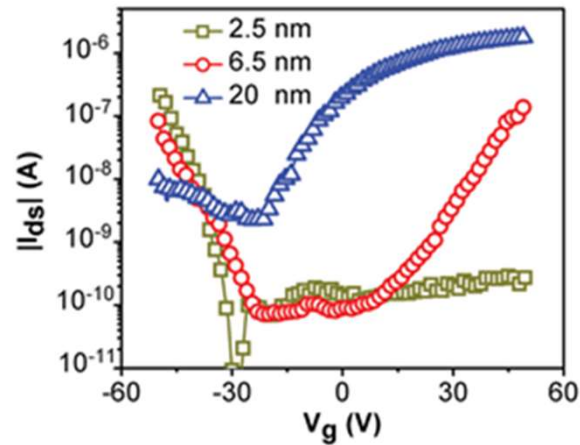
Low WF of In on  $WSe_2$  → n-type  $WSe_2$

# Carrier Type Control in TMDs: Thickness

Theoretical energy of monolayer to five-layer WSe<sub>2</sub>

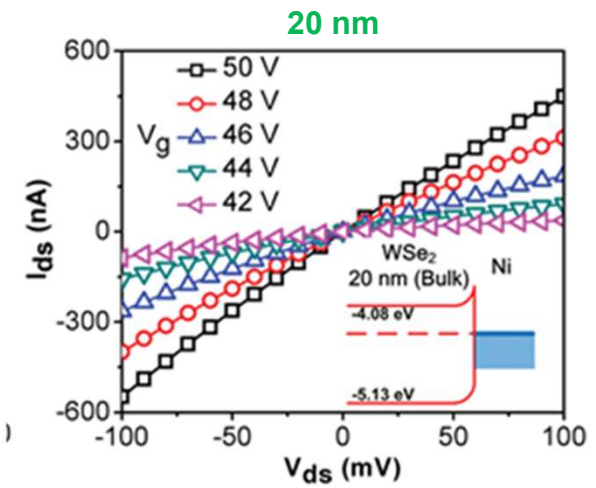
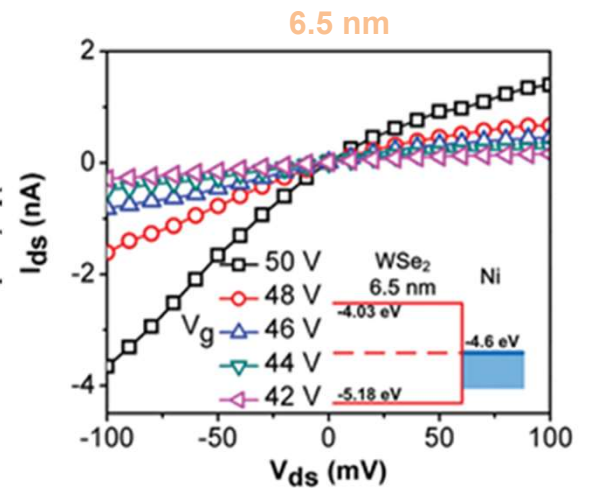
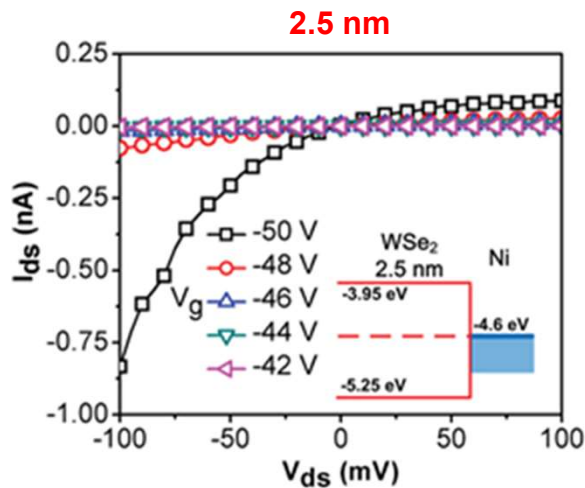


Transfer curves of WSe<sub>2</sub> transistors with various thicknesses



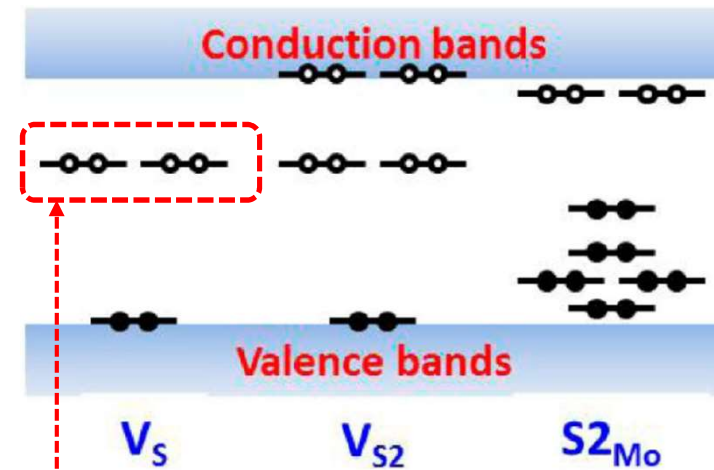
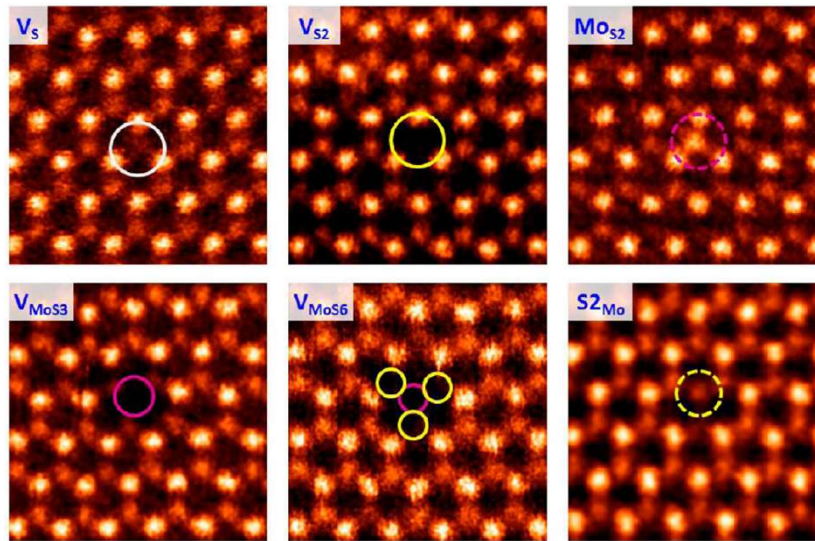
Carrier type control with various thicknesses

- 2.5 nm-thick WSe<sub>2</sub> → p-type WSe<sub>2</sub>
- 6.5 nm-thick WSe<sub>2</sub> → ambipolar WSe<sub>2</sub>
- 20 nm-thick WSe<sub>2</sub> → n-type WSe<sub>2</sub>



# Carrier Type Control in TMDs: Defect

Intrinsic point defects in monolayer MoS<sub>2</sub>



W. Zhou et al. Nano Letters (2013)

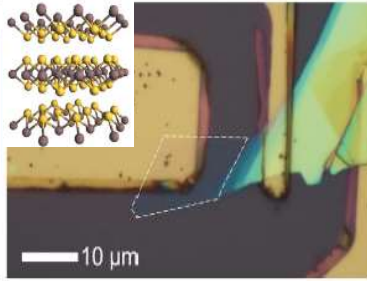
N-doping of TMDs by vacancies

- Sulfur vacancies have the lowest formation energy
- Sulfur vacancies introduce two **unoccupied deep levels** about 0.6 eV below the conduction

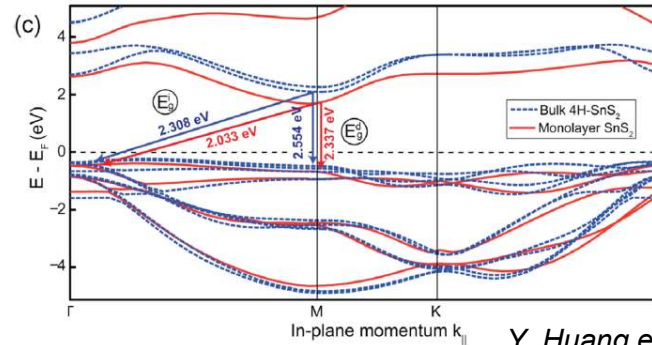
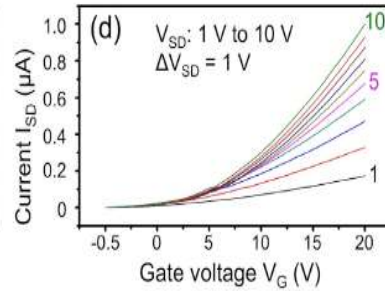
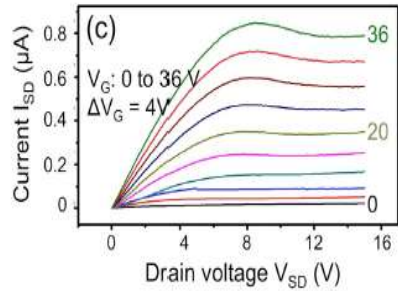
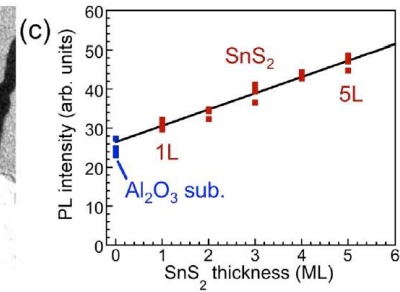
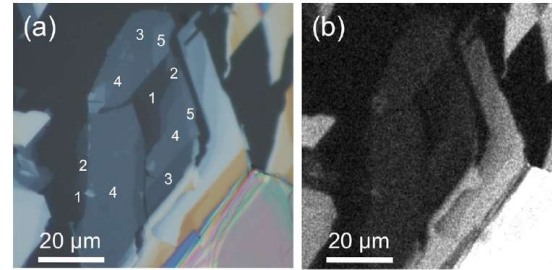
Sulfur vacancies act as a donor → n-type MoS<sub>2</sub>

# Emerging TMDs

## Tin Disulfide (SnS<sub>2</sub>)



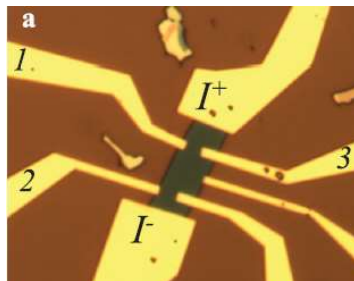
Thickness: ~ 0.6 nm per layer  
 Bandgap: 2.2 eV  
 SS: 80 mV/decade  
 On/Off ratio: ~ 10<sup>6</sup>  
 Mobility: 5 cm<sup>2</sup>/Vs



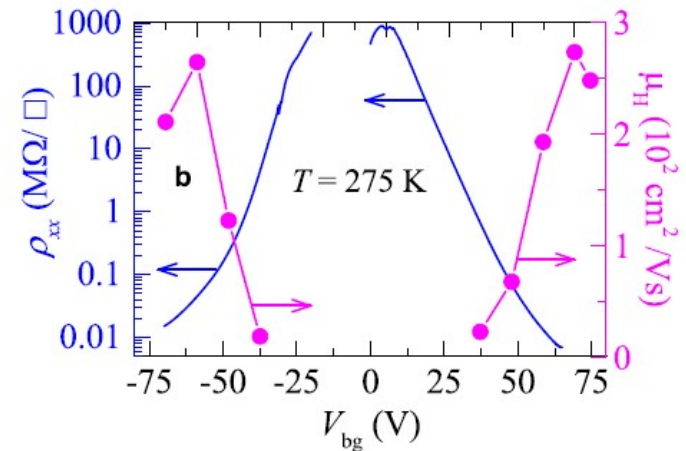
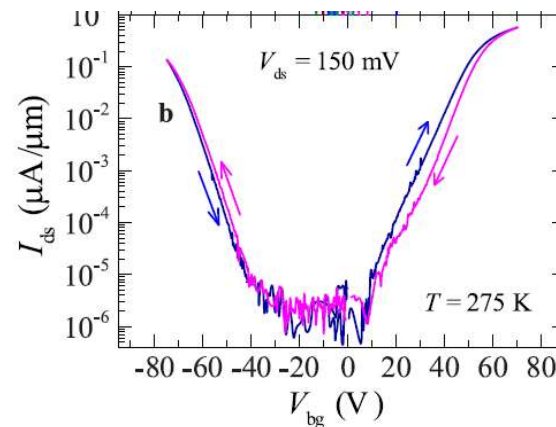
*SnS<sub>2</sub> has indirect bandgap for both bulk and monolayer*

Y. Huang et al. ACS Nano (2014)

## Molybdenum selenide (MoSe<sub>2</sub>)



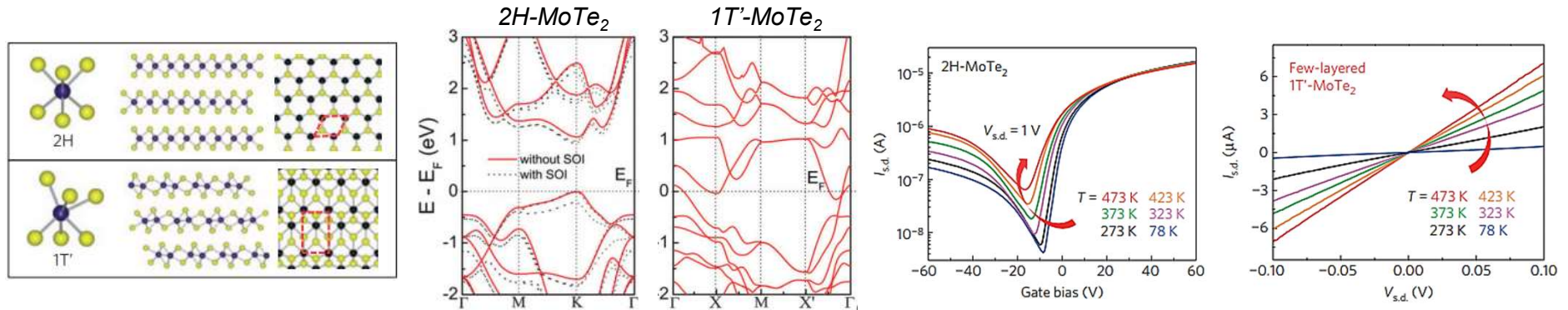
Thickness: ~ 0.7 nm per layer  
 Bandgap: ~ 1.41 eV  
 Mobility: ~ 200 cm<sup>2</sup>/Vs (e<sup>-</sup>)  
 ~150 cm<sup>2</sup>/Vs (h<sup>+</sup>)



N. R. Pradhan et al. ACS Nano (2014)

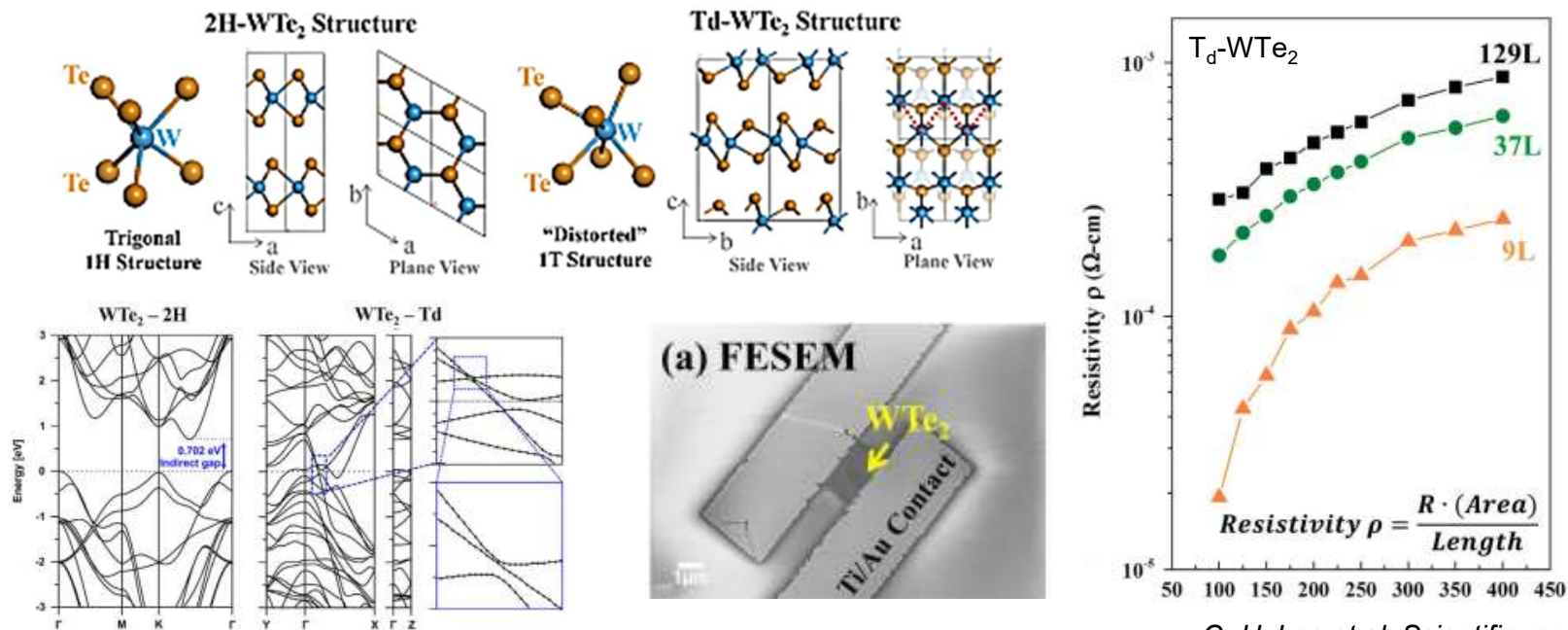
# Emerging TMDs

## Molybdenum Ditelluride ( $\text{MoTe}_2$ )



M. Kan et al. PCCP (2015) & D. H. Keum et al. Nature physics (2015)

## Tungsten Ditelluride ( $\text{WTe}_2$ )



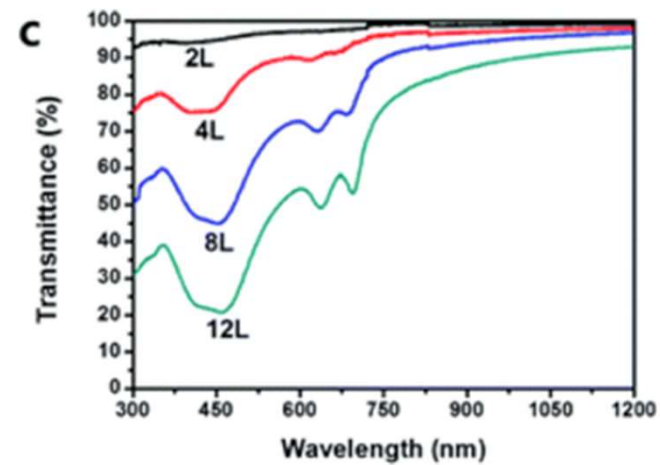
C.-H. Lee et al. Scientific reports (2015)

# Optical Transparency of TMDs

CVD-MoS<sub>2</sub>



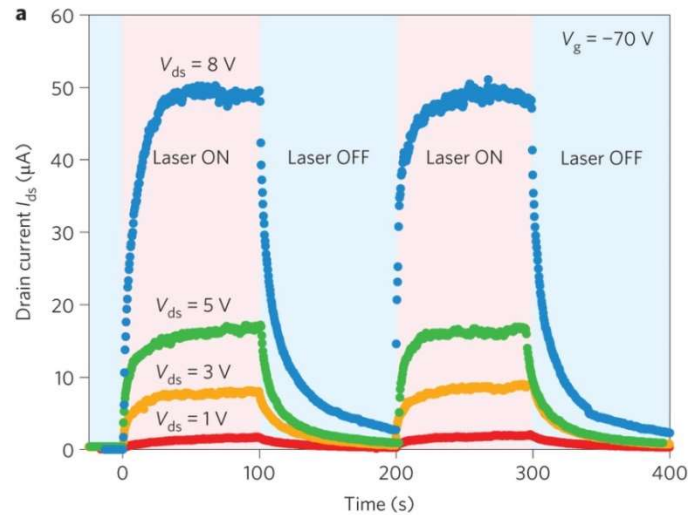
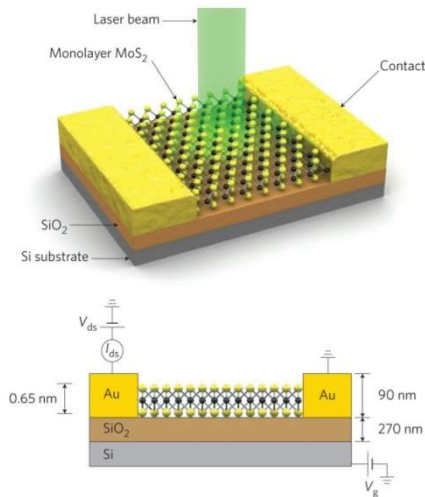
2L -> 4L -> 8L -> 12L



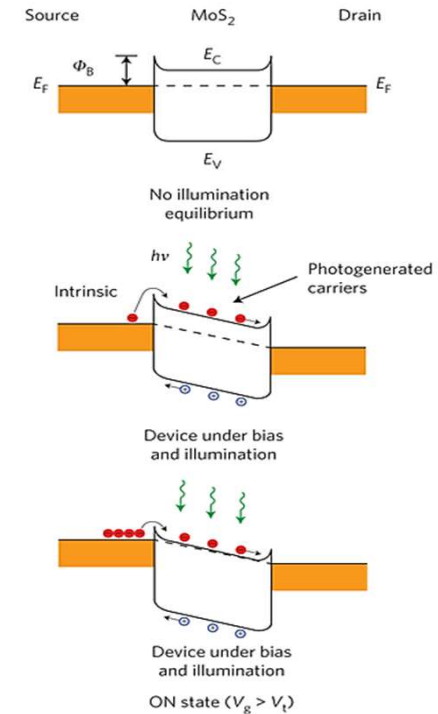
Over 90% transmission rate  
@2L and visible range

# Optical Response of TMDs

## Highly efficient MoS<sub>2</sub> photodetector

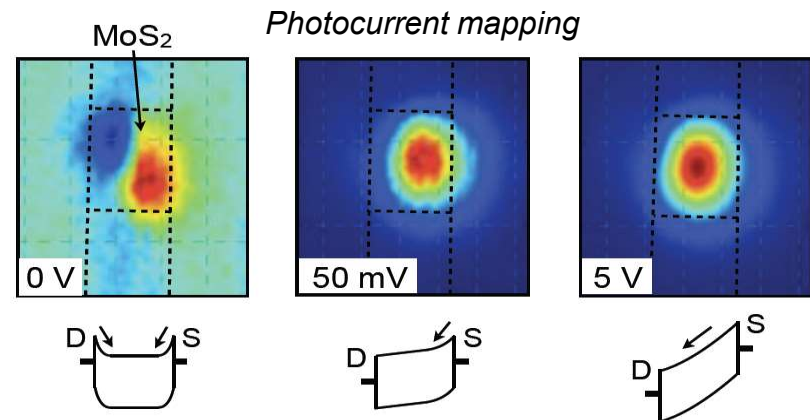
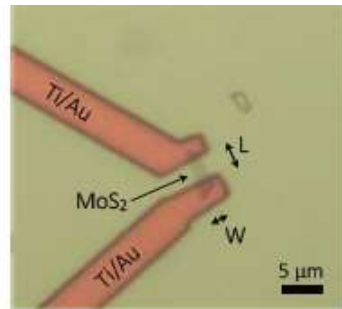
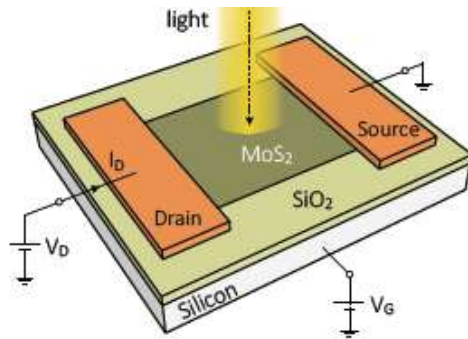


High efficiency: 880 A/W (cf. graphene: 0.5 mA/W)  
 High light absorption: 5 ~ 10%  
 Efficient charge separation due to limited dimension (ultrathinness)



O. Lopez-Sanchez et al. Nature Nanotechnol. (2013)

## Mechanism of photocurrent in MoS<sub>2</sub>

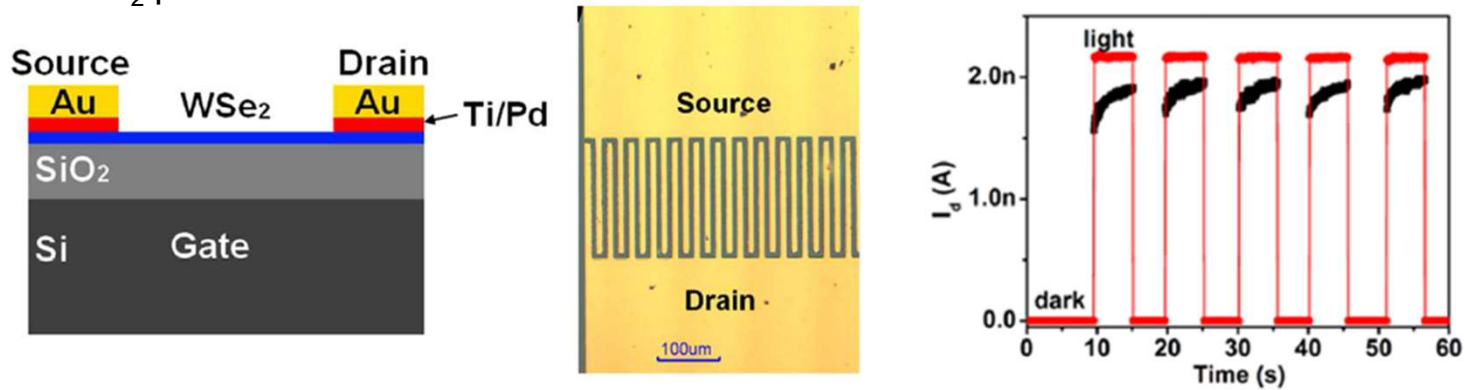


M. M. Furchi et al. Nano Lett. (2014)



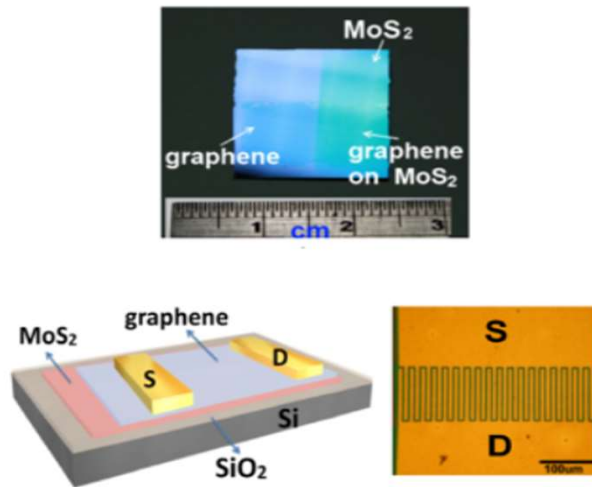
# Optical Response of TMDs

WSe<sub>2</sub> photodetector



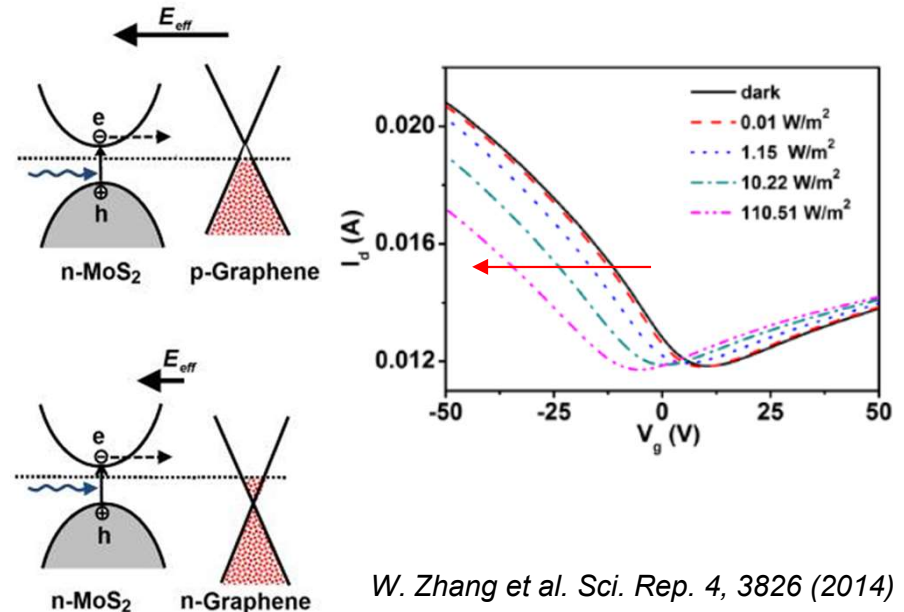
W. Zhang et al. ACS Nano (2014)

MoS<sub>2</sub>/Graphene heterostructure photodetector



1. Electron-hole pairs are produced in MoS<sub>2</sub>.
2. Electrons moves to graphene due to effective electric field.
3. High photoresponsivity is obtained.

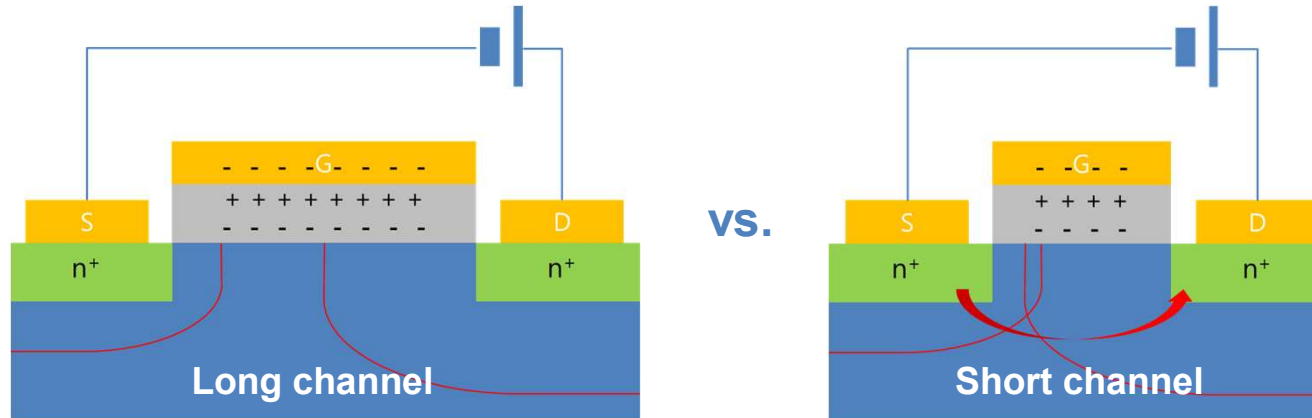
Gate-tunability of photocurrent



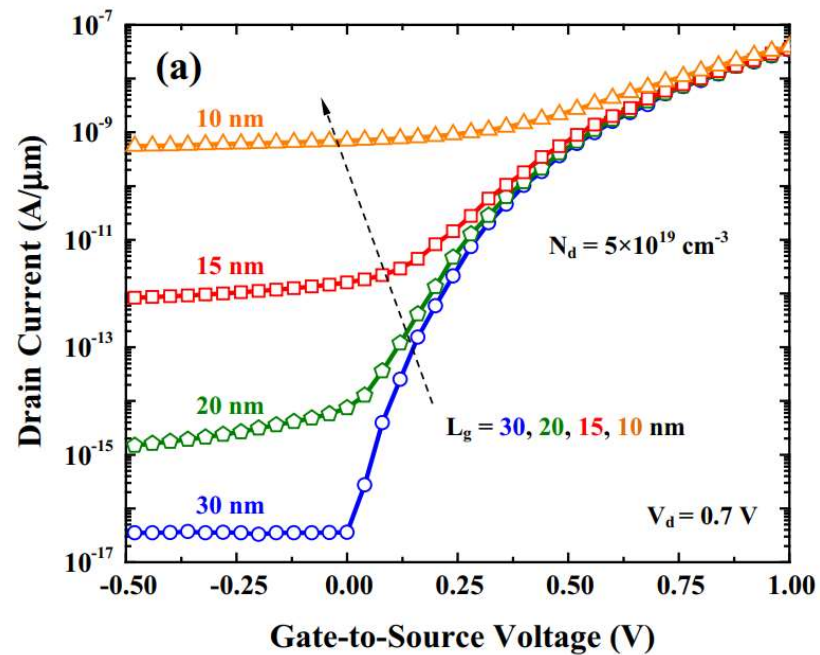
W. Zhang et al. Sci. Rep. 4, 3826 (2014)

# Short Channel Effect

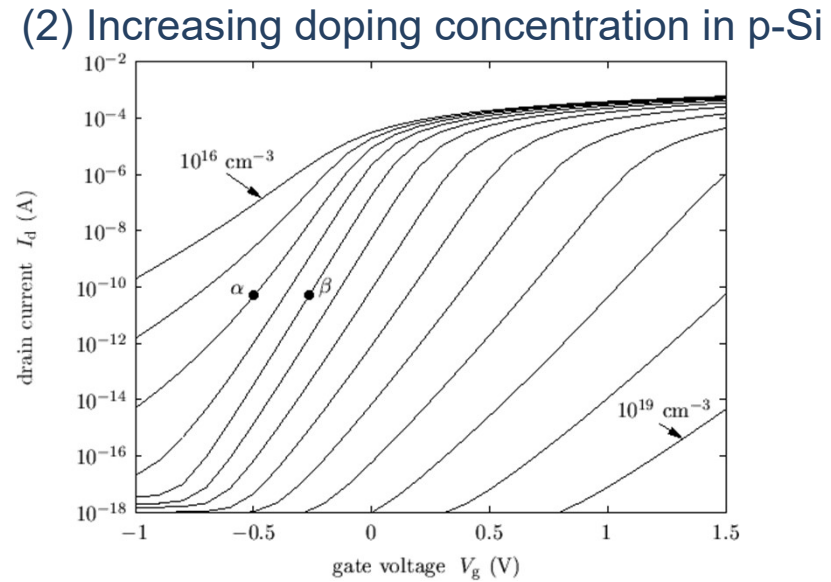
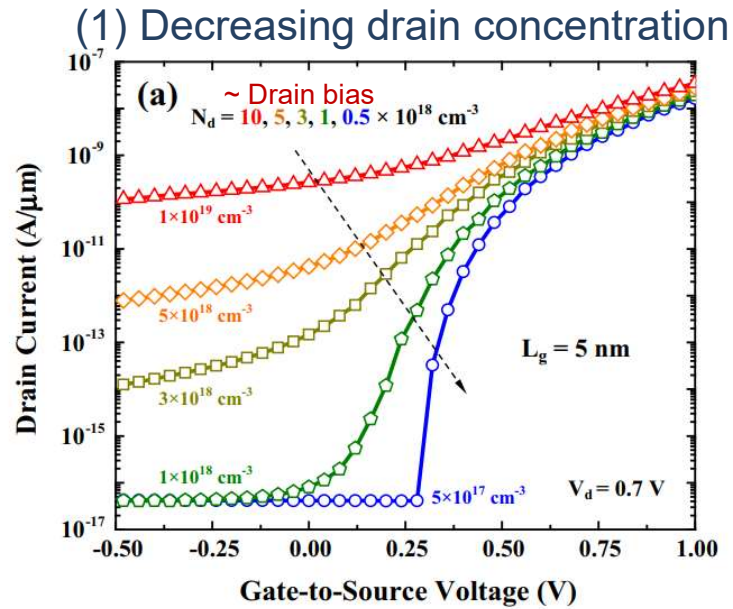
## Subthreshold leakage



Electrons can flow at turn-off state (current leakage)



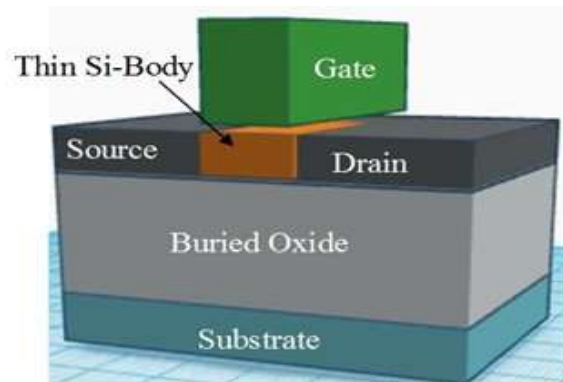
# Short Channel Effect



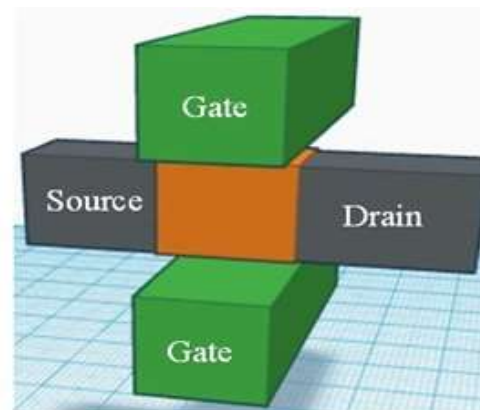
Degradation of carrier mobility due to difficulty in overcoming of contact barrier and increase charged impurity scattering

N.D. Chien et al, Microelectronics Reliability, 2015

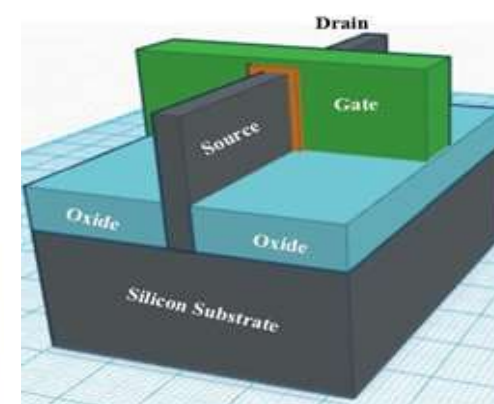
Thin silicon on Insulator  
(higher gate capacitance)



Dual gates



FinFET



# 2D semiconductors : Promising candidates beyond Si

## Switching behavior of thin film FET

One-dimensional Poisson equation

$$\frac{d^2\varphi(x)}{dx^2} - \frac{\varphi(x)}{\lambda^2} = 0 \text{ with } \lambda = \sqrt{\frac{t_b t_{ox} \epsilon_b}{\epsilon_{ox}}},$$

Transistor size ( $\lambda$ ) :  $\downarrow \rightarrow t_b : \downarrow$  &  $\epsilon_b : \downarrow$

$\varphi(x)$  : Potential distribution in the source/drain direction

$\lambda$  : Transistor characteristic length

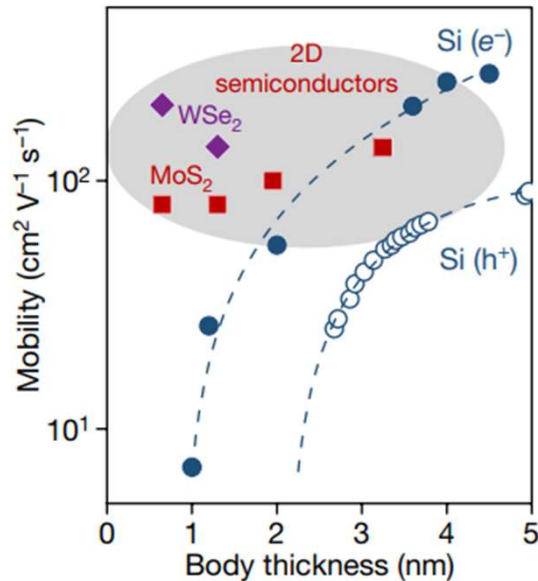
$t_b$  : Thickness of the semiconductor body

$\epsilon_b$  : Dielectric constant of the semiconductor body

$t_{ox}$  : Thickness of the dielectric layer

$\epsilon_{ox}$  : Dielectric constant of the dielectric layer

## 1. Atomically thin body thickness ( $t_b < 1\text{nm}$ )



### Silicon

- Surface dangling bond and roughness.
- Strongly interface roughness scattering, leading to degradation of carrier mobility with decreasing  $t_b$

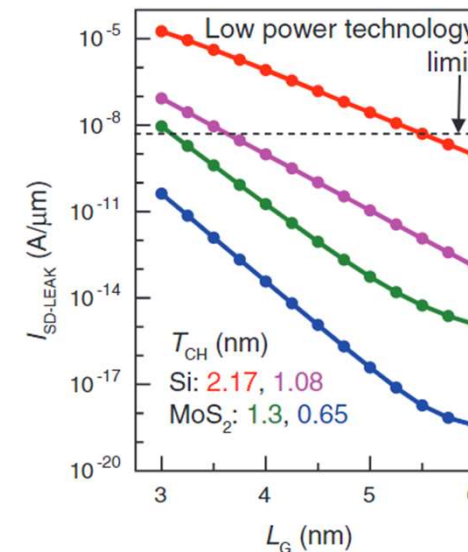
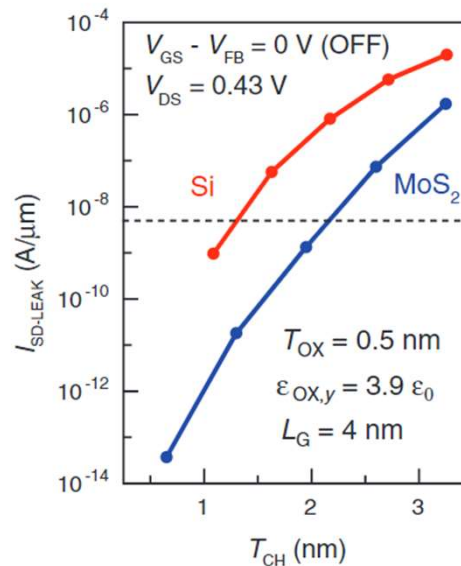
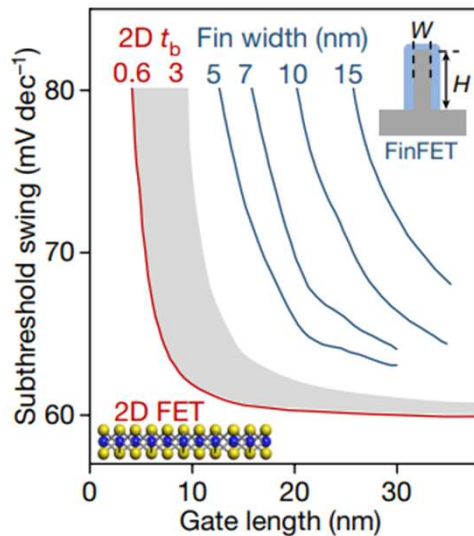
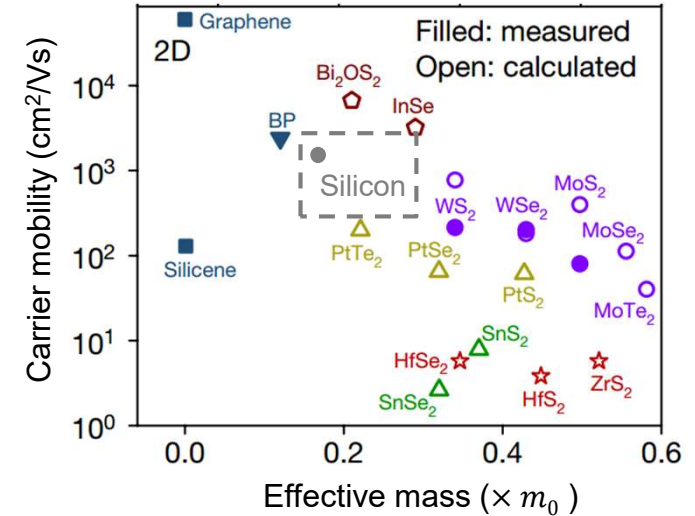
### 2D semiconductor

- No dangling bond and ultra-flat interface
- Little mobility variation with decreasing  $t_b$

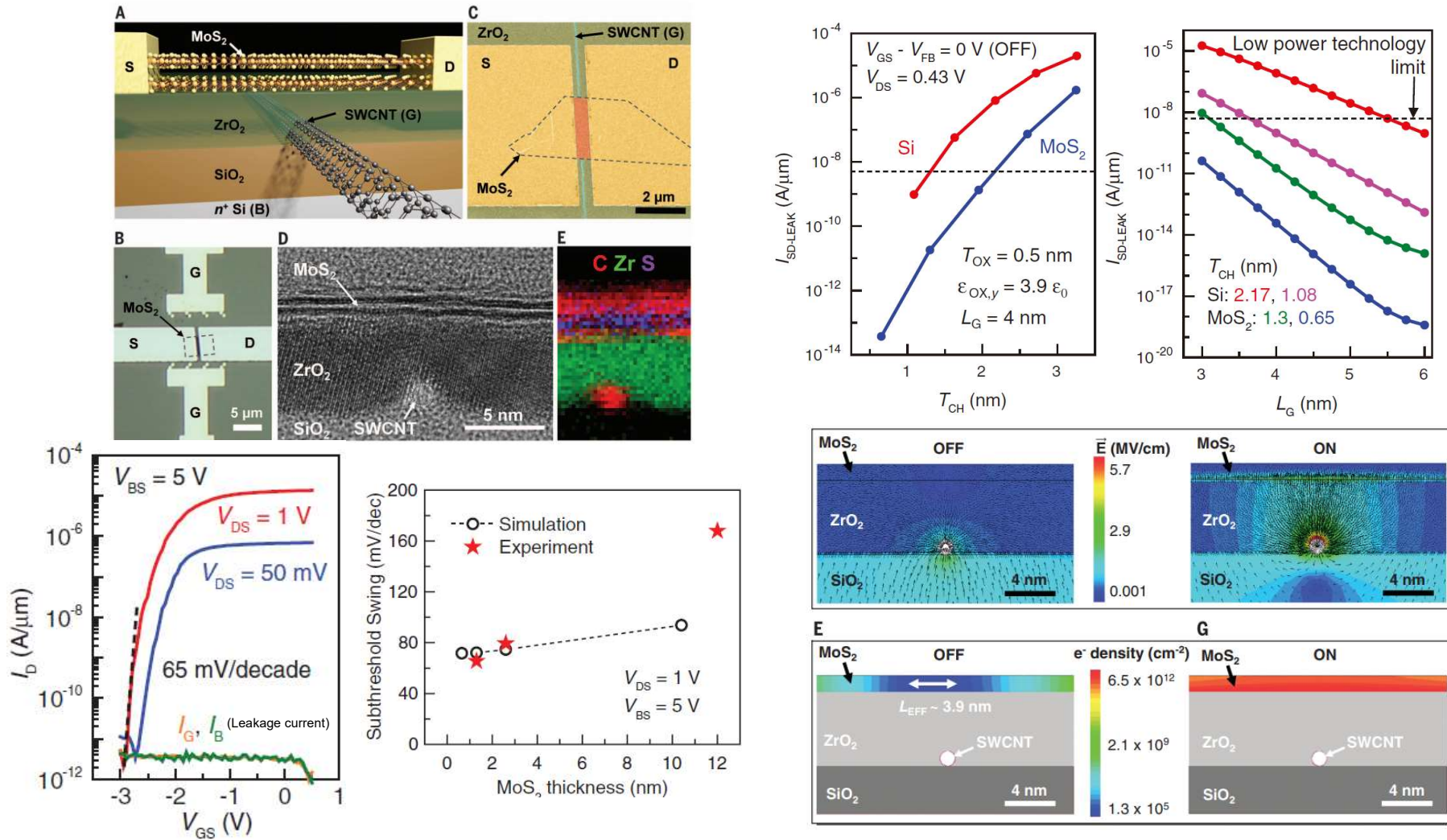
# 2D semiconductors : Promising candidates beyond Si

## 2. Immunity to short channel effect of 2D semiconductor

- Low in-plane dielectric constant ( $\epsilon_b : \downarrow$ )  
 $\rightarrow \epsilon_{MoS_2} : \sim 4 / \epsilon_{Si} : \sim 11.7$
- Larger effective mass & Larger bandgap  
 $\rightarrow$  Effectively suppressing in direct tunnelling between source and drain electrodes in short channel devices, thus effectively suppressing leakage currents

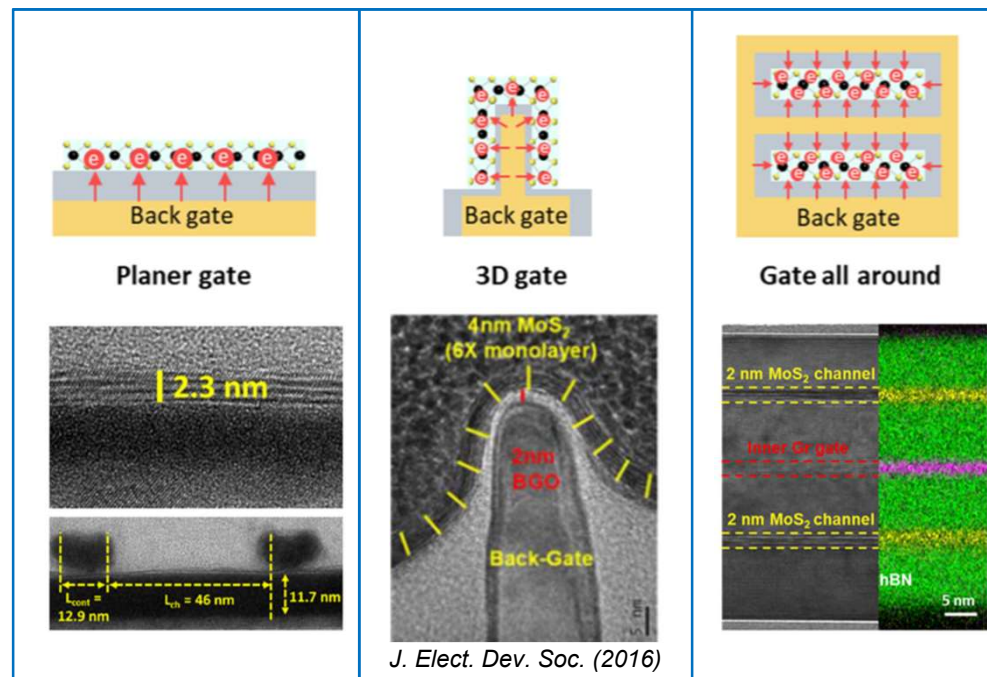
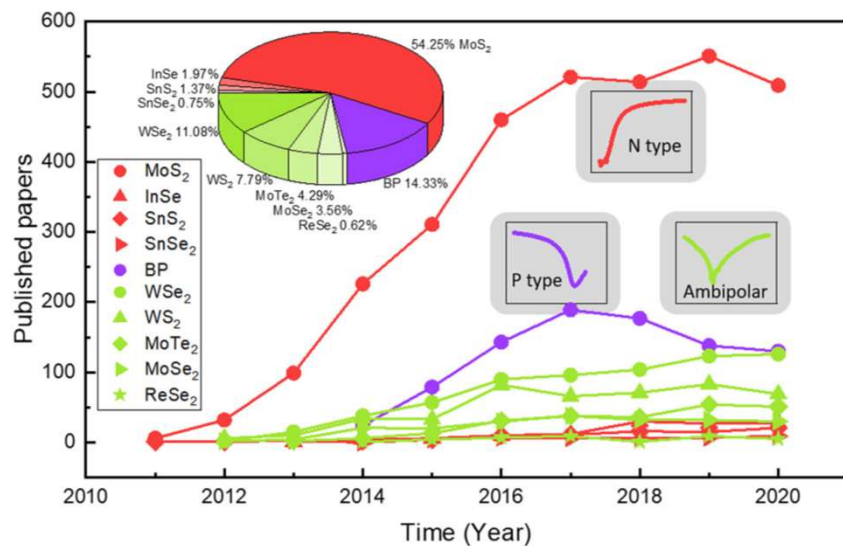
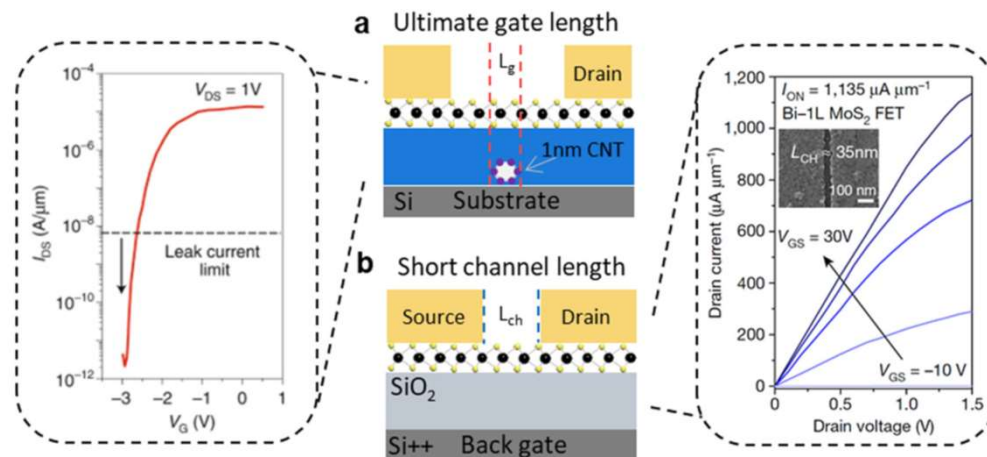
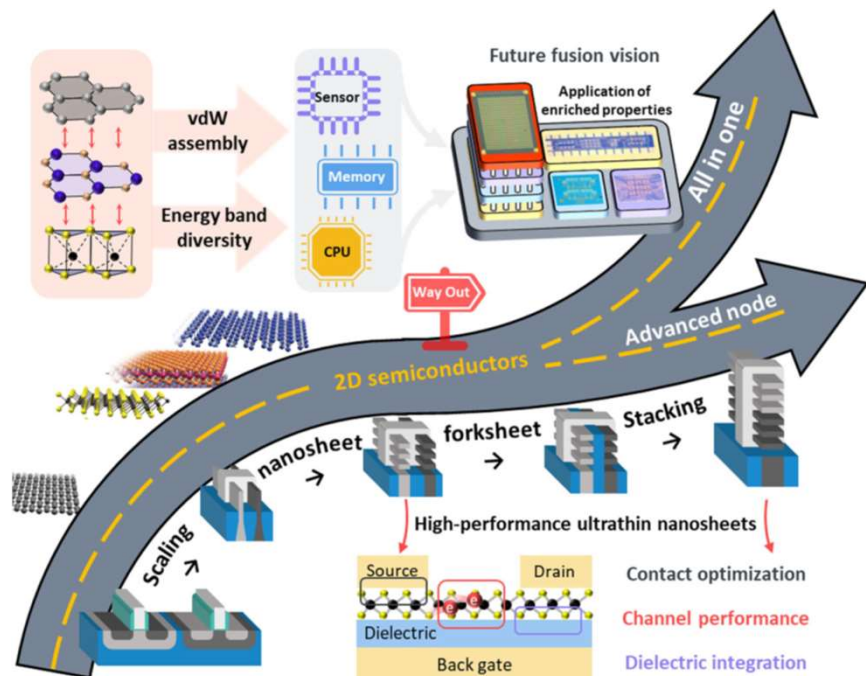


# No Short Channel Effect in 2D Channel



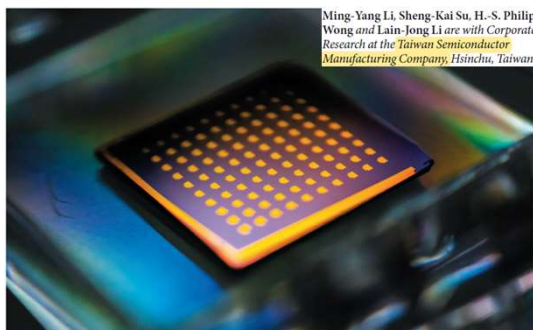
- Cause of low short channel effect, channel length can be scaled-down to nano-meter unit.
- TMD channels have high mobility (~hundreds cm<sup>2</sup>/V·s).
- However, high contact resistance makes device performance worse.
- Researches for reducing contact resistance are under way actively.

# Research Trend in 2D Devices



# Breakthrough in 1nm process

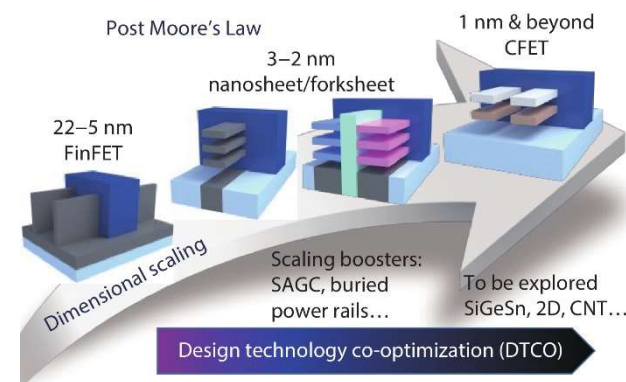
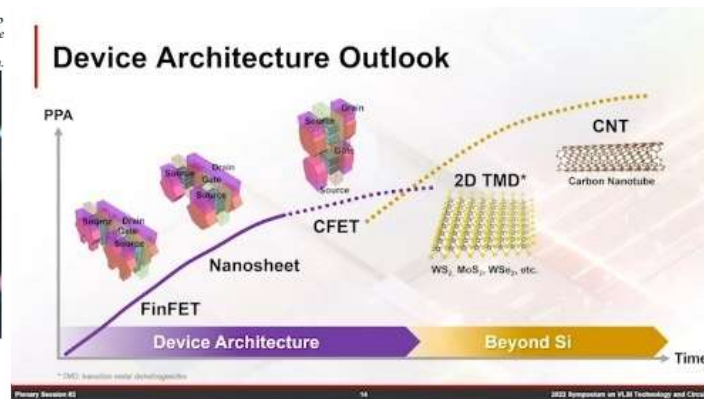
## 2D semiconductors for next-generation FETs



Ming-Yang Li, Sheng-Kai Su, H.-S. Philip Wong and Lain-Jong Li are with Corporate Research at the Taiwan Semiconductor Manufacturing Company, Hsinchu, Taiwan.

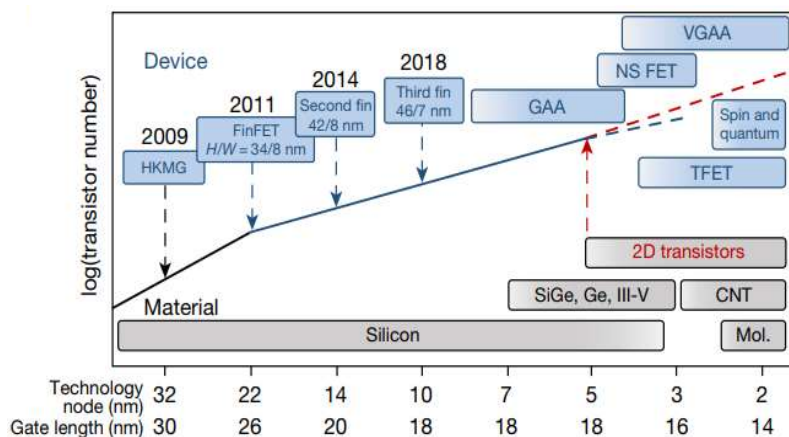
Chips made from stacks of transistors just one molecule thick might power the next generation of computers.

How 2D semiconductors could extend Moore's law



Nature, 567, 169-170 (2019) & TSMC at VLSI 2022

## Papers from global semiconductor companies



Nature 591, 43-53 (2021)

Article  
**Ultralow contact resistance between semimetal and monolayer semiconductors**

Article  
**High-κ perovskite membranes as insulators for two-dimensional transistors**

Article  
**Wafer-scale single-crystal hexagonal boron nitride monolayers on Cu (111)**

ARTICLE  
<https://doi.org/10.1038/s41467-022-31886-6> OPEN  
Low-defect-density WS<sub>2</sub> by hydroxide vapor phase deposition

RESEARCH ARTICLE  
**ADVANCED MATERIALS**  
www.advmat.de

2D Materials-Based Static Random-Access Memory

REVIEW ARTICLE  
**nature electronics**  
<https://doi.org/10.1038/s41928-021-00670-1>

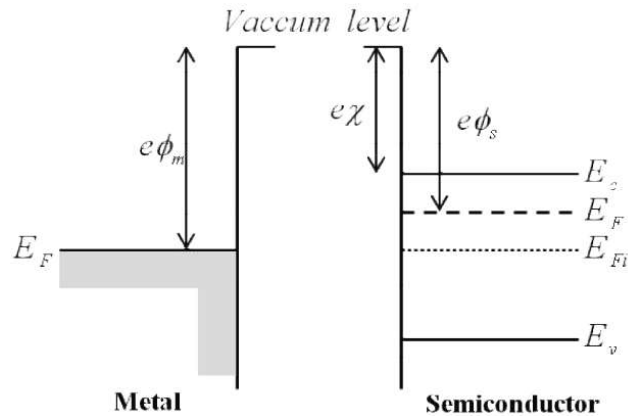
Transistors based on two-dimensional materials for future integrated circuits

ARTICLES  
**nature materials**  
<https://doi.org/10.1038/s41563-020-0795-4>

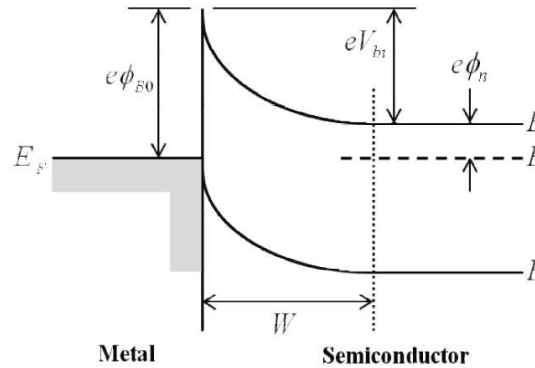
Ledge-directed epitaxy of continuously self-aligned single-crystalline nanoribbons of transition metal dichalcogenides



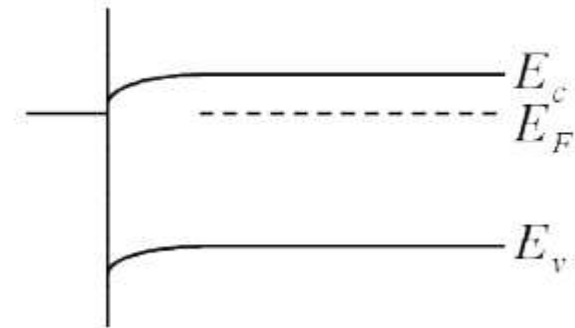
# Schottky and Ohmic Contacts



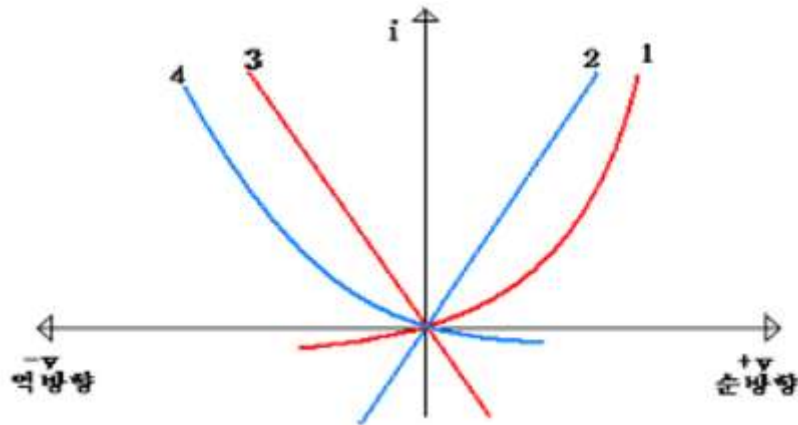
<before contact>



<after contact>

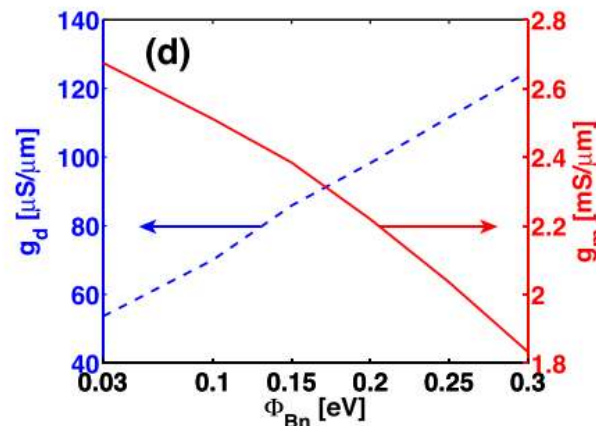
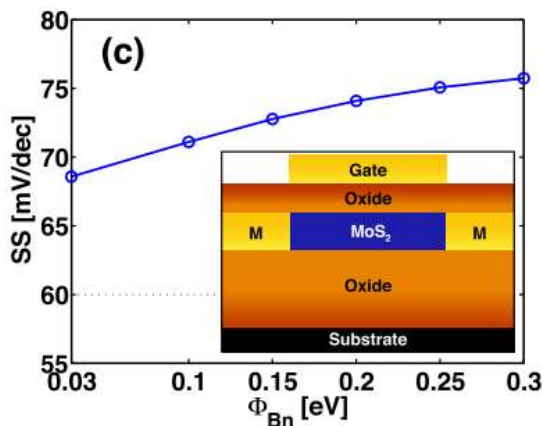
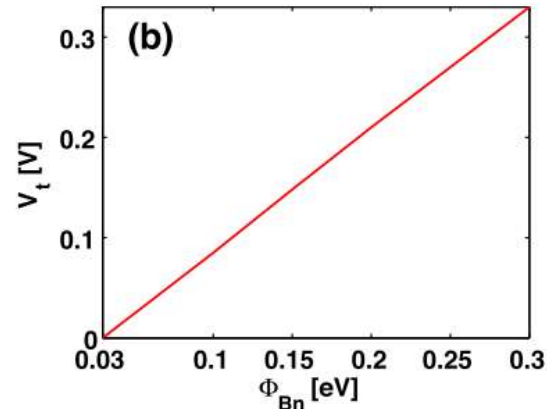
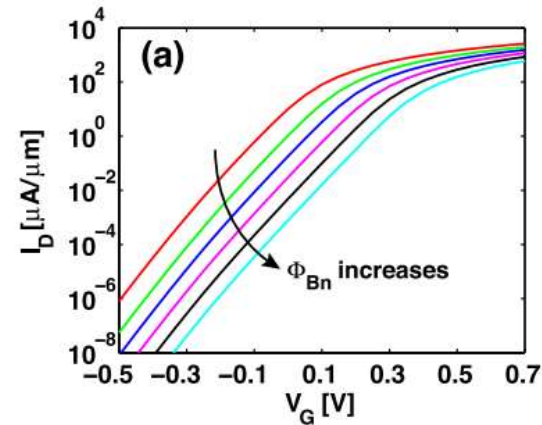


<Ohmic contact>



- Ohmic contact (2: n-type, 3: p-type)  
→ Non rectifying
- Rectifying contact (1: n-type, 4: p-type)  
→ Schottky contact

# Schottky and Ohmic Contacts



When  $\Phi_{Bn}$  increases from 30 to 300meV

- Linear increase of threshold voltage( $V_t$ )  
→ Difficult to overcome the SB
- Subthreshold swing(SS) shows degradation by 10%  
 $SS = \partial V_G / \partial \log_{10} I_D$

- $g_d$  (drain tunability) is increased by 130%

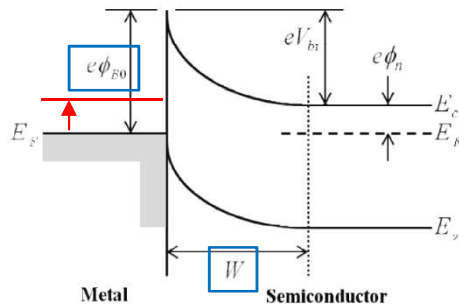
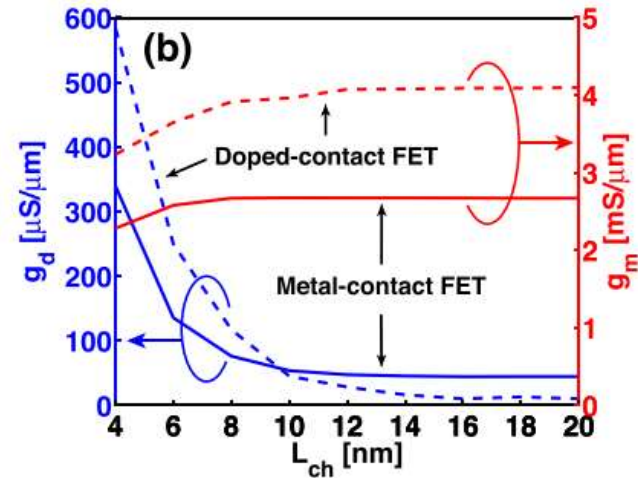
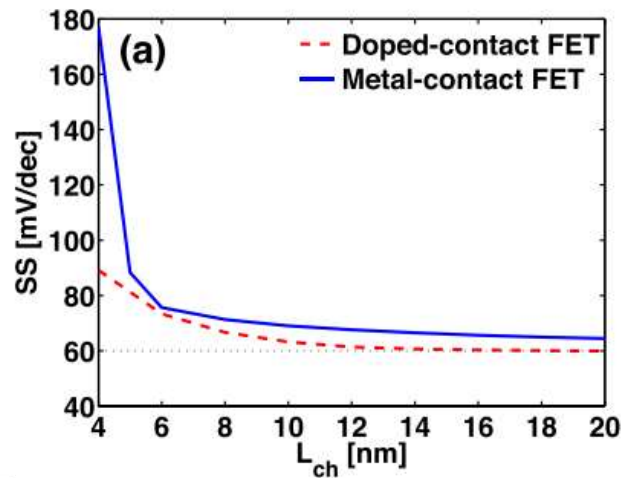
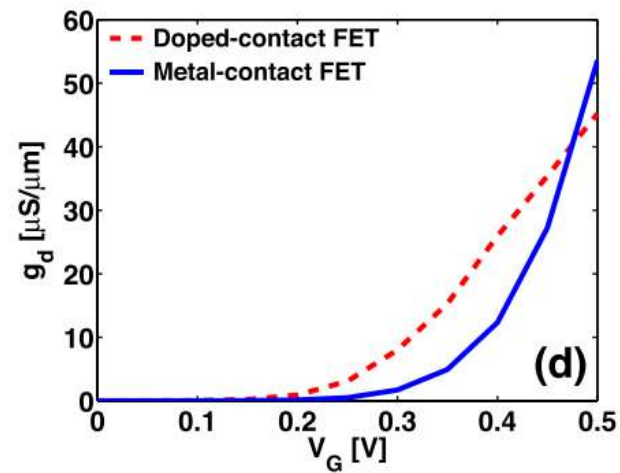
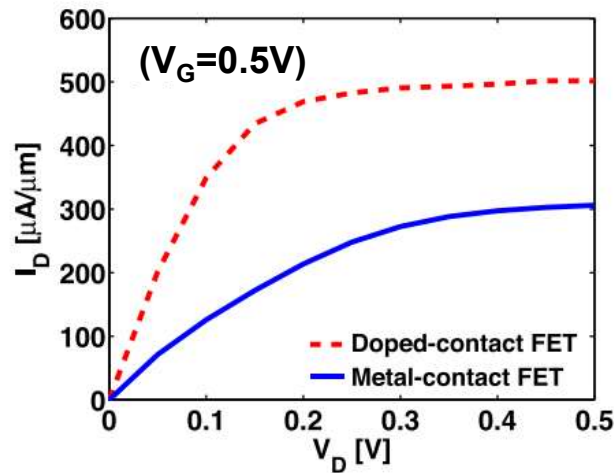
$$g_d = \partial I_D / \partial V_D$$

- $g_m$  (gate tunability) is decreased by 30%

$$g_m = \partial I_D / \partial V_G$$

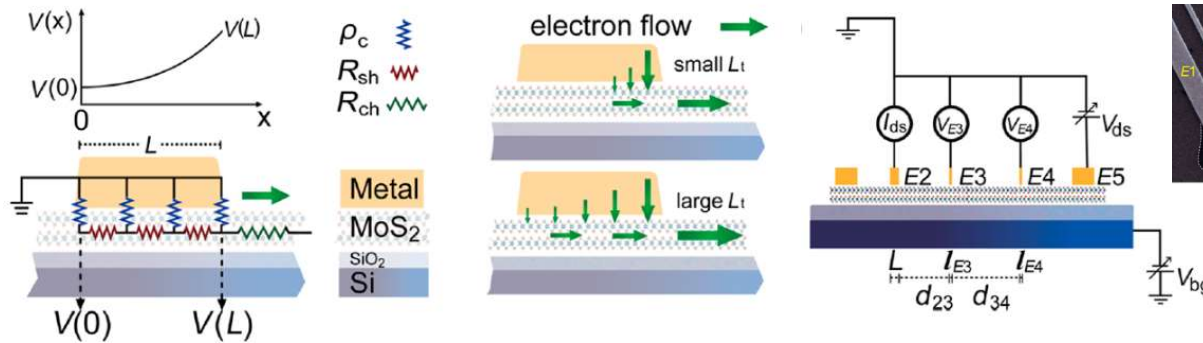
**Better device performance can be achieved by using smaller  $\Phi_{Bn}$**

# Schottky and Ohmic Contacts: Effect of doping



- **At low gate voltages**  
Thermionic current is more susceptible to the variation of  $V_D$  with doped contacts than with metal contacts
- **At high gate voltages**  
The Schottky barrier thickness is more sensitive to the  $V_D$  variation than the top of the barrier in doped-contact FETs

# 2D Semiconductor-Metal Contacts

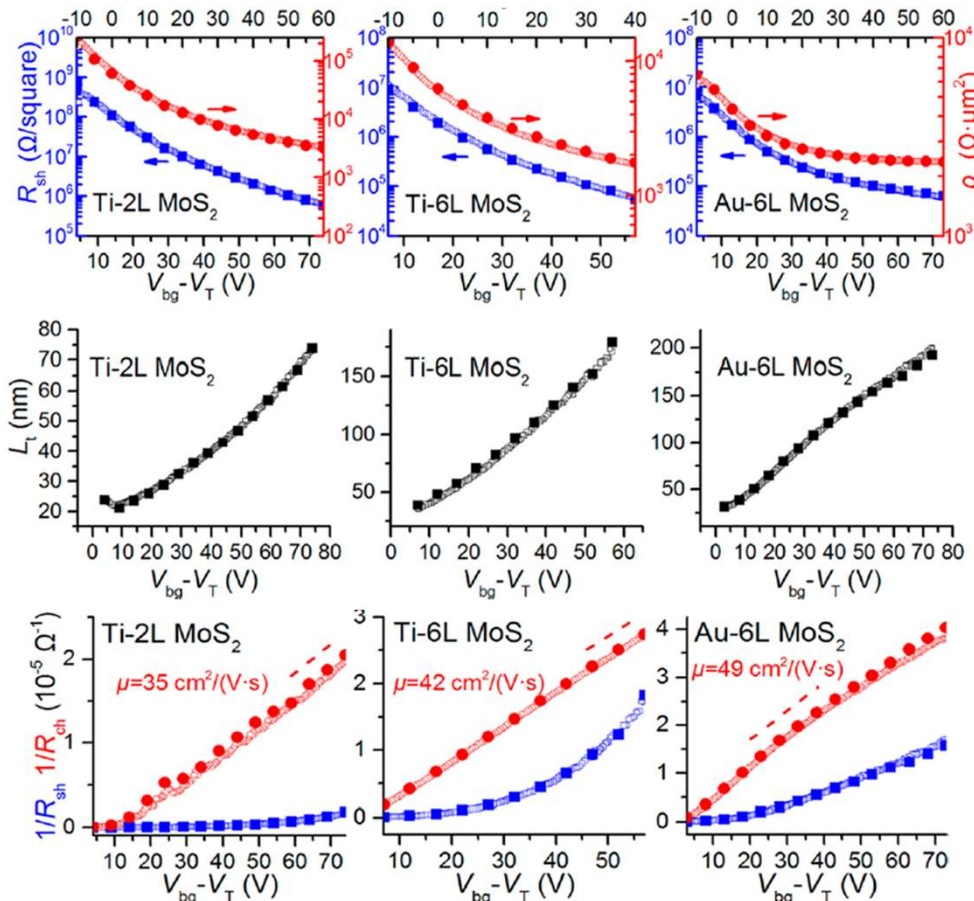


Contact Resistance

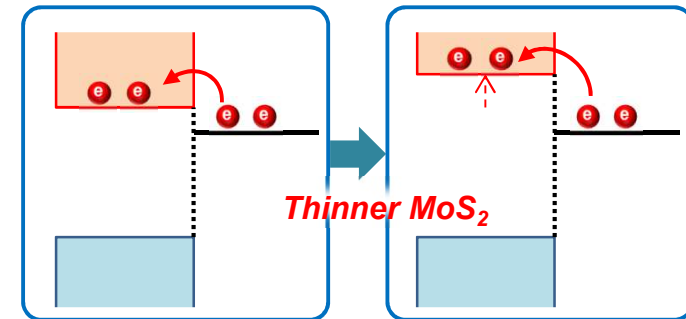
$$R_c = V(L)/I_{ds}$$

Effective conductive length

$$L_t = \sqrt{\rho_c/R_{sh}}$$



1. Contact Resistance increases with decreasing thickness.  
→ Rise of the conduction band bottom

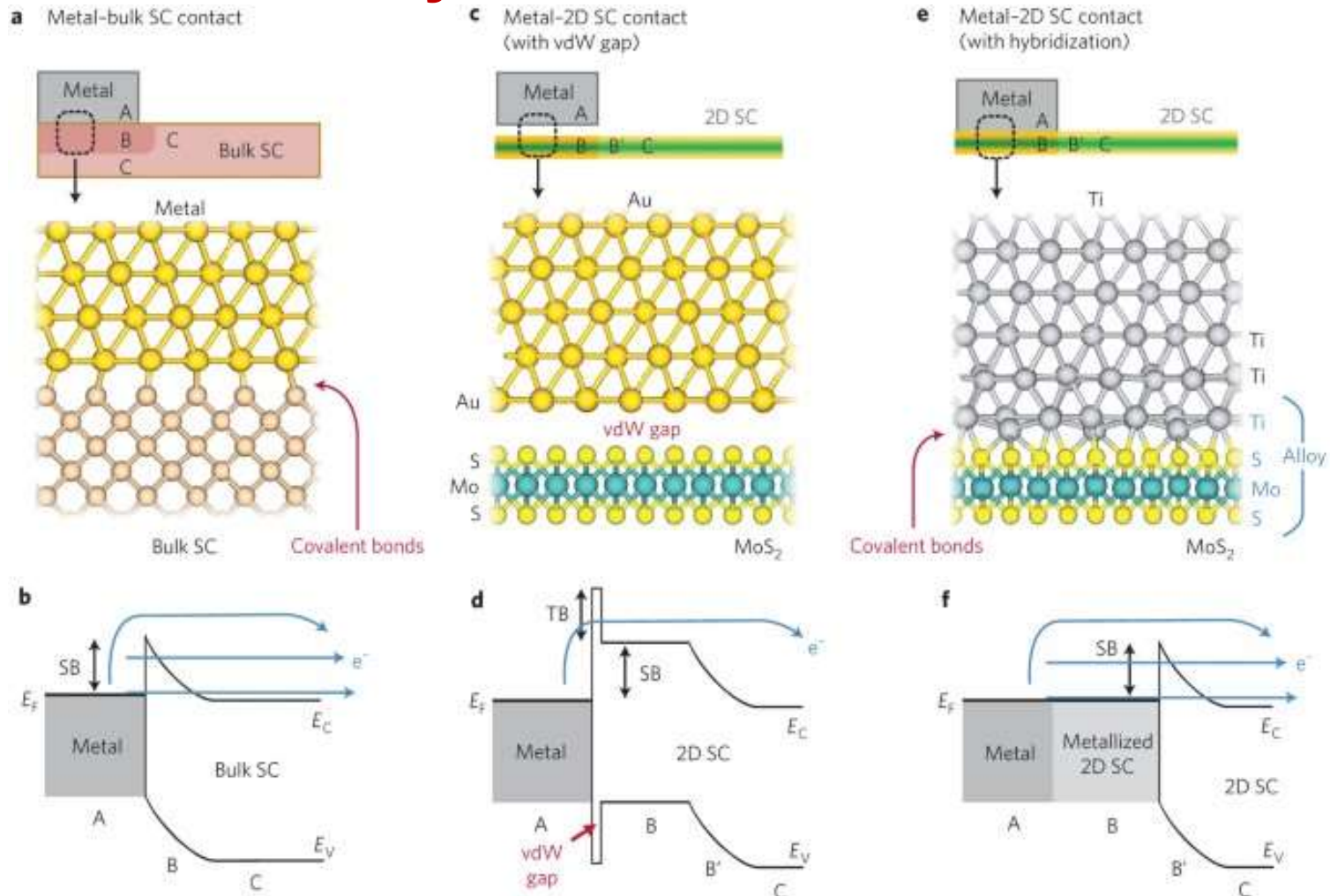


2. Effective conductive length ( $L_t$ ) increases with  $V_{bg}$ .  
→  $R_{sh}$  drops more severely.
3.  $R_c/R$  become larger for shorter channel length.  
→ In short channel devices,  $R_c$  is critical.

For low contact resistance ( $R_c$ )

1.  $L \gg L_t$
2. Engineering of dielectric environment (doping)
3. Band engineering in Interlayer between  $\text{MoS}_2$  & metal

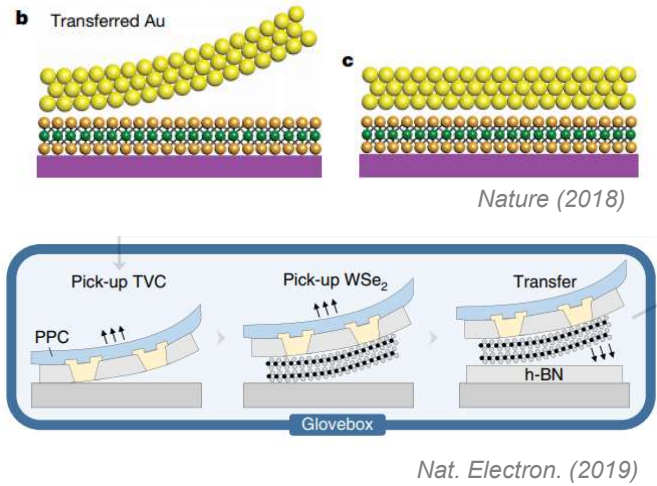
# Schottky and Ohmic Contacts



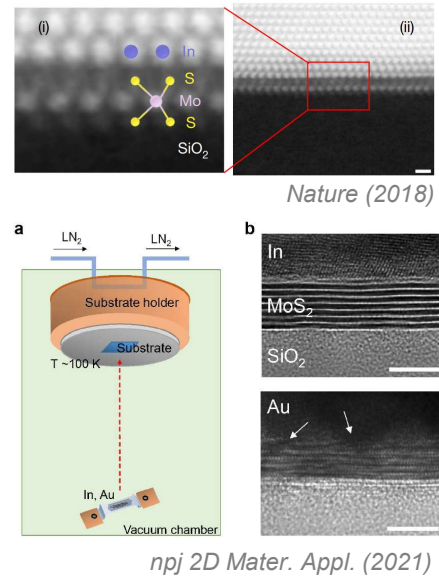
- vdW gap forms **additional ‘tunnel barrier’** between 2D channel and metal.
- For device-to-device variability of metal-contact MoS<sub>2</sub> FETs, Schottky barrier height is a key device parameter that determines the overall performance of transistors.
- To reduce device-to-device variability in MoS<sub>2</sub> FETs, contact resistance should be reduced.
- **Need to eliminate the vdW gap using metallized 2D SC.**

# 1. vdW contact

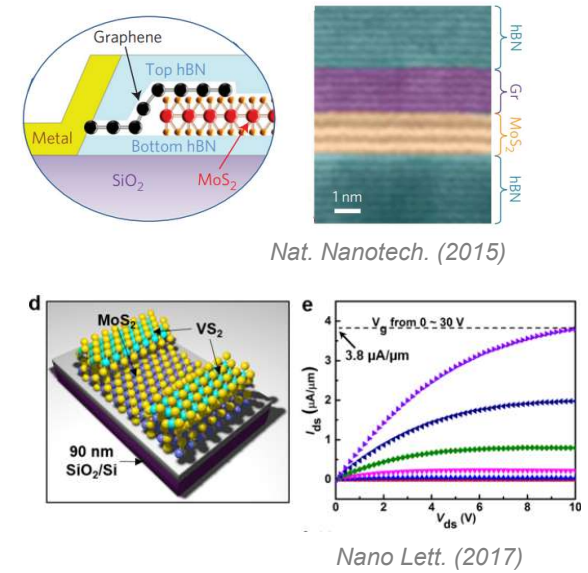
## Transfer of metal electrodes



## Indium metal contact

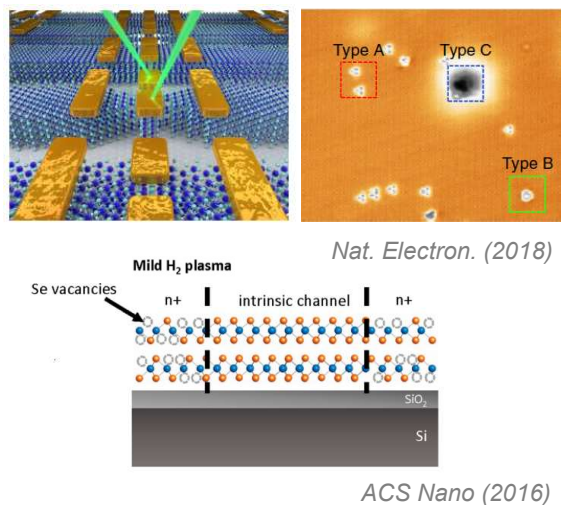


## Stacked vdW contact

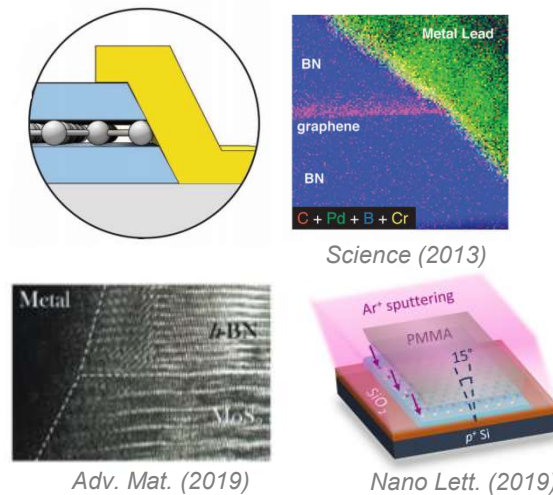


# 2. Chemically bonded contact

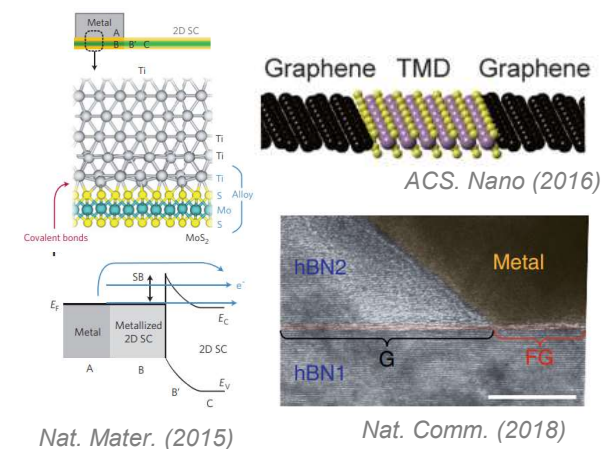
## Contact via defects



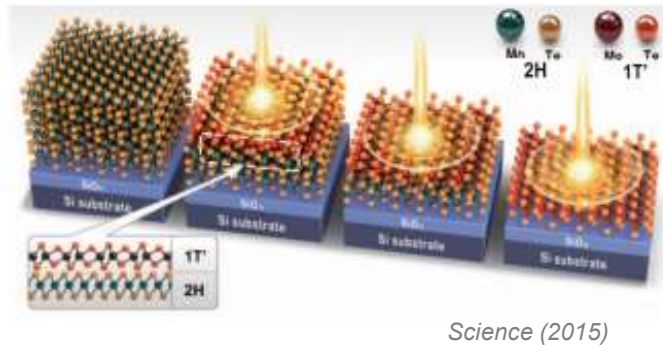
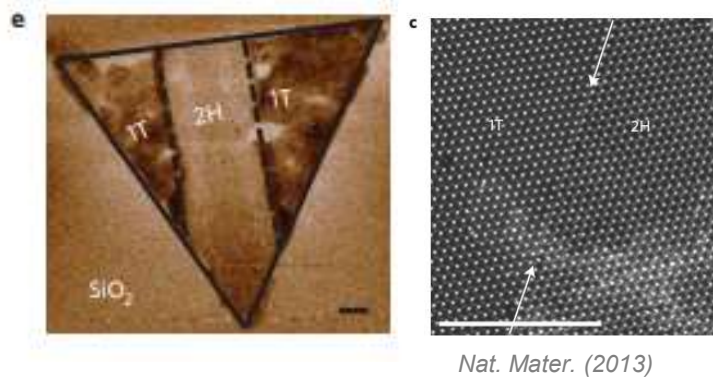
## Edge contact



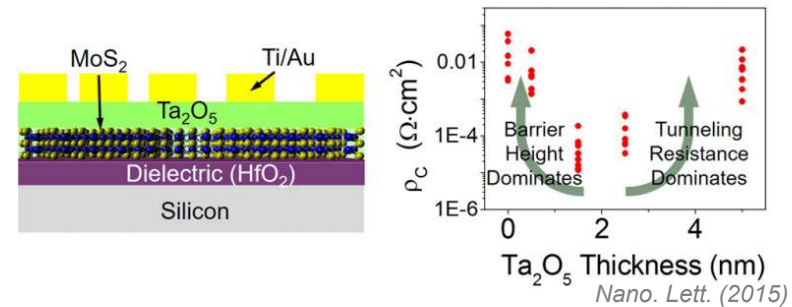
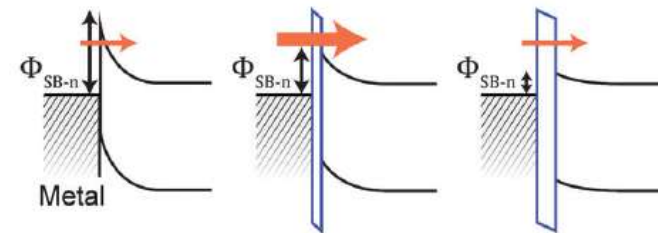
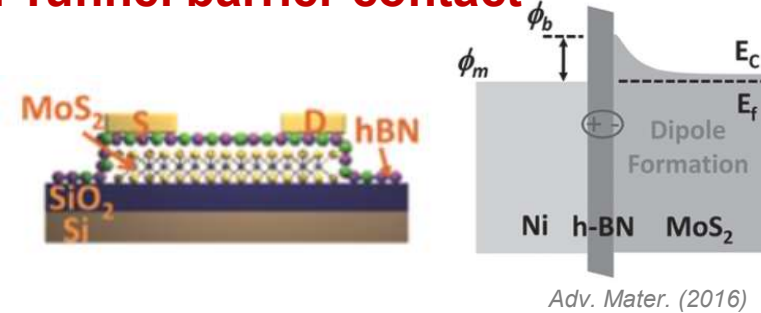
## Contact with chemical bonding



### 3. Phase engineered contact



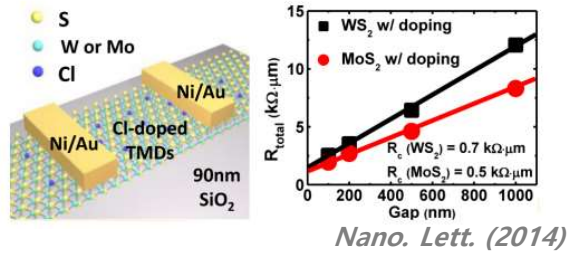
### 4. Tunnel barrier contact



- Phase transition can make one-dimensional contact between semiconducting and metallic phases.
  - laser exposure, solution exposure
- As inserting buffer layer between electrode and TMD channel, Schottky barrier can be reduced by tunnel contact.
  - Stack insulating 2D material(hBN) between electrodes and TMD channel
  - Deposit insulating interlayer materials directly

## 5. Contact improvement by doping

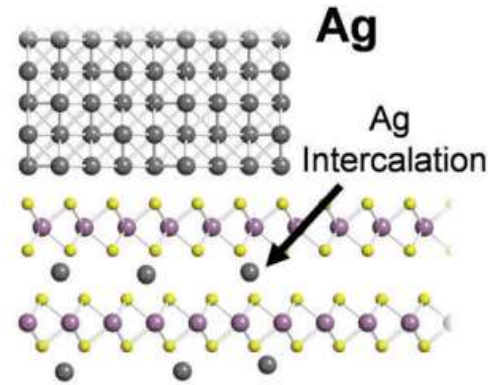
### Molecular doping



MX <sub>n</sub>	Dopant	Type	Concentration [cm <sup>-2</sup> ]	Mobility [cm <sup>2</sup> V <sup>-1</sup> s <sup>-1</sup> ]
MoS <sub>2</sub>	Nb	p	$1.8 \times 10^{14}$	14
	P	p	$10^{10}$ - $10^{12}$	137.7
	Re	n	$5.5 \times 10^{12}$	—
MoSe <sub>2</sub>	W	p	$4.0 \times 10^{11}$	1.6
WS <sub>2</sub>	N	p	$3.83 \times 10^{11}$	1.7
	Cl	n	$6.0 \times 10^{11}$	60
WSe <sub>2</sub>	S	n	—	68.2
SnS <sub>2</sub>	Fe	—	—	8.15
SnSe <sub>2</sub>	Se	n	—	4.6
	Cl	n	$>10^{12}$	167

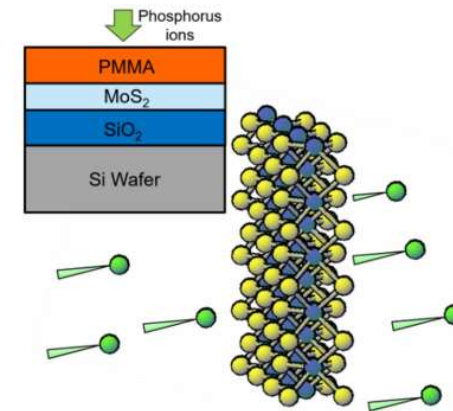
*Nanoscale Horiz. (2019)*

### Intercalation doping



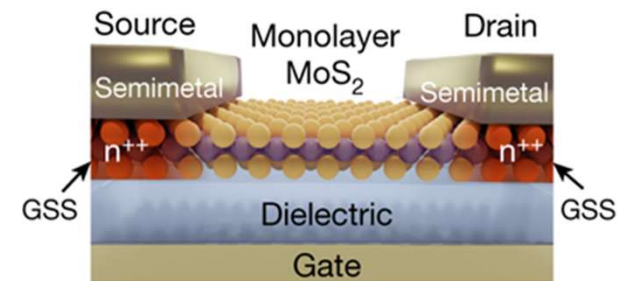
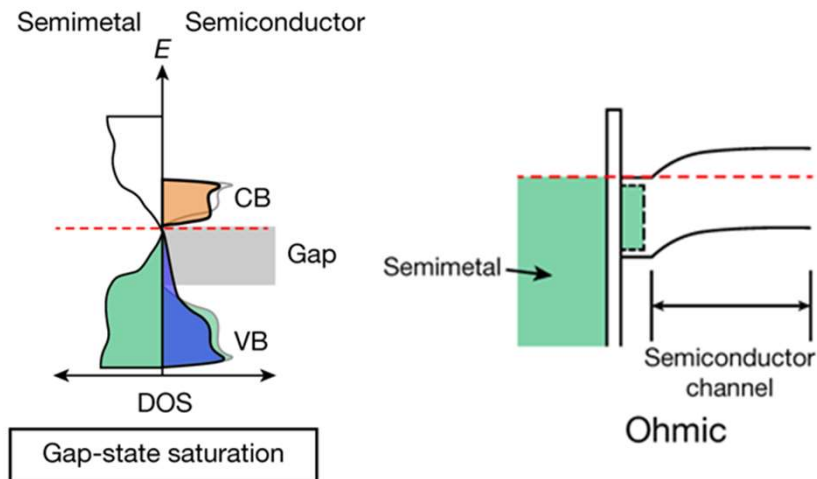
*J. Appl. Phys (2017)*

### Ion implantation



*Semicond. Sci. Technol. (2017)*

## 6. Semi-metal contact

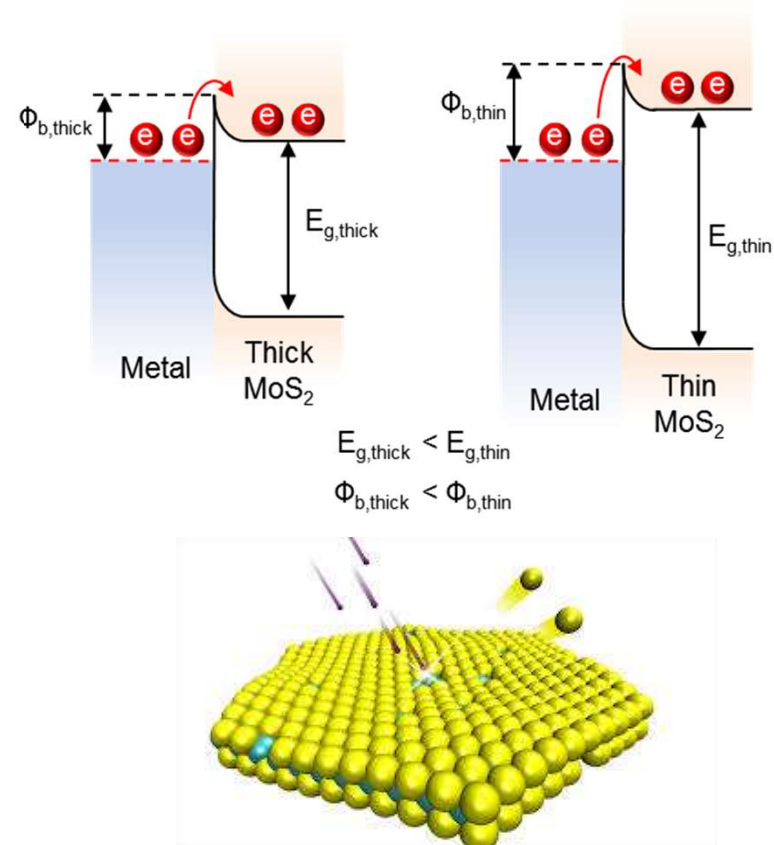
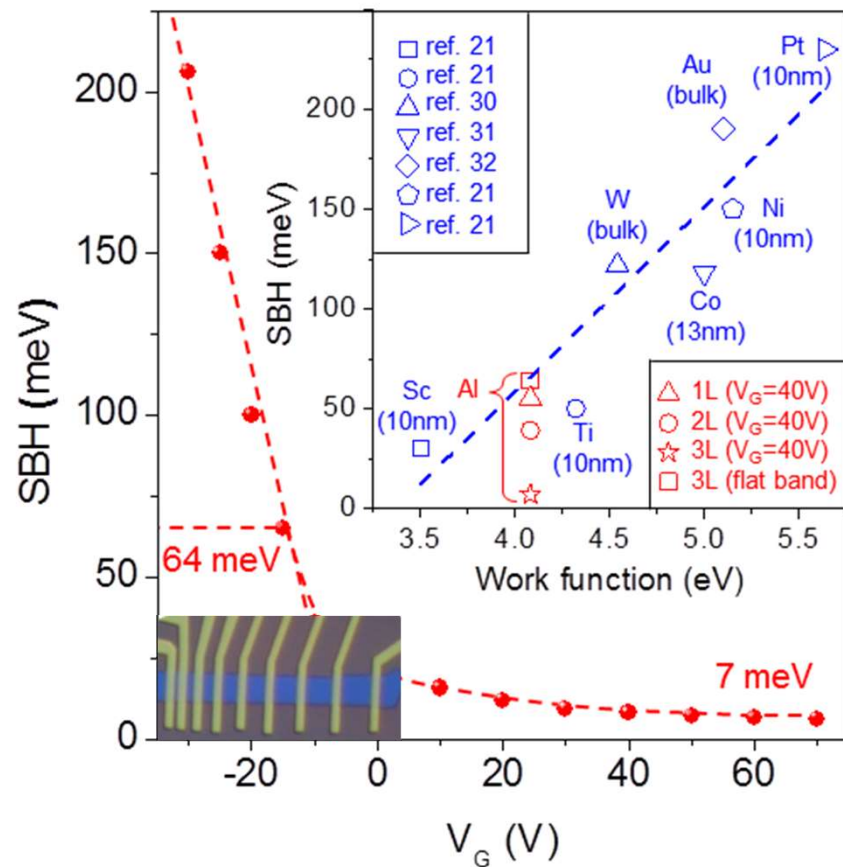


*P.C. Shen et al. Nature (2021)*



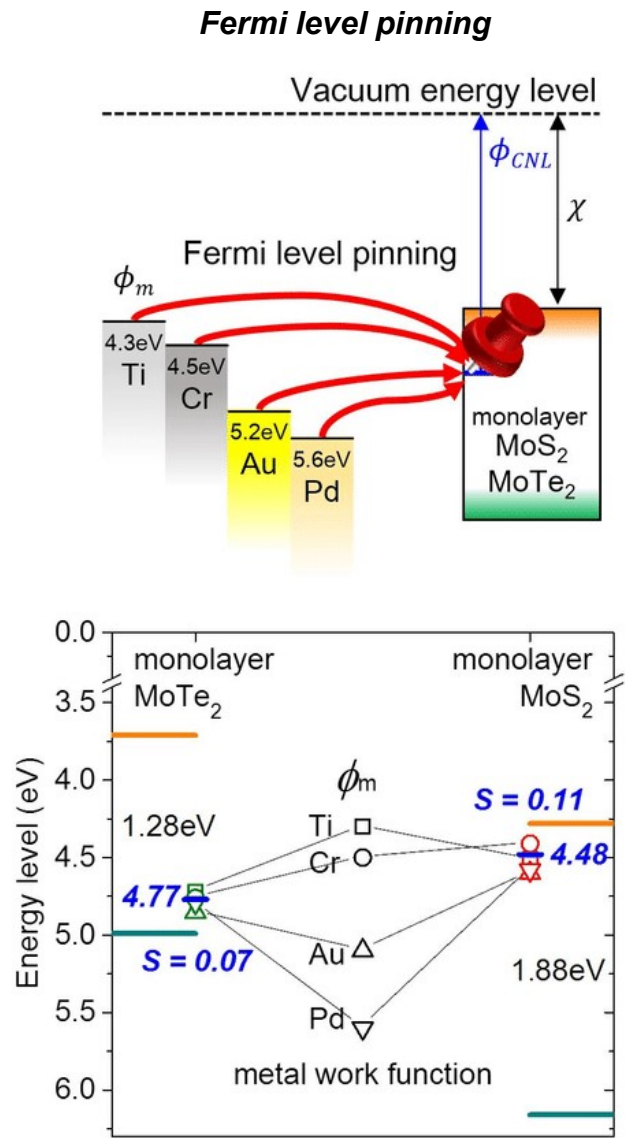
# Low Work Function Metal for Contact

Contact Barrier of various metals



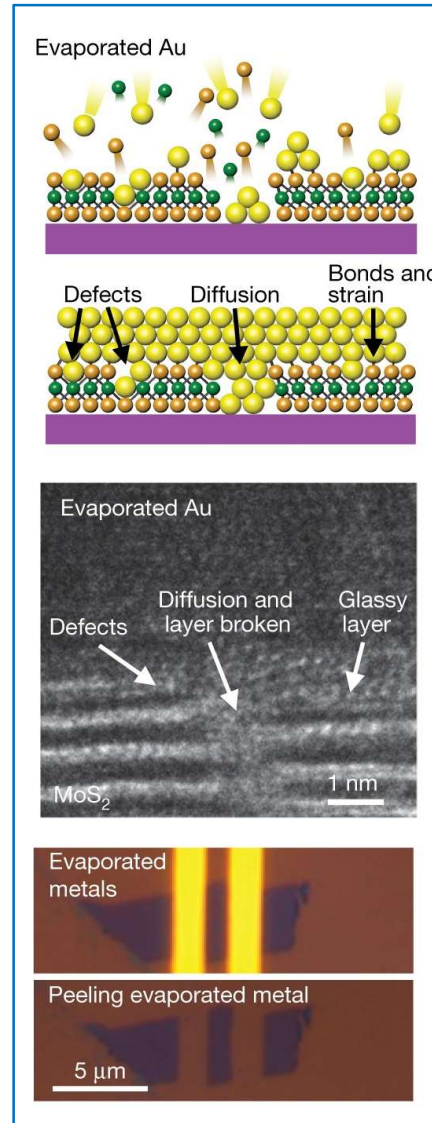
- ❑ Al contacts to MoS<sub>2</sub> are gate-voltage- and thickness-dependent.
- ❑ Still high contact resistance due to pinning at MoS<sub>2</sub>-metal interface

# Van der Waals Contact

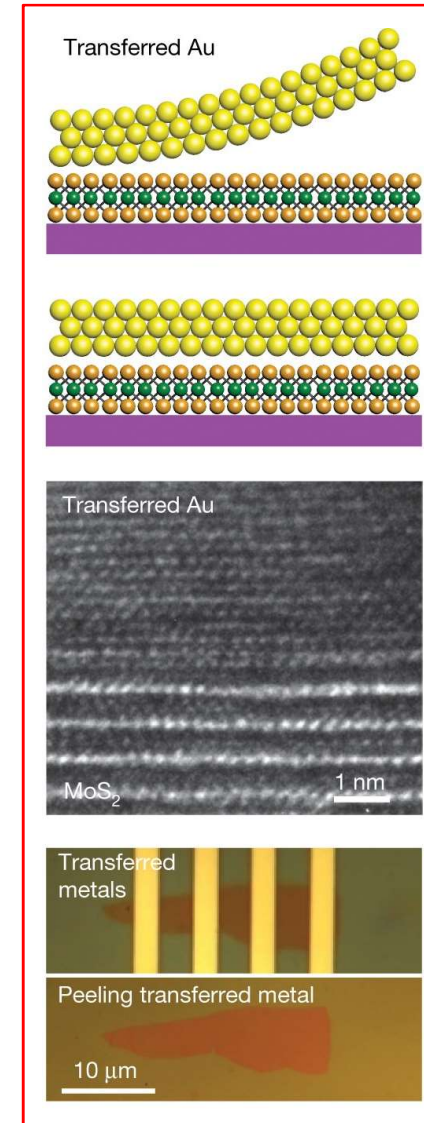


C. Kim, et al. ACS Nano (2017)

## Deposited contact



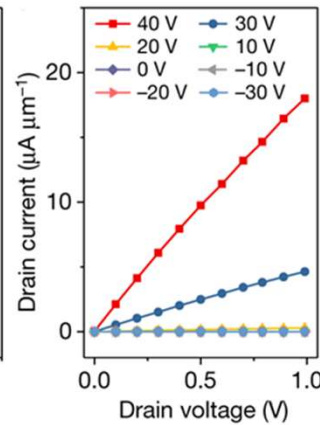
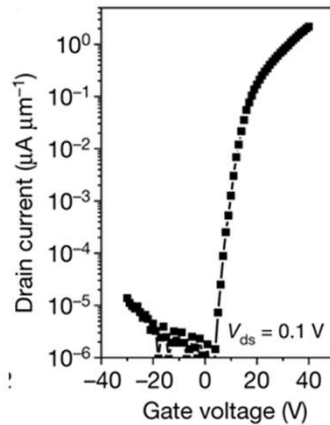
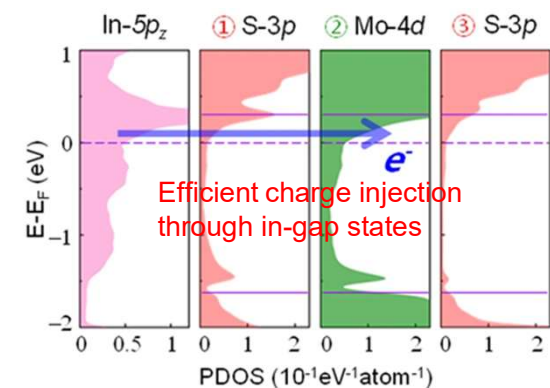
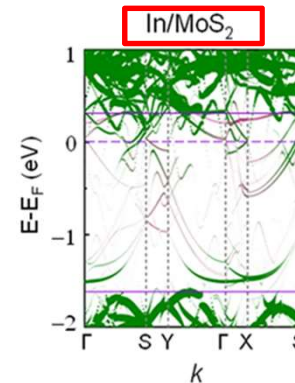
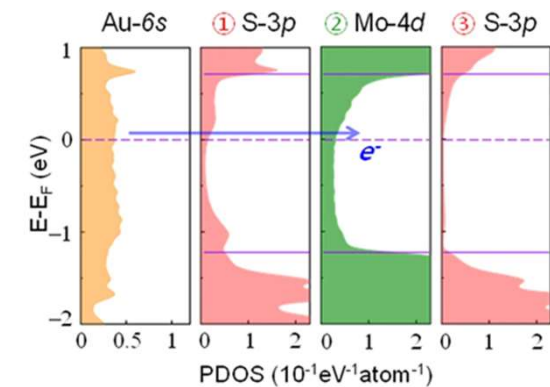
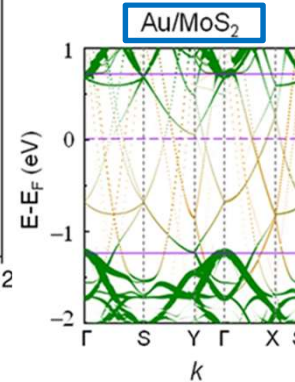
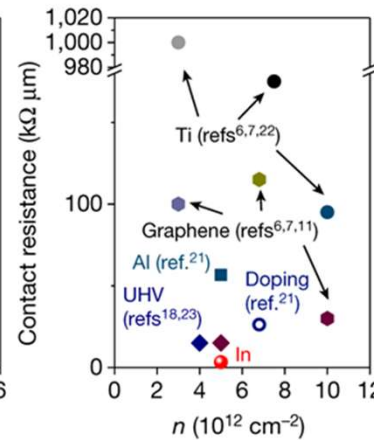
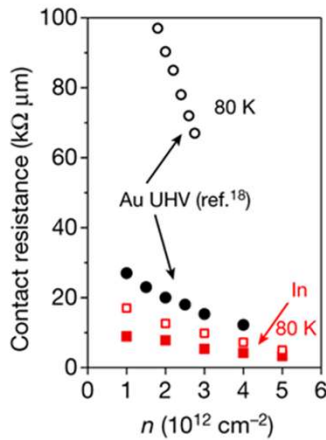
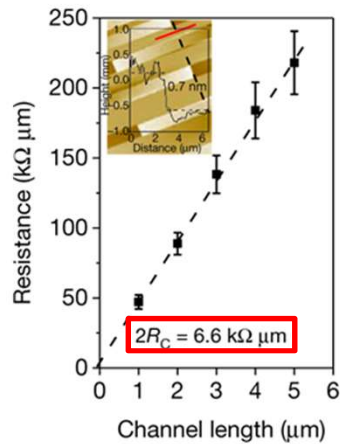
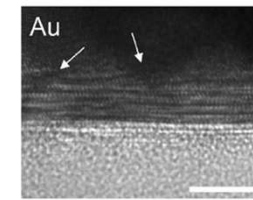
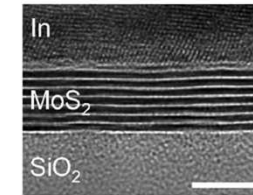
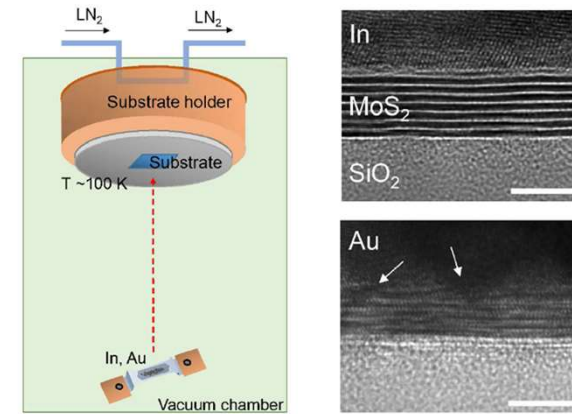
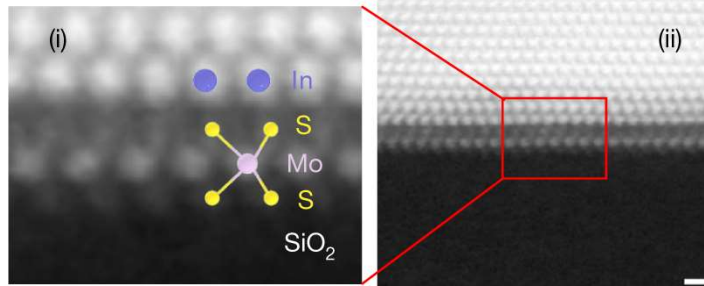
## vdW contact



Y. Liu, et al. Nature (2018)

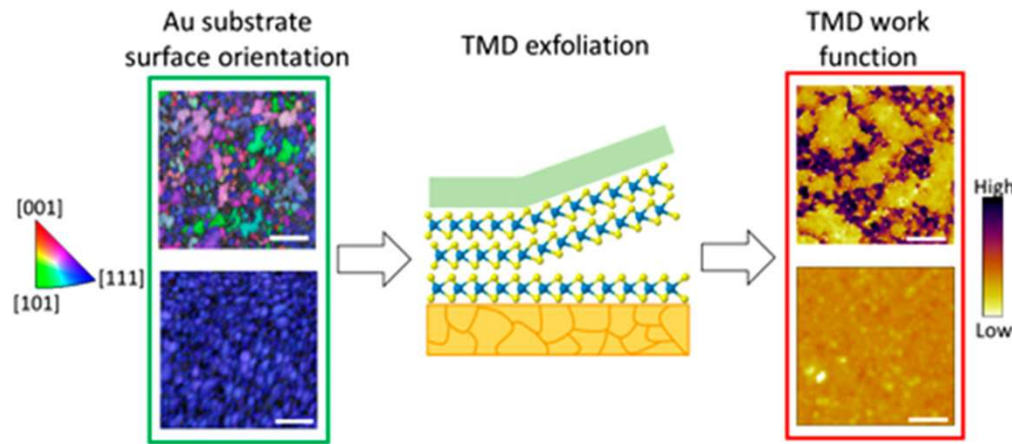
# Van der Waals Contact

Indium contact by thermal evaporation (low energy)

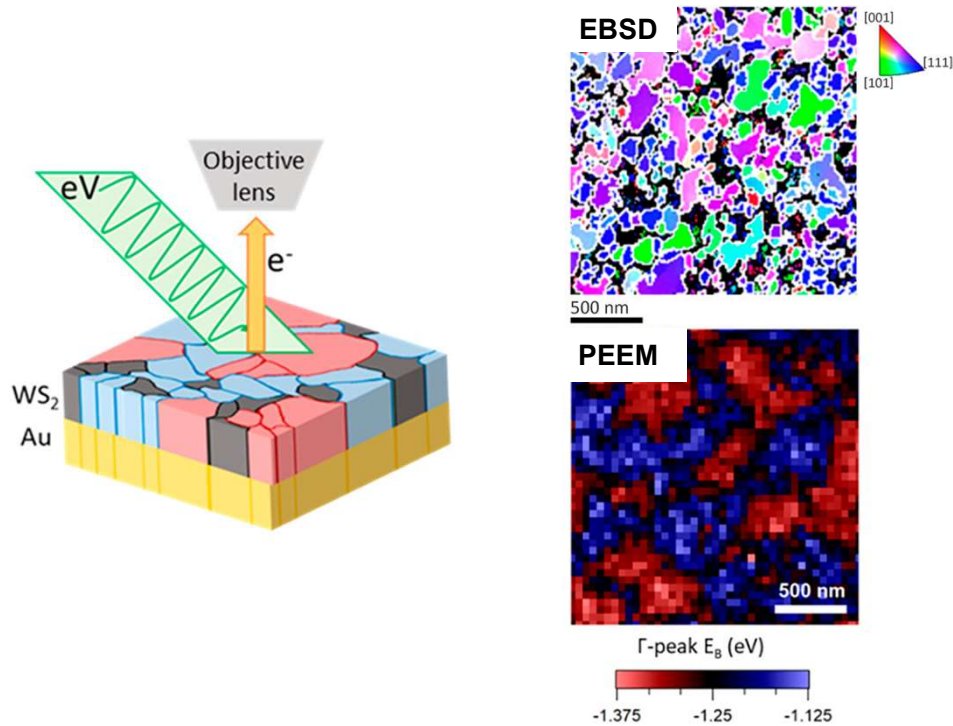


# Nanoscale Heterogeneous Transition Metal Dichalcogenide–Au Interfaces

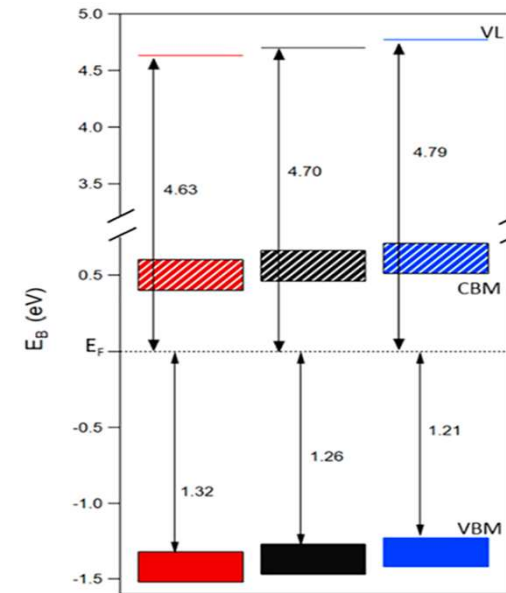
## Schottky barrier measurement of WS<sub>2</sub> on deposited Au



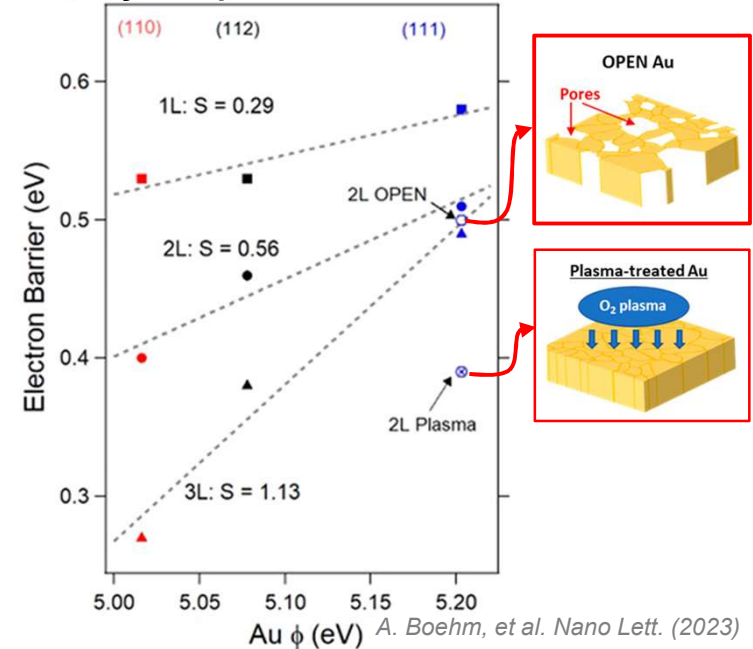
## Photoemission electron microscopy (PEEM) for WS<sub>2</sub> on Au



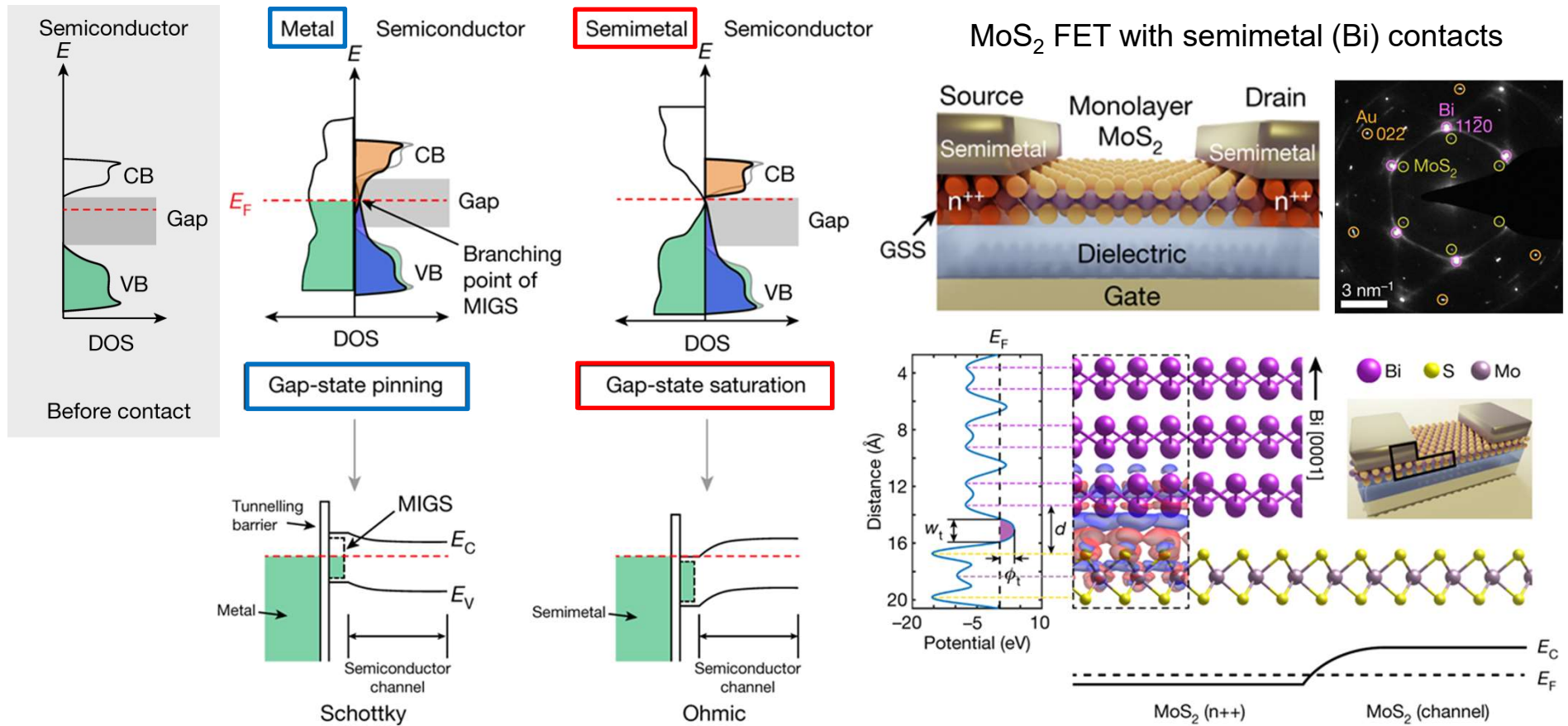
## Local variation of barrier



## Layer-dependence of barrier



# Semimetal–semiconductor Contact



## Interface of metal and semiconductor

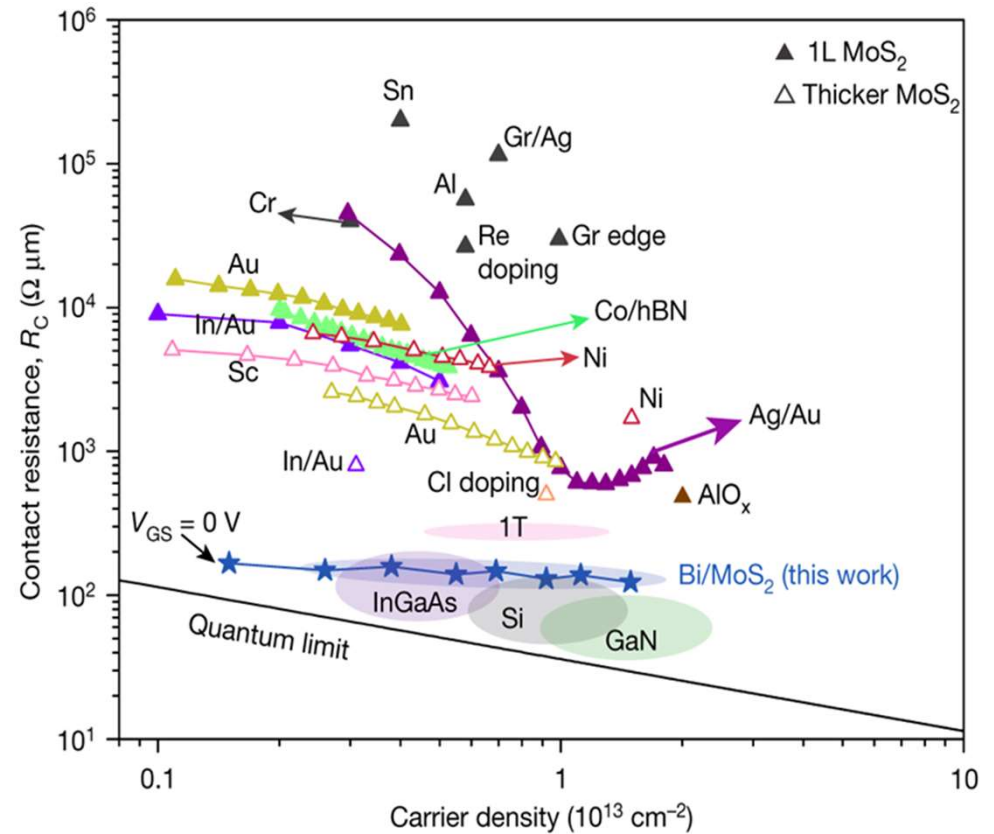
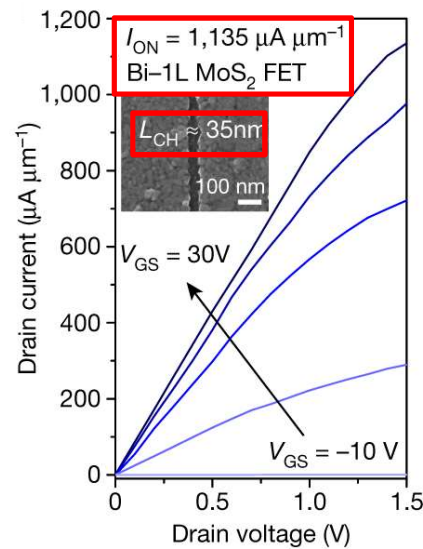
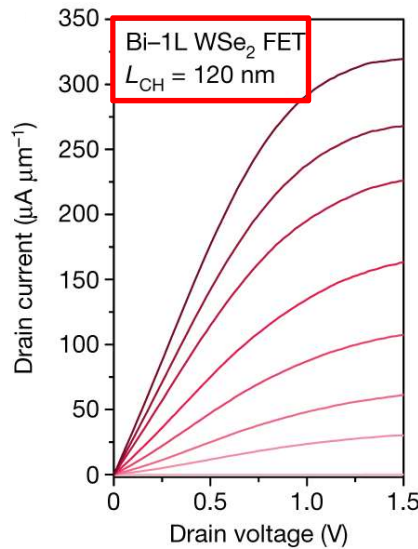
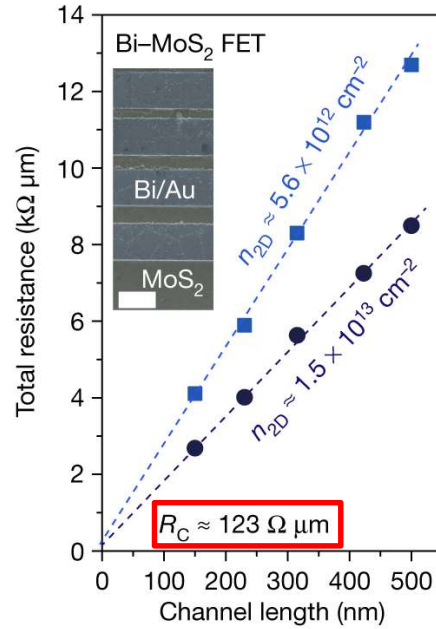
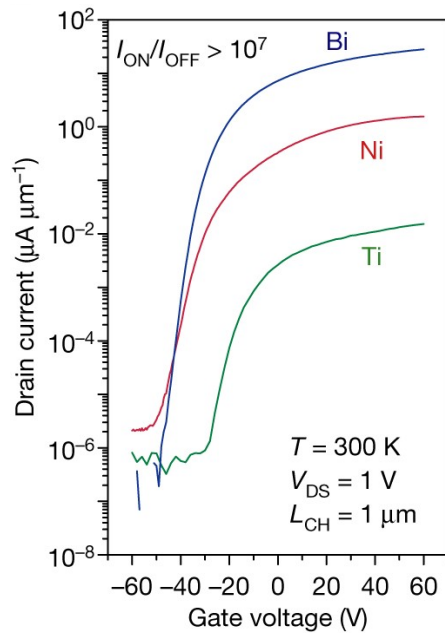
- Due to the metal-induced gap states (MIGS), the Fermi level ( $E_F$ ) is pinned around the branching point of the MIGS, leading to **gap-state pinning**. The Schottky barrier is induced as a result of gap-state pinning.

## Interface of semimetal and semiconductor

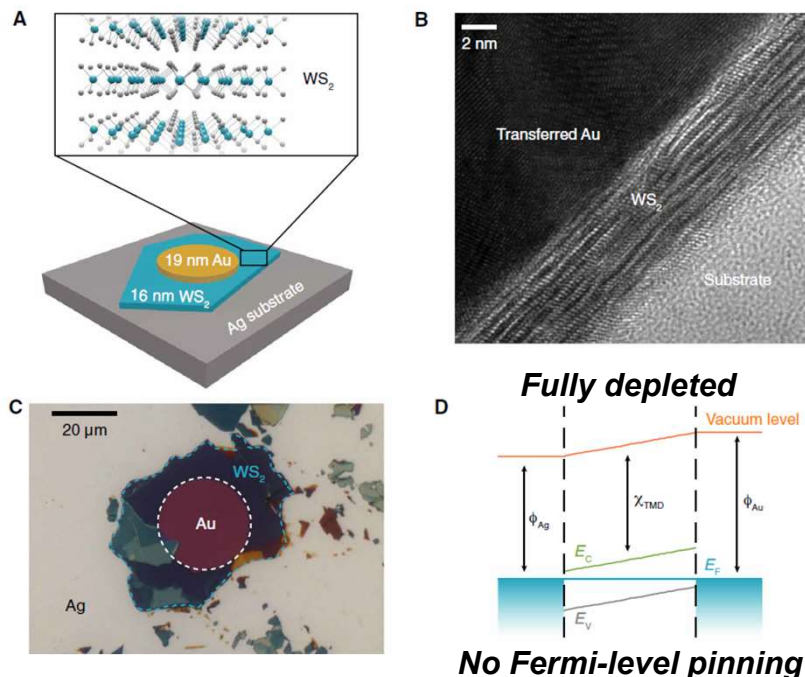
- Because the Fermi level of the semimetal aligns with the conduction band of the semiconductor and the DOS at the Fermi level of the semimetal is near-zero, conduction-band-contributed MIGS are suppressed and the branching point is elevated into the conduction band. The MIGS, now mostly contributed by the valence band, are saturated, leading to **gap-state saturation**. The Ohmic contact is induced due to gap-state saturation.

*P.C. Shen et al. Nature (2021)*

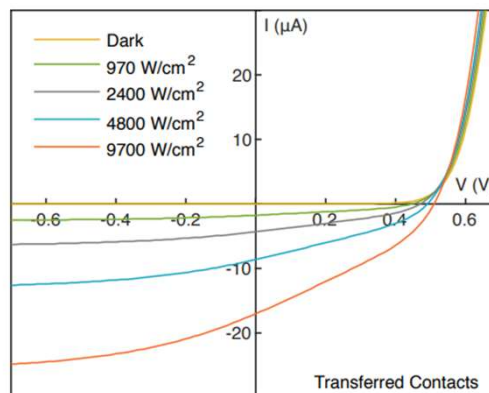
# Semimetal-semiconductor Contact



# Vertical Schottky-junction TMD Photovoltaics

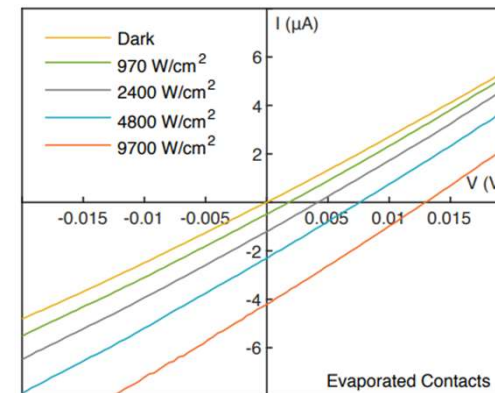


**Transferred device**



**Rectifying behavior**  
due to the difference  
between  $WF_{Au}$  and  $WF_{Ag}$

**Evaporated device**



**resistive behavior**  
due to  $\phi_{evaporated Au} \approx$   
 $\phi_{transferred Ag}$  by  $E_F$  pinning

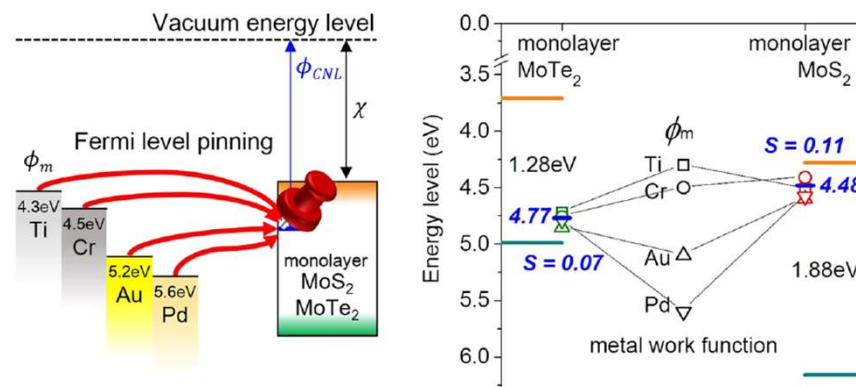
C. M. Went et al. *Sci. Adv.* (2019)

Forming van der Waals contacts to eliminate the Fermi-level pinning by metal transfer process.

1. No Fermi-level pinning by metal transfer
2. Fully depleted by vertical structure ( $\sim 19$  nm of  $WS_2$ )

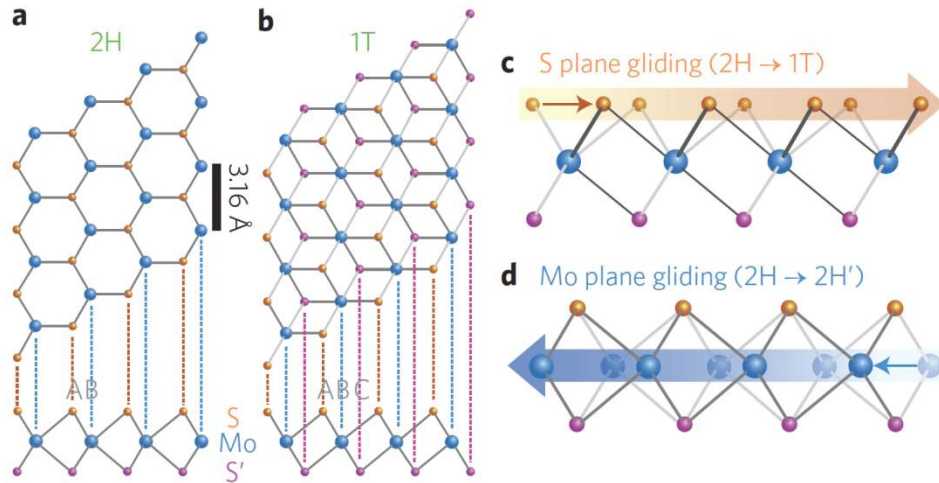
Rectifying behavior  $\rightarrow$  photovoltaic property

**Fermi-level pinning by conventional metal evaporation**



C. Kim et al. *ACS Nano* (2017)

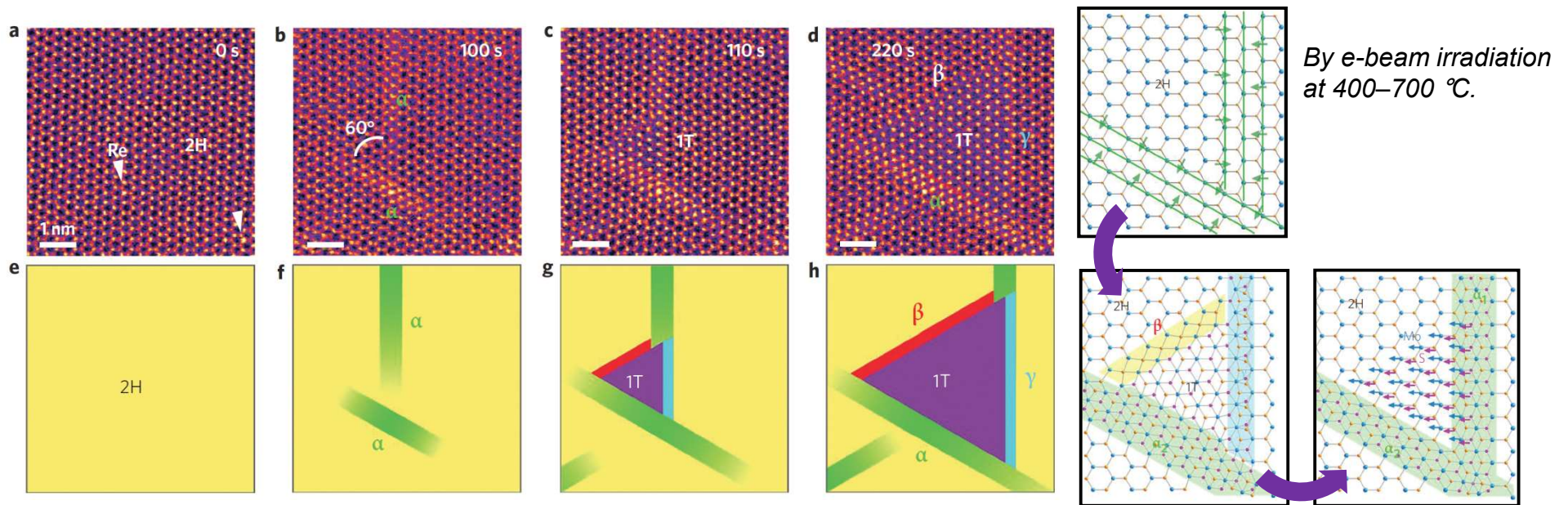
# Phase Transition of MoS<sub>2</sub>



Phase transitions from 2H to 1T in one-atom thick layer alter the properties of a material.

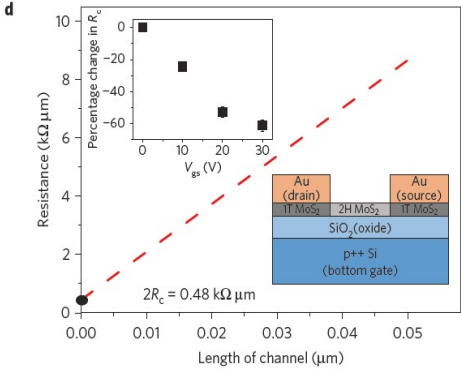
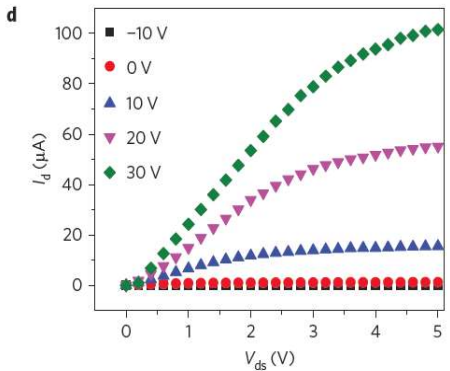
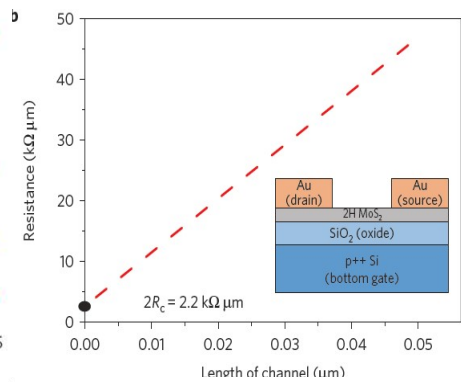
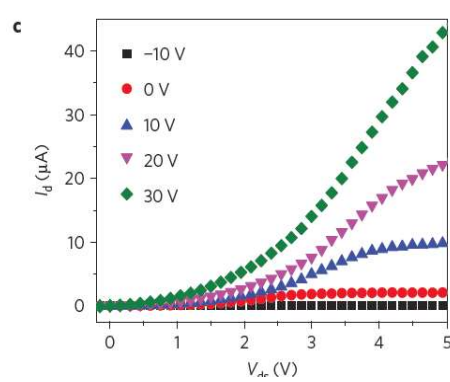
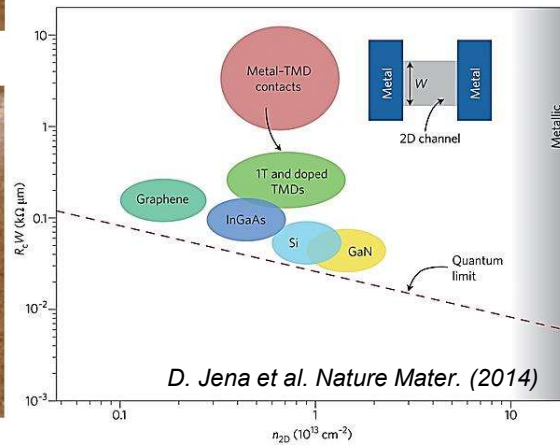
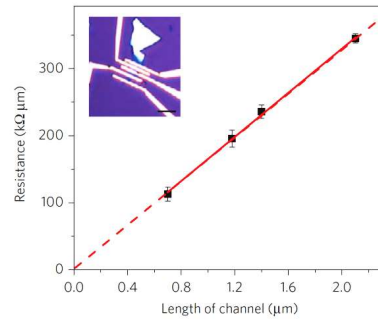
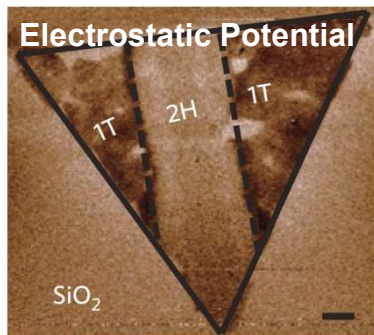
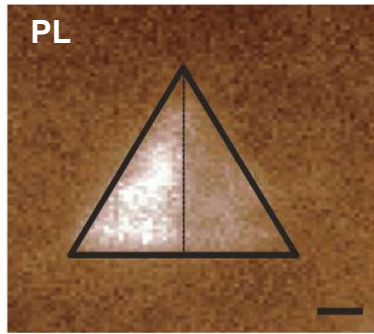
1. Stable semiconducting (2H) phase
2. Metastable metallic (1T) phase

*Difference only by a transversal displacement of one of its two Sulphur planes*





# Phase Engineering of MoS<sub>2</sub>



## Traditional methods for low contact resistance

1. Heavy doping of semiconductor
2. Use of metal with appropriate work function
3. Large semiconductor contact region
4. Reduction of barrier thickness by large bias

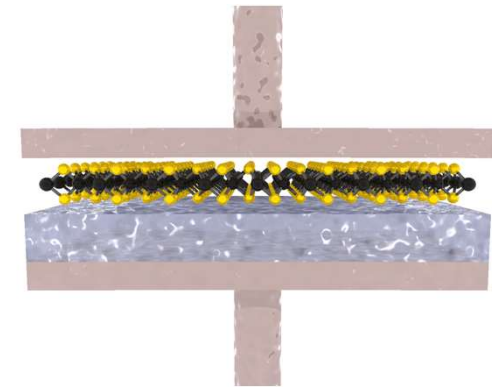
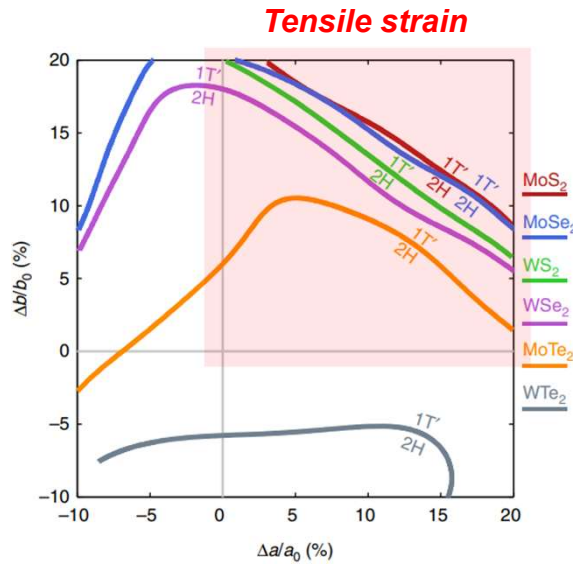
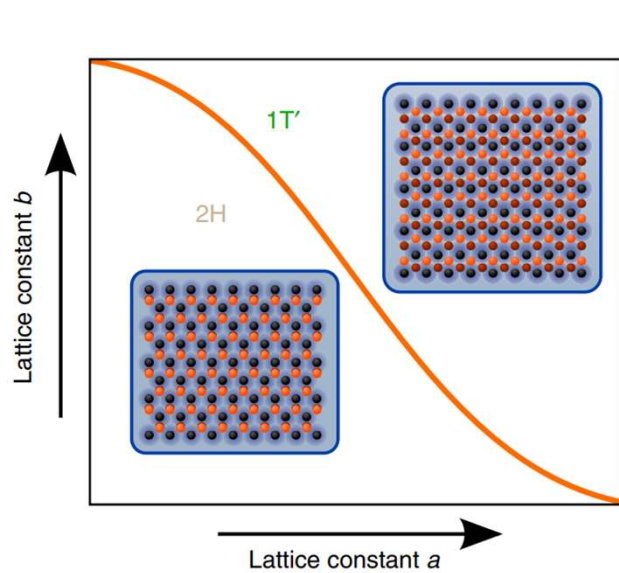
**Unconventional method** to address contact resistance problem, based on the local conversion of MoS<sub>2</sub> semiconducting layers into a metal.

Chemical method for phase transition: Treating the MoS<sub>2</sub> with an organometallic solution containing n-butyl lithium. Lithium donates electrons to the 2H MoS<sub>2</sub>, converting it into the 1T metallic phase.

*Contact resistance drops from ~ 1–10 kΩ μm to ~ 0.2–0.3 kΩ μm*

R. Kappera et al. Nature Mater. (2014)

# Strain Induced Phase Transition of TMDs



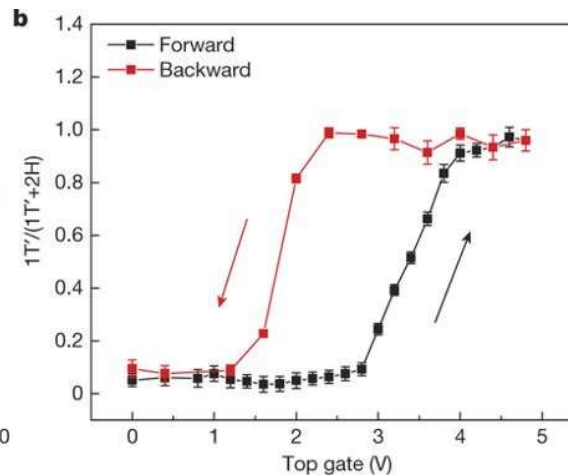
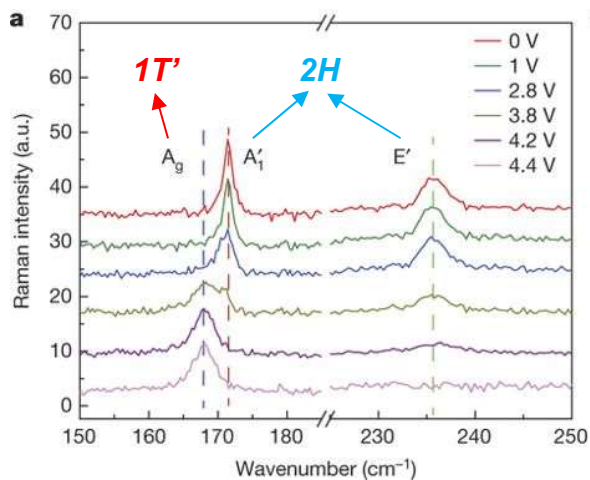
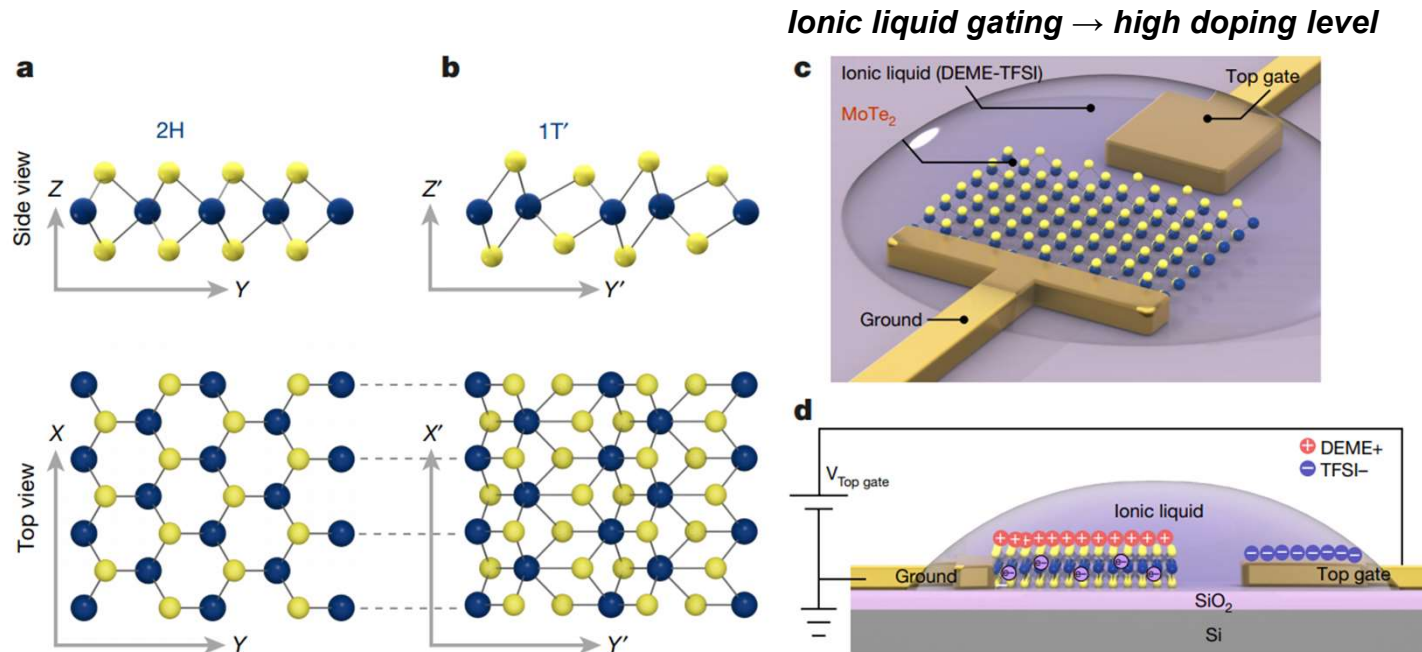
## Phase transition of TMDs by strain

1. In 2D system, lattice constants can be independently controlled with underlying substrate
2. In spite of compression in 2D is problematic, still phase transition can be occurred through tensile strain in 2D materials.

Tendency to lower the internal energy,  $U \rightarrow$  phase transition

K. -A. N. Duerloo Nat. Commun. (2014)

# Ion-gating Induced Phase Transition of MoTe<sub>2</sub>

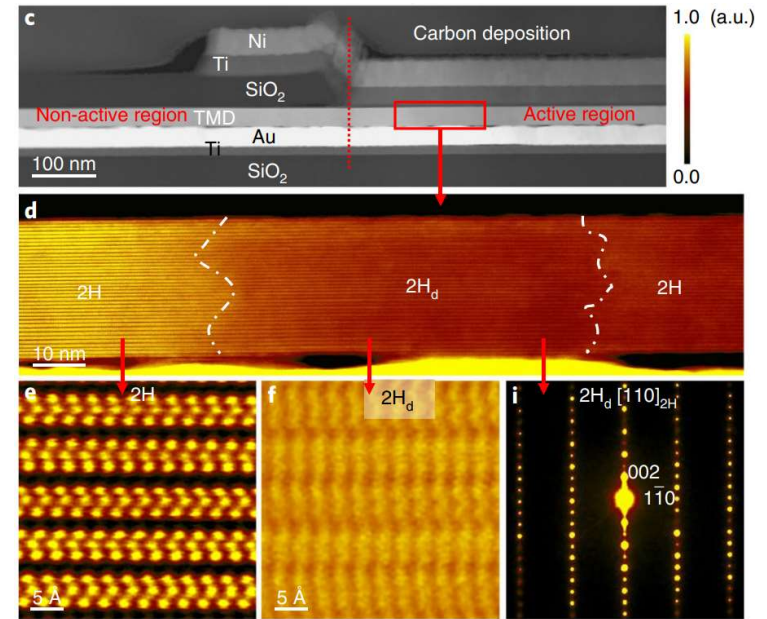
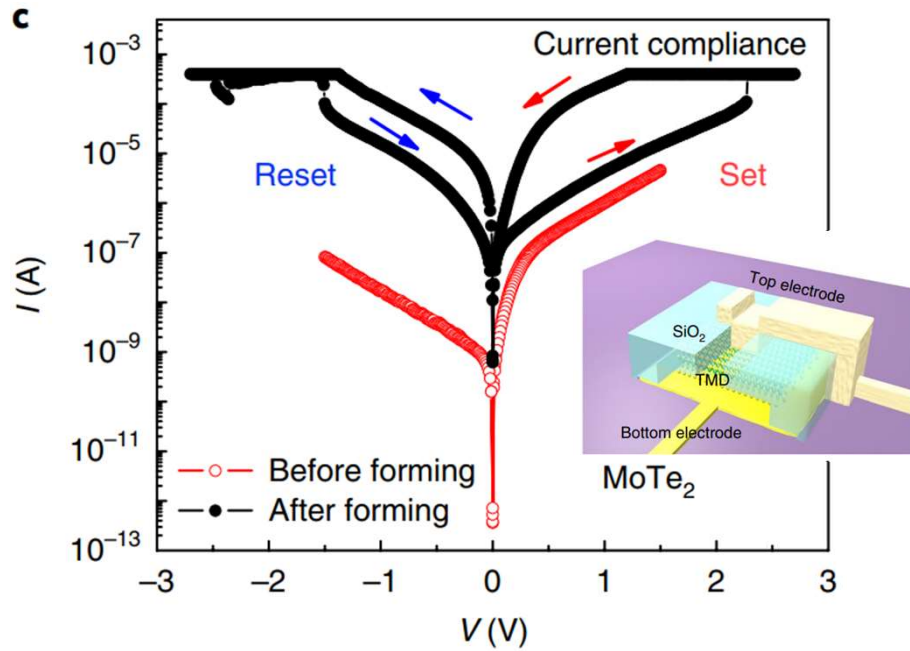


Phase transition of MoTe<sub>2</sub> by excessive electrons doping

1. Doping level up to  $10^{14}$  electrons/cm<sup>2</sup> in mono layer MoTe<sub>2</sub>
2. In the condition of high charge density, 1T' phase become thermodynamically stable phase

High doping → 2H to 1T' phase transition

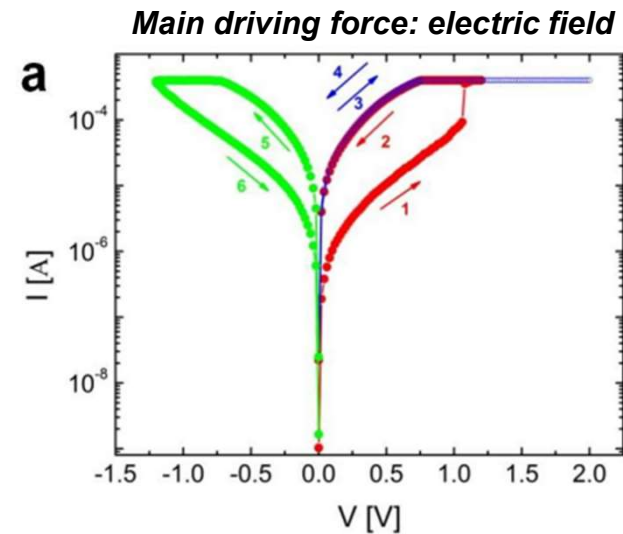
# Electric-field Induced Phase Transition of Te-based TMDs



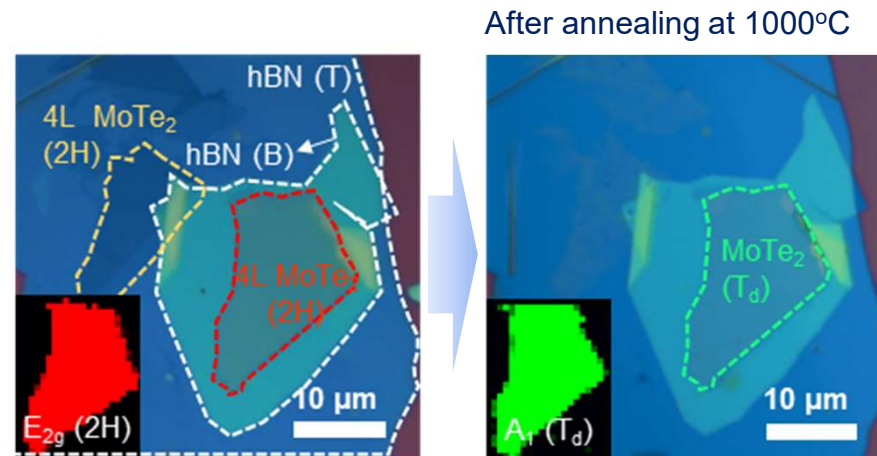
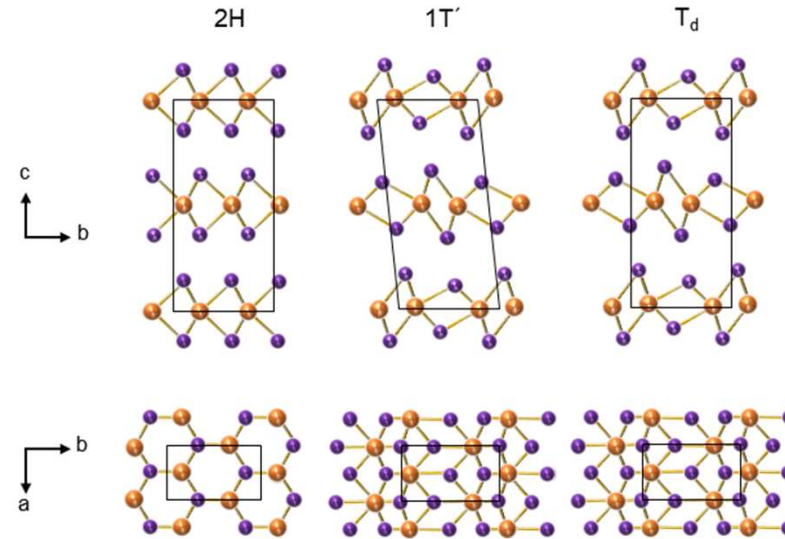
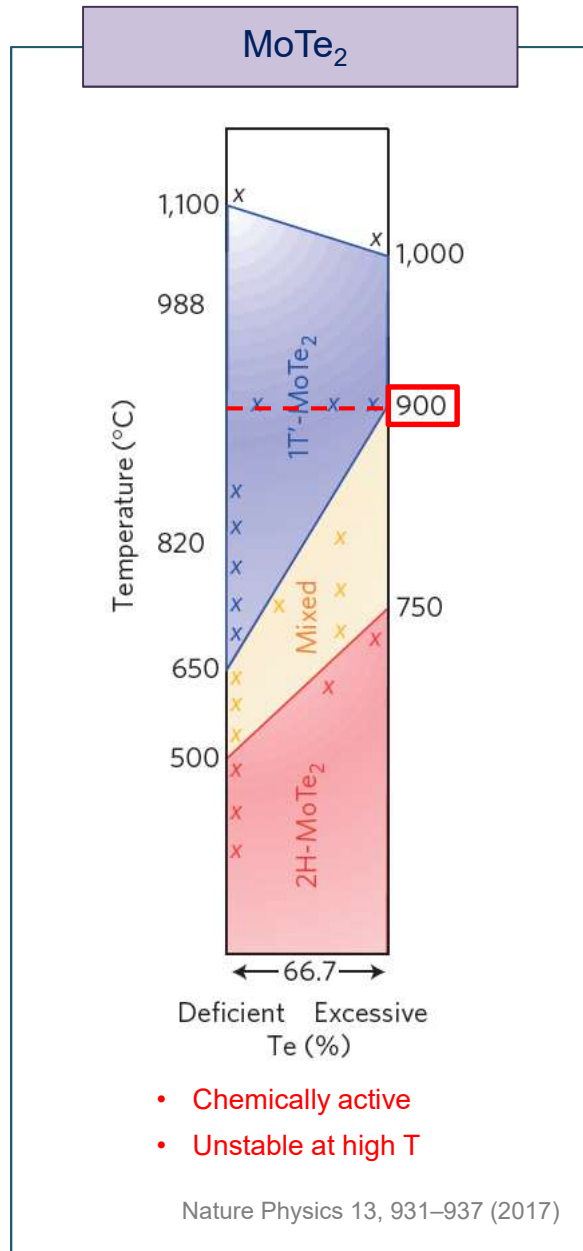
## Phase transition of Te-based TMDs by electric field

1.  $2H_d$  phase conductive path is formed in  $2H$  phase structure
2. For the bipolar switching, the main driving force is the electric field, rather than Joule heating

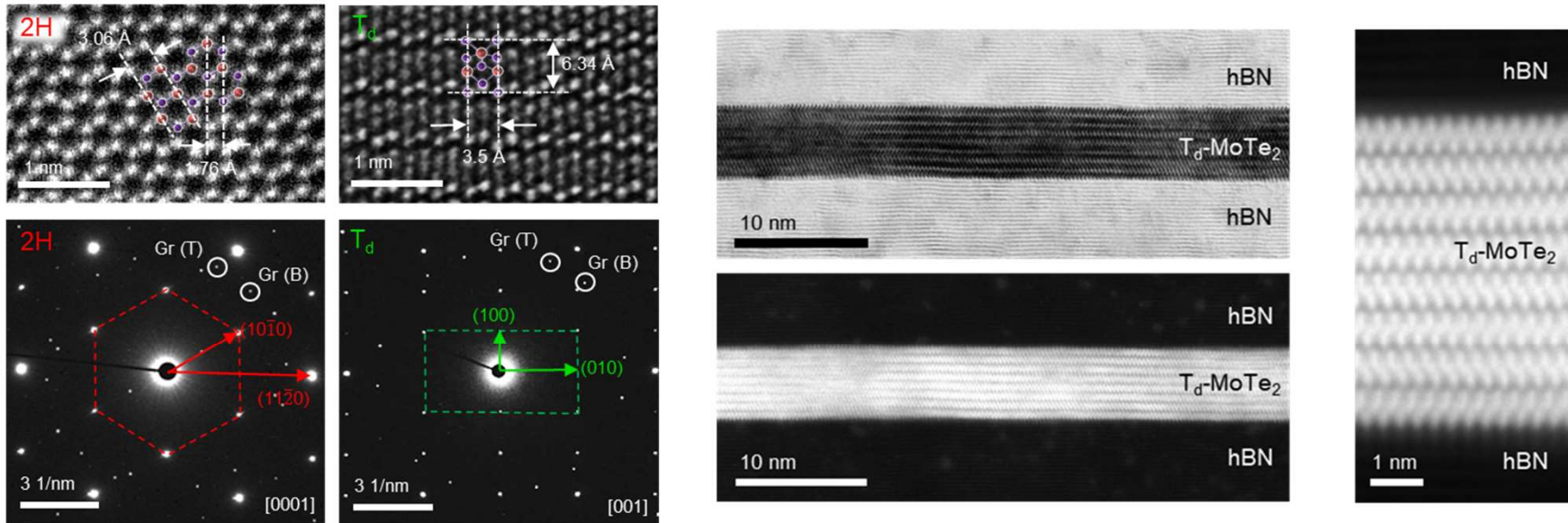
Electric field  $\rightarrow$   $2H$  to  $2H_d$  phase transition



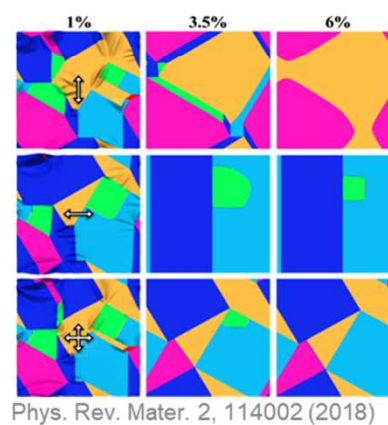
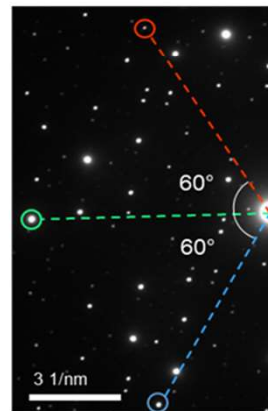
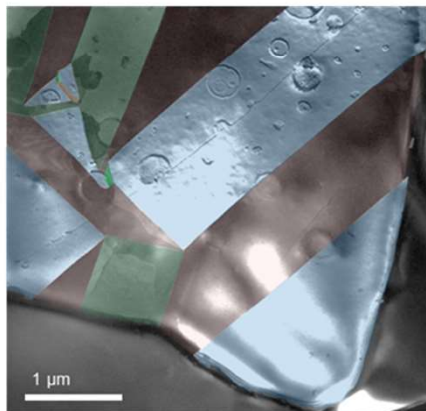
# Formation of Low Resistance Contacts by Phase Transition



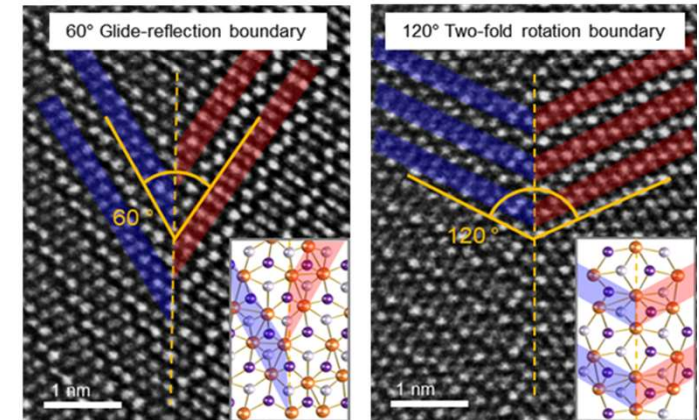
# Formation of Low Resistance Contacts by Phase Transition



## Polycrystalline $T_d$ - $\text{MoTe}_2$

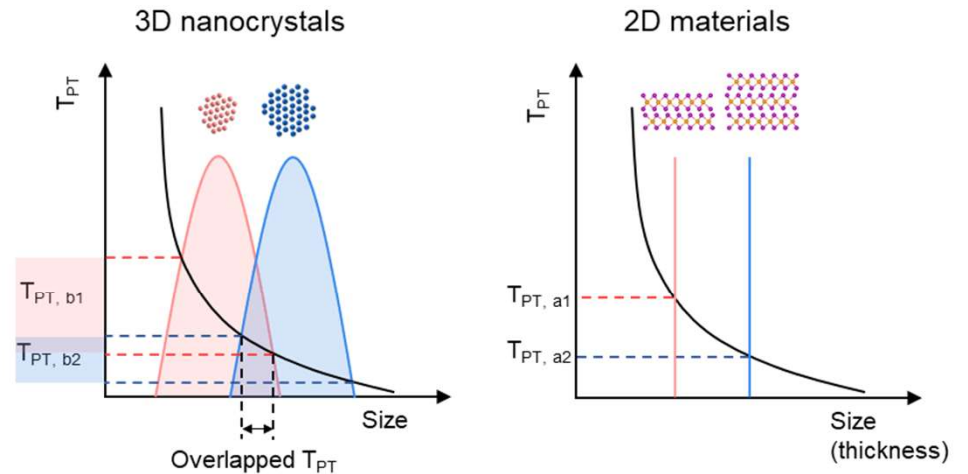
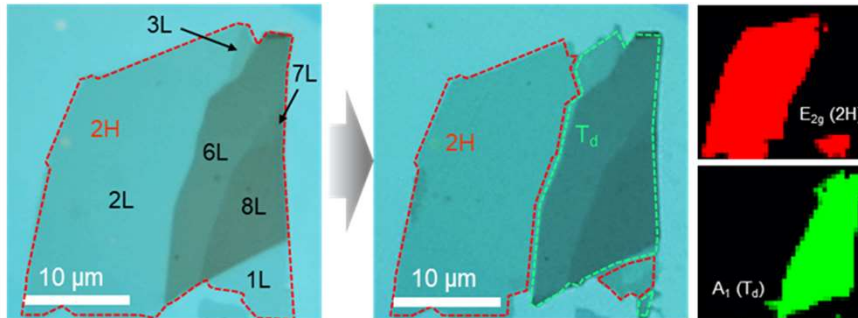


## Grain boundary structure

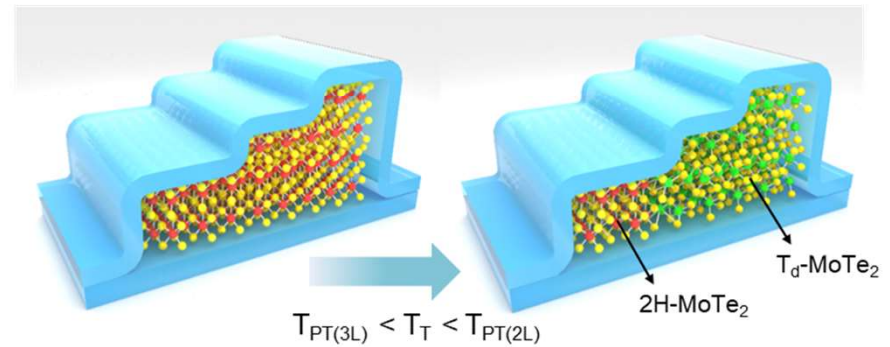
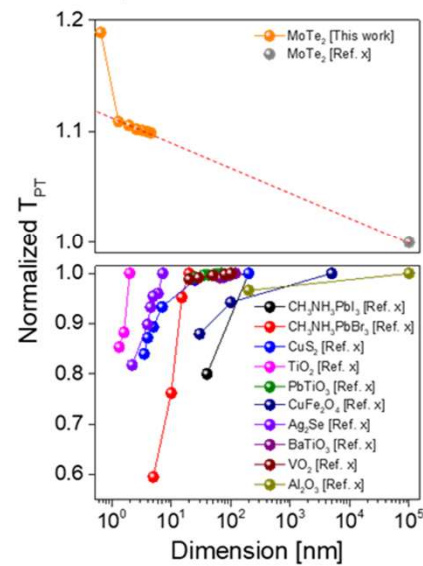
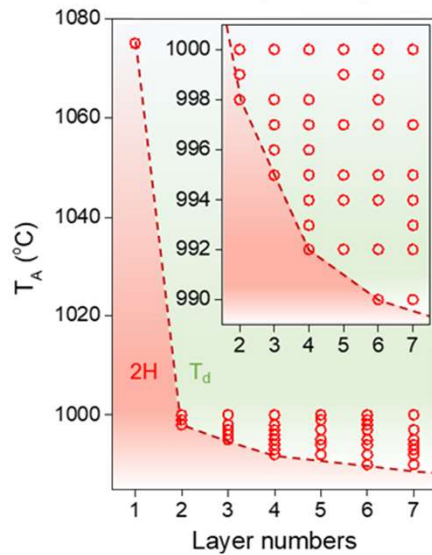


# Formation of Low Resistance Contacts by Phase Transition

## Phase transition of MoTe<sub>2</sub> with different thicknesses



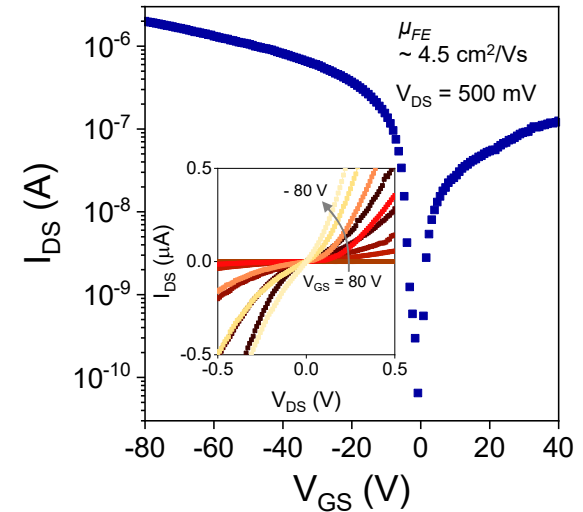
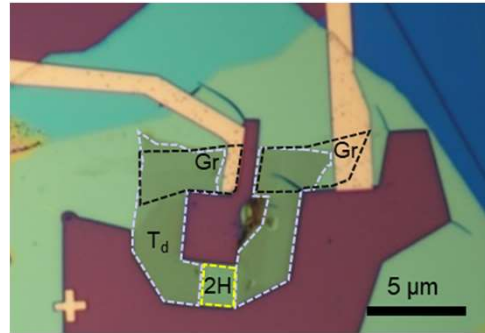
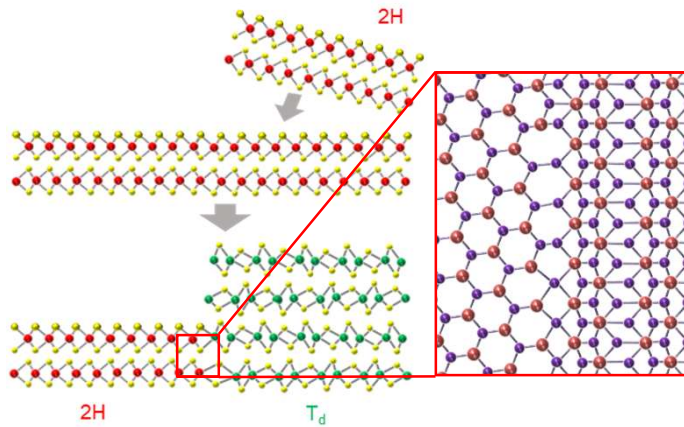
## Layer-dependent PT temperature



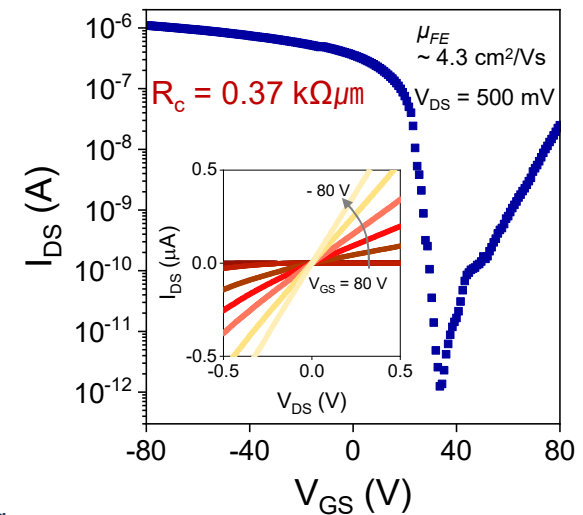
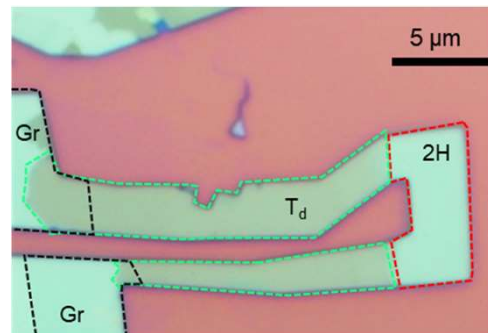
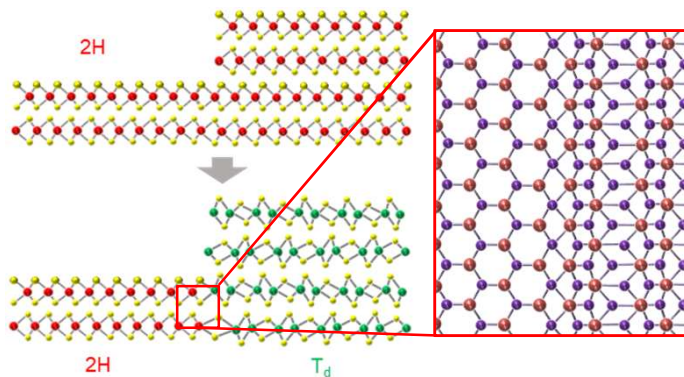
$T_{PT}$  from 2H to  $T_d$  decreases as the thickness increases.

# Formation of Low Resistance Contacts by Phase Transition

## Misaligned 2H-T<sub>d</sub> heterointerface



## Aligned 2H-T<sub>d</sub> heterointerface



- In-plane 2H-T<sub>d</sub> contacts can be fabricated by thickness-controlled PT patterning.
- Low in-plane contact resistance improves device performance of MoTe<sub>2</sub> FETs.